

Characterization of Xe-TMA mixtures with NEXT-MM

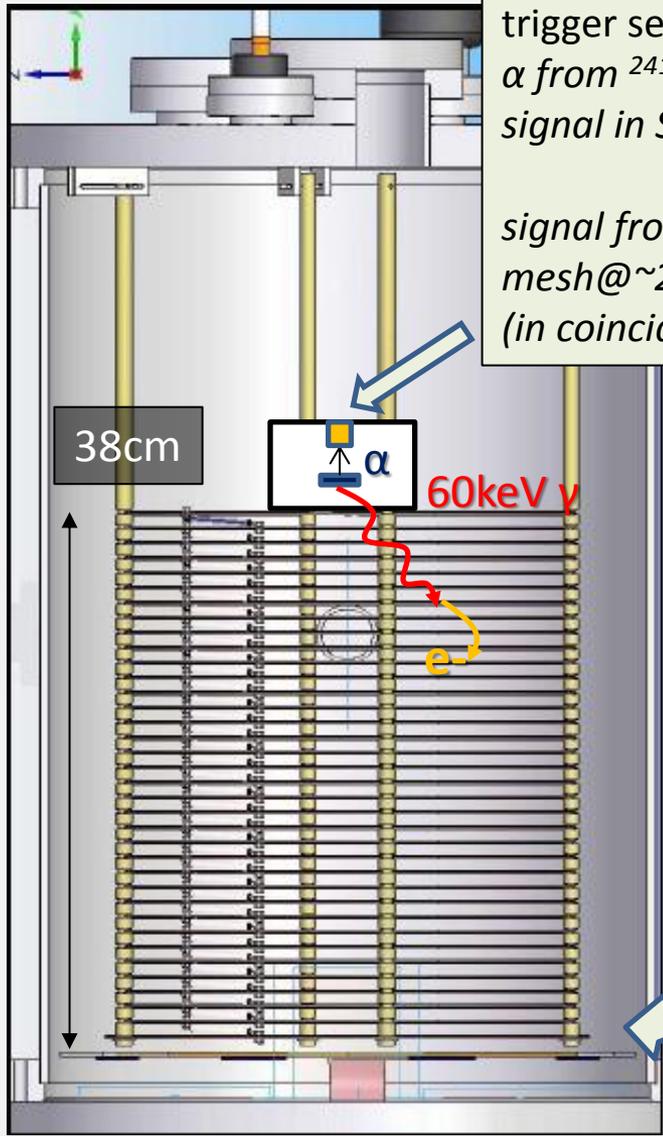
Diego Gonzalez Diaz
(Zaragoza University)

disclaimer:

A detailed description of the technical details of NEXT-MM will be circulated inside the collaboration soon.

I will focus here on the main results of potential interest for NEXT-100

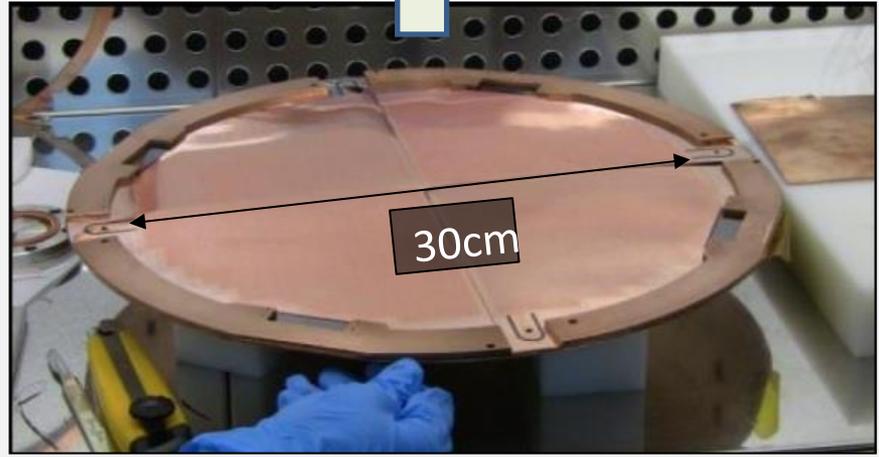
Part 1: system description



trigger setup:
 α from ^{241}Am creates
 signal in Si-diode
 +
 signal from MM-
 mesh@~20keV threshold
 (in coincidence)



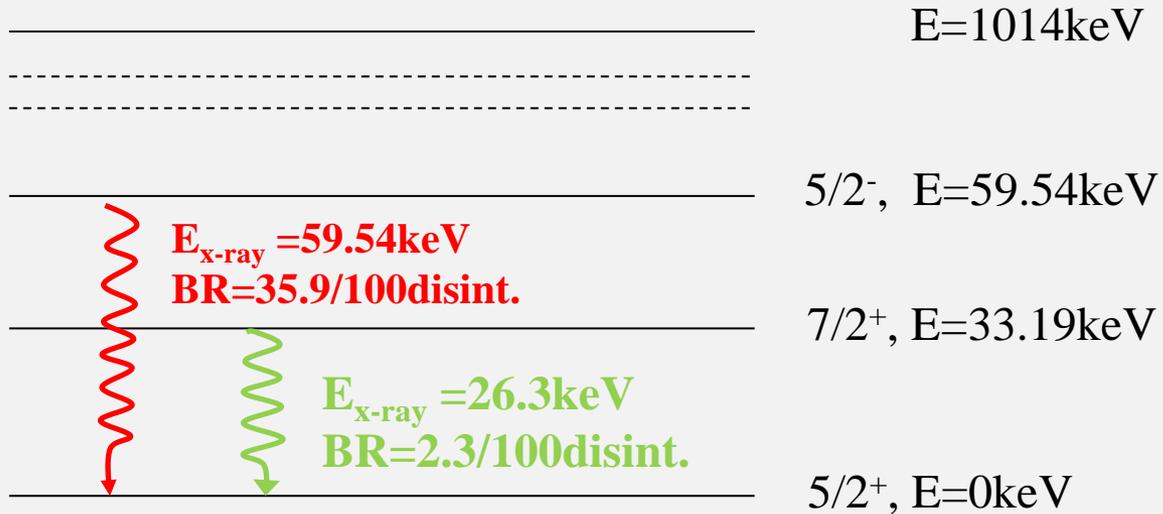
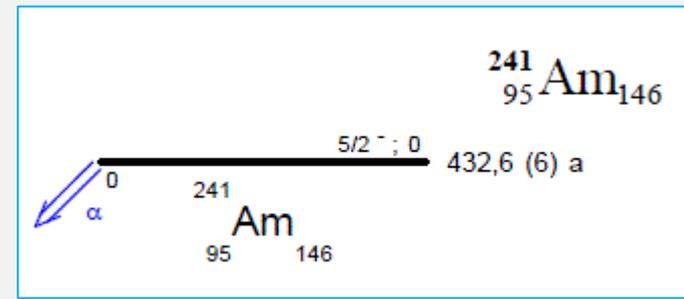
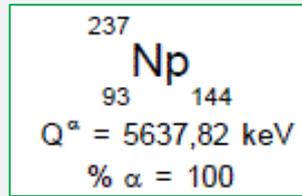
T2K electronics (based on the AFTER chip)



0.8cmx0.8cm pixelized
 microbulk Micro-Megas

field-cage

$E_\alpha = 5.578\text{MeV}(84.45\%), 5.535\text{MeV}(13.23\%)$



Xe atomic properties

Edge energies, keV

K	34.5820007
L ₁	5.45200014
L ₂	5.09999999
L ₃	4.78100014
M	1.14300001
K-alpha	29.802
K-beta	33.644001
L-alpha	4.11100006
L-beta	4.42199993

list of observable x-ray photons (~above 1% probability)

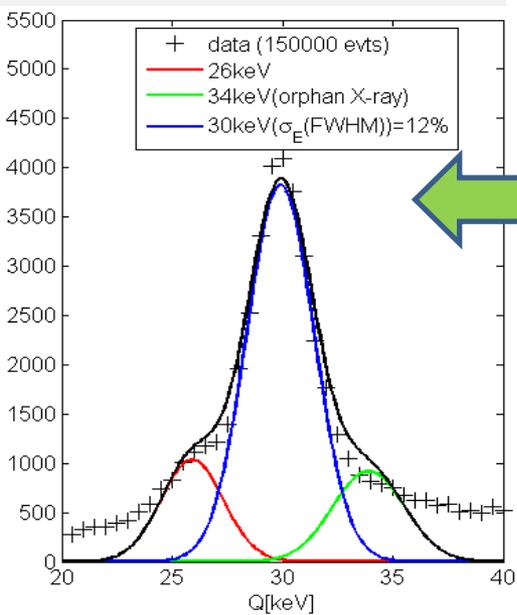
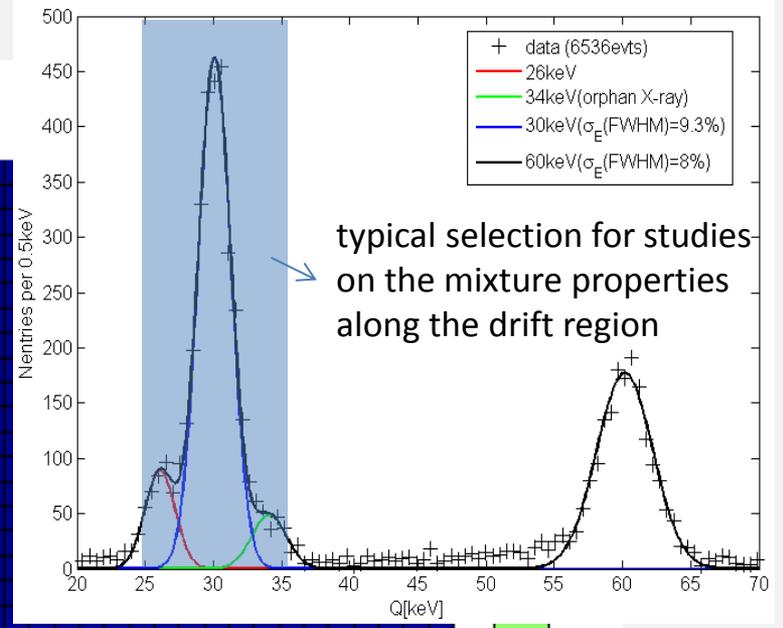
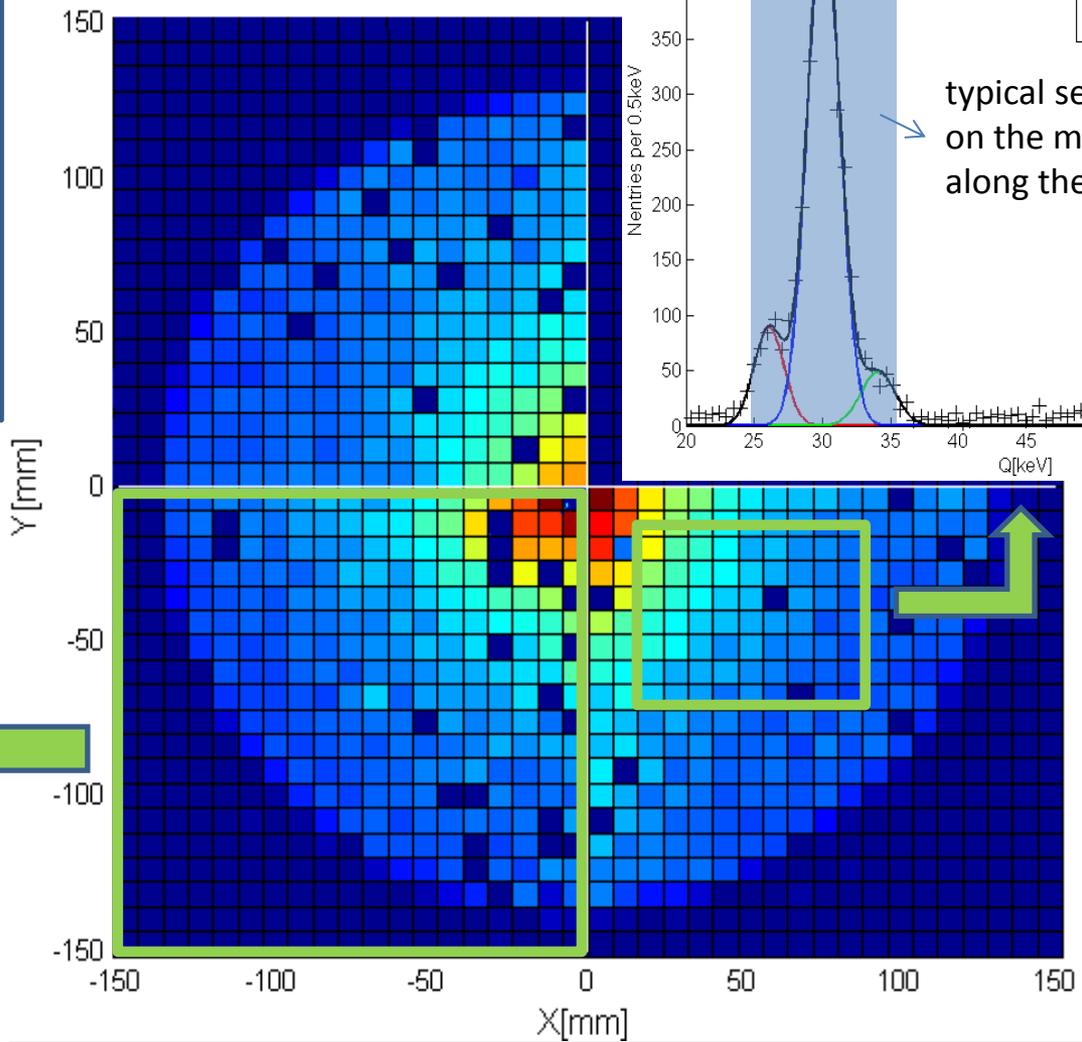
- | | | | |
|---------------------------------------|------------------------|-----|---|
| 1. full absorption main Am-peak: | 59.54 keV | → | 1 |
| 2. orphan K _β : | 33.64 keV | → | 2 |
| 3. escape K _α : | 59.54-29.8 = 29.74 keV | } → | 3 |
| 4. orphan K _α : | 29.80 keV | | |
| 5. escape K _β : | 59.54-33.6 = 25.94 keV | } → | 4 |
| 6. full absorption secondary Am-peak: | 26.3keV | | |

status as of today, before increasing pressure

level of connectivity: **92%**
 unconnected pixels: **8%**
 of which
 unclear origin: **1%**
 understood(solvable): **5.2%**
 damaged pixels: **1.8%**

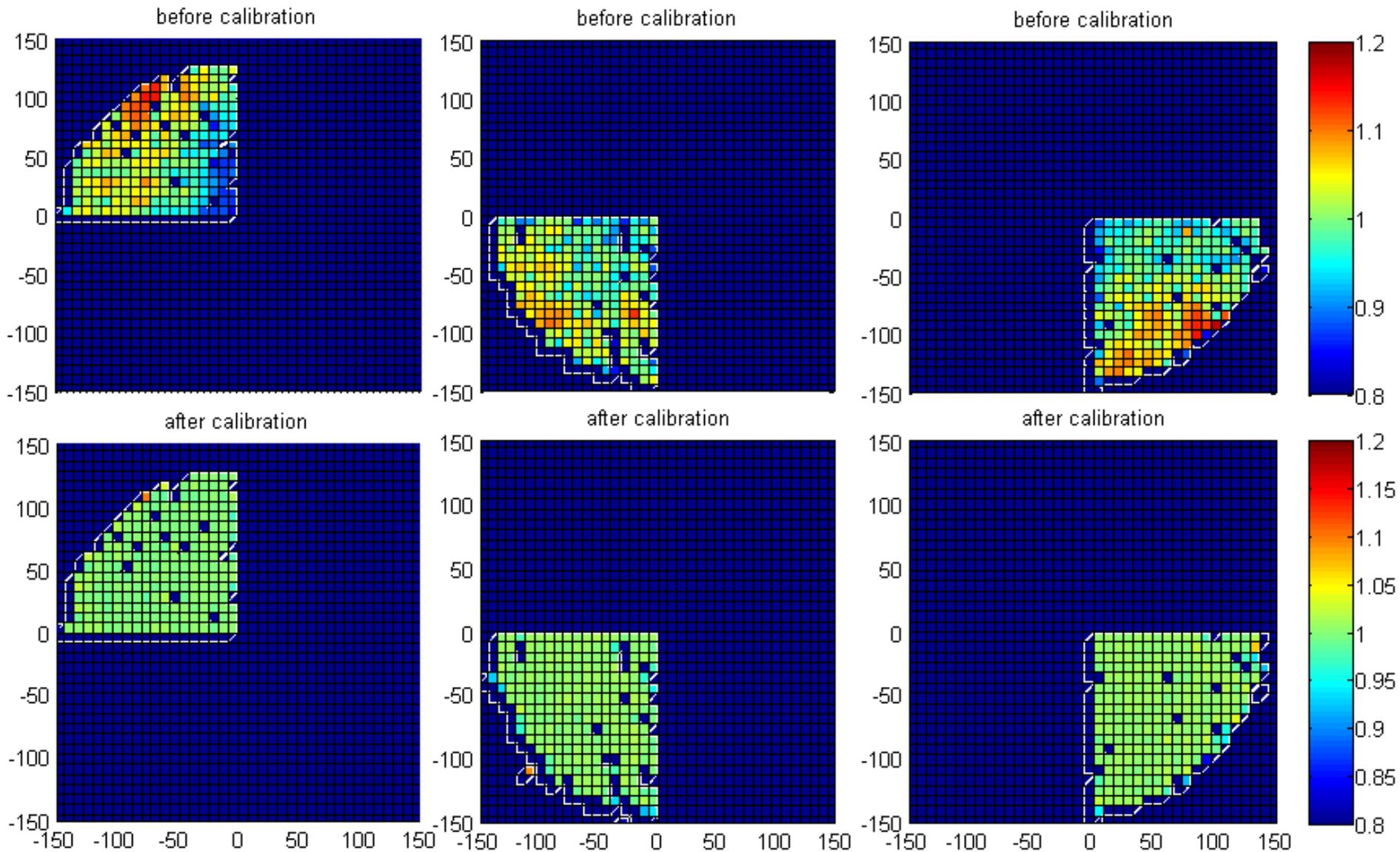
sector 1 to be repaired for the HP-campaign

blob position at x-y plane



tails mainly due to i) field edge effects, ii) bad event containment, iii) to a minor extent to unconnected pixels

gain maps are necessary in order to achieve ultimate resolution

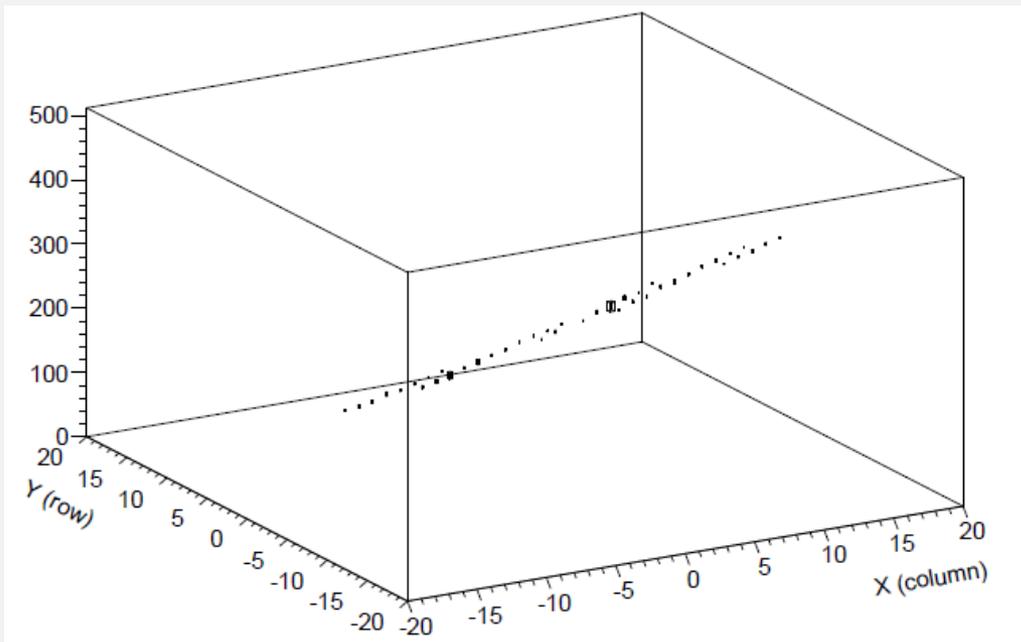
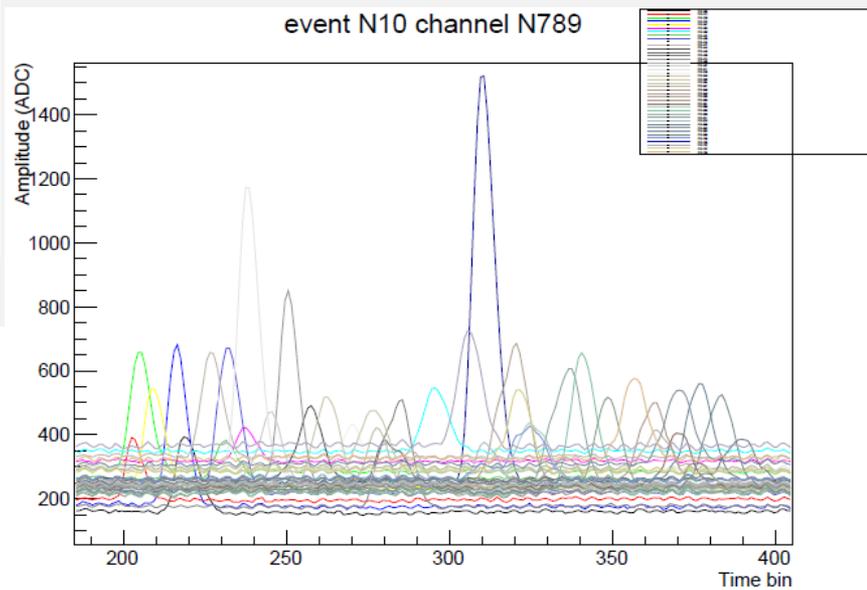
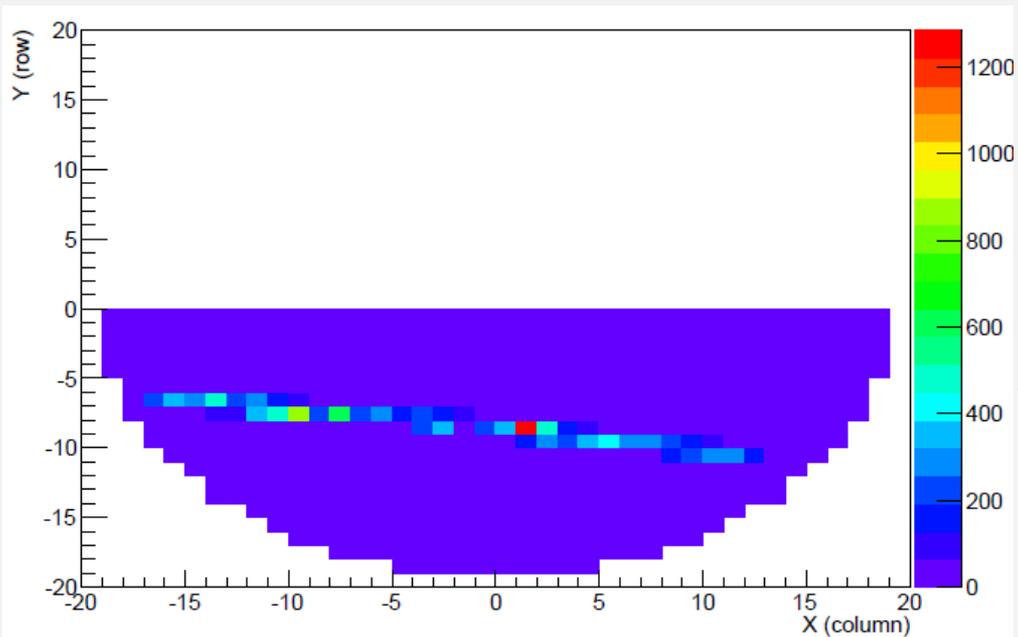


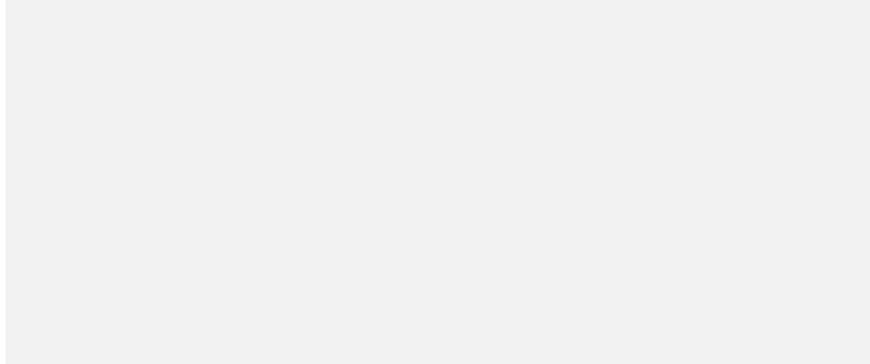
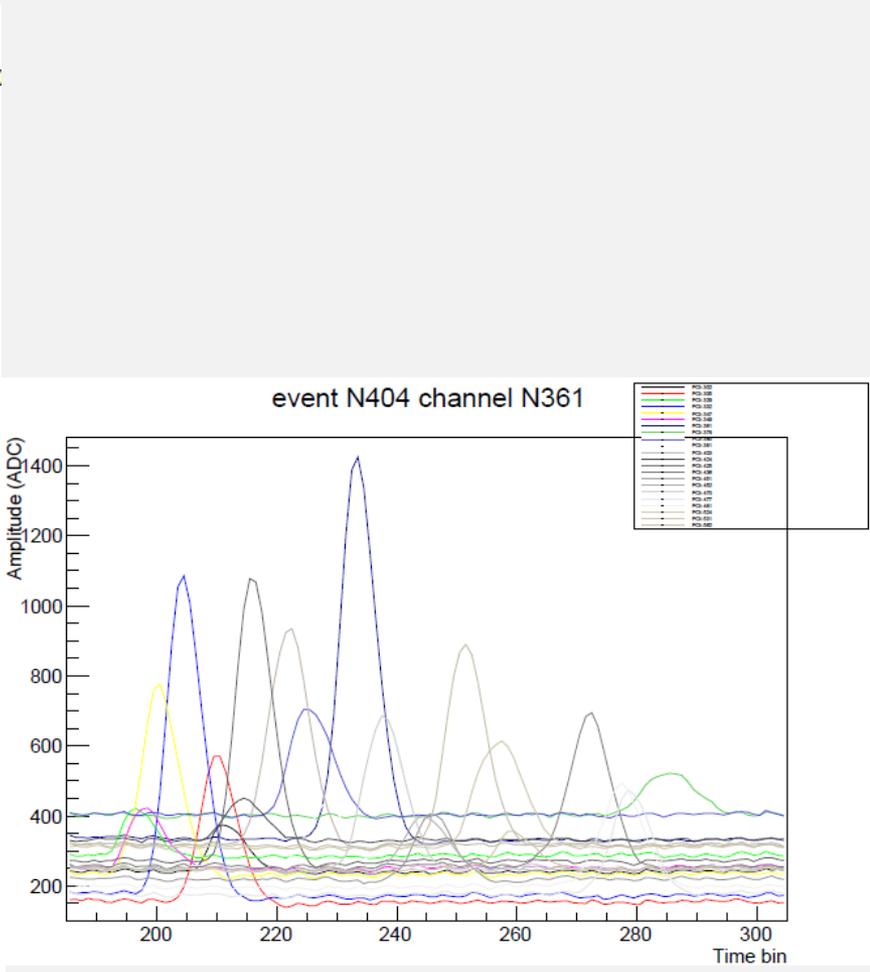
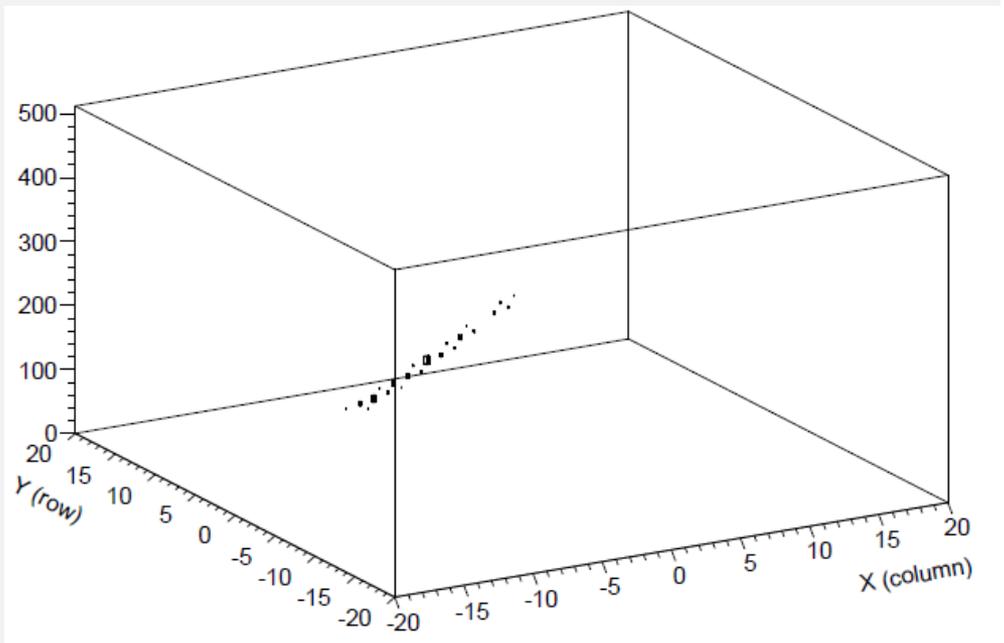
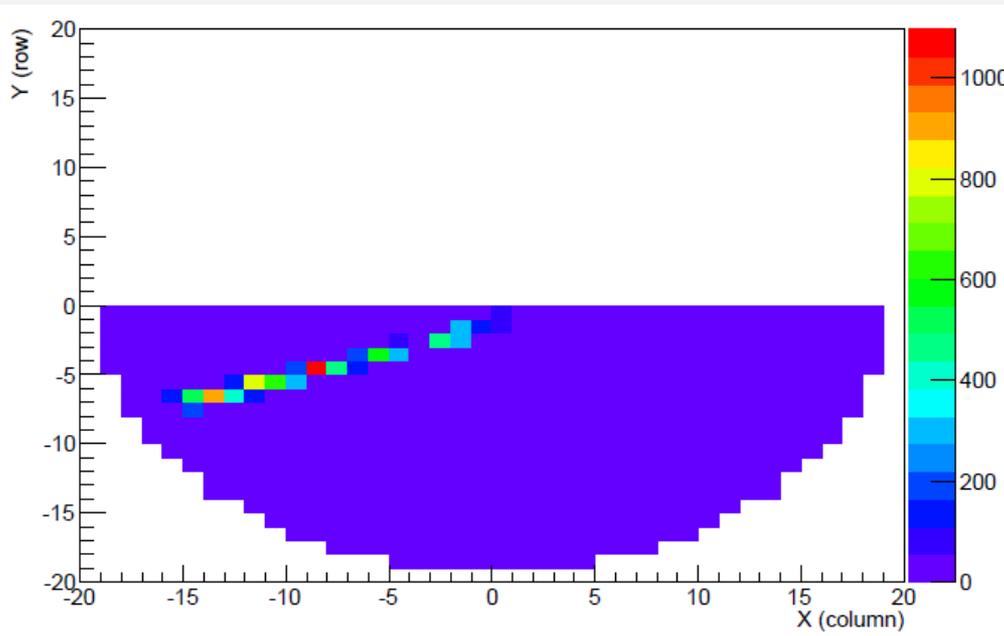
some typical events
(from old run: only lower half
instrumented)

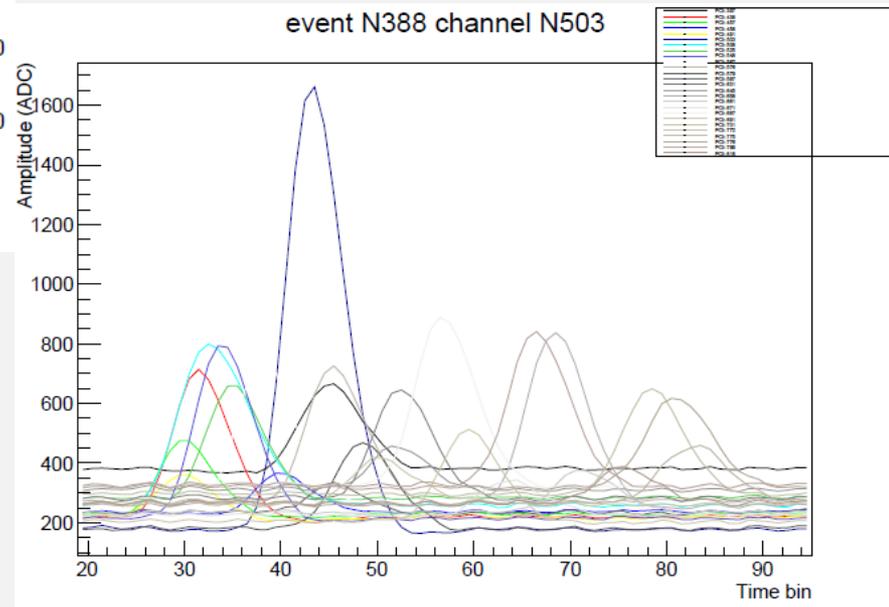
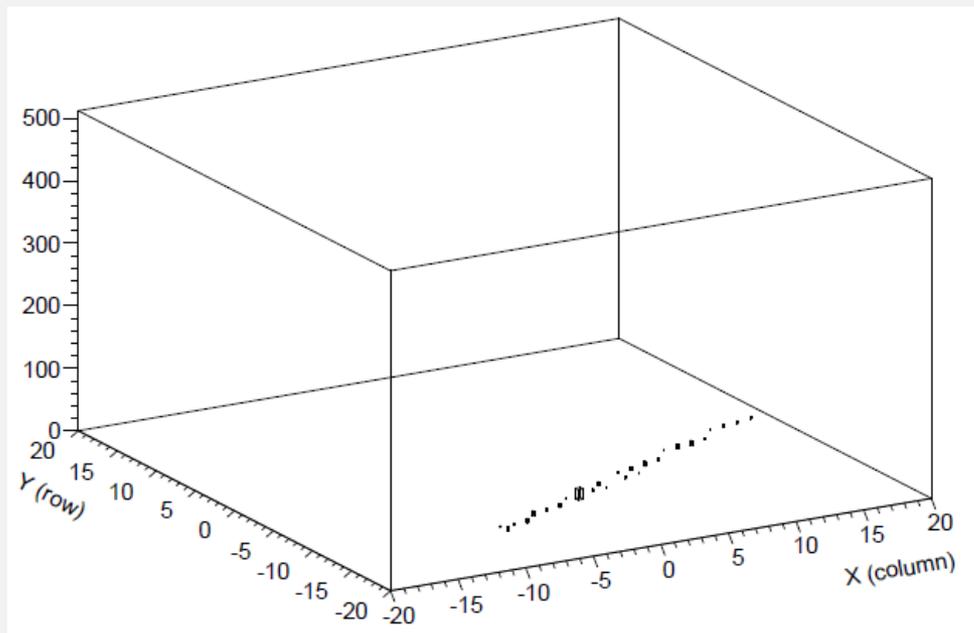
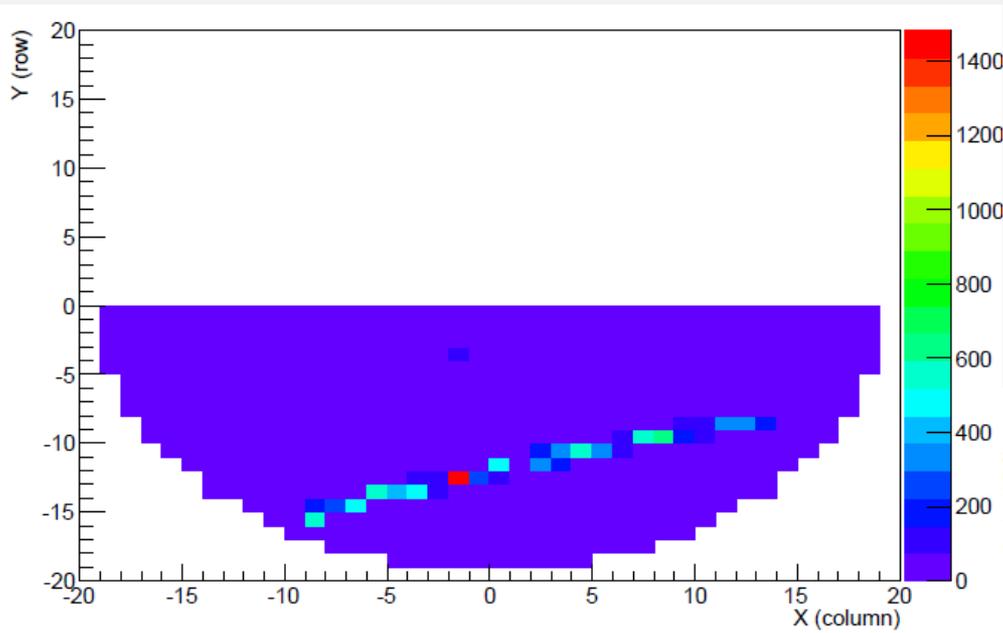
1. Muons

in random coincidence with
trigger

(no analysis, just selection on the
event display)



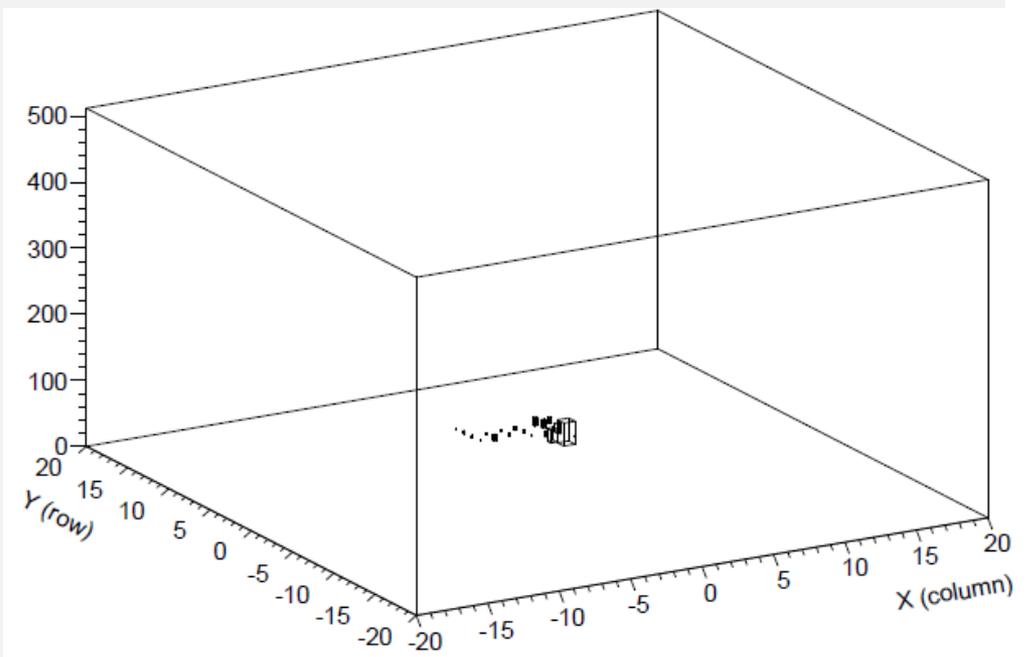
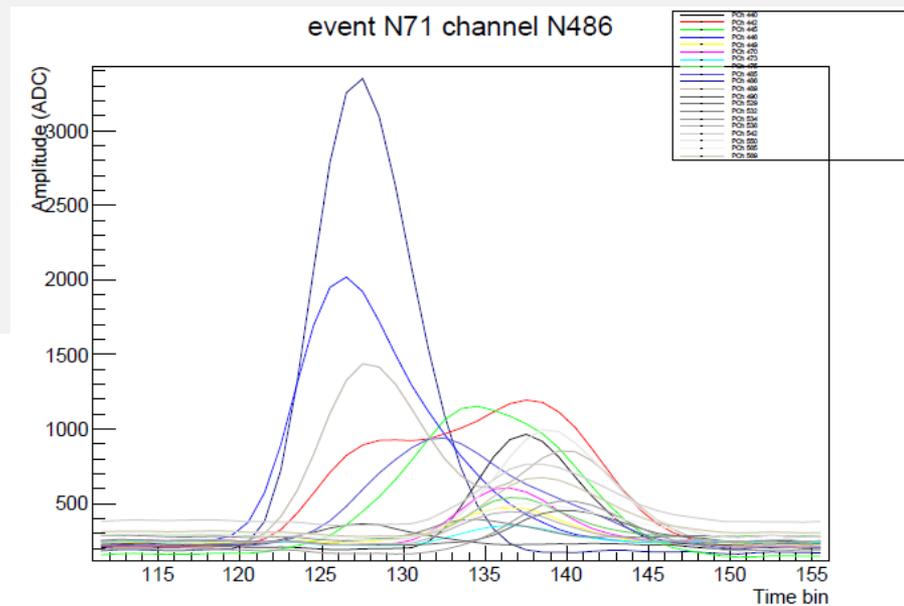
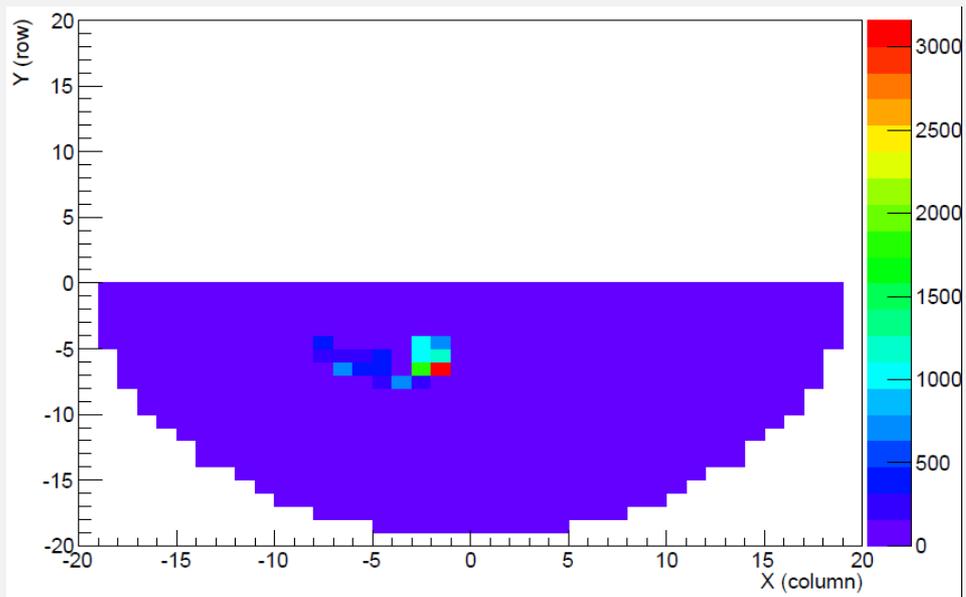


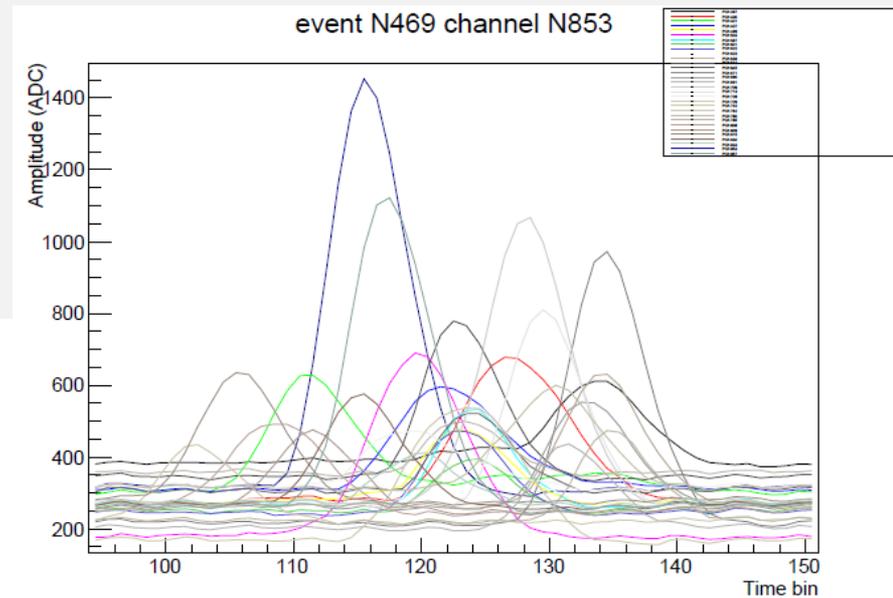
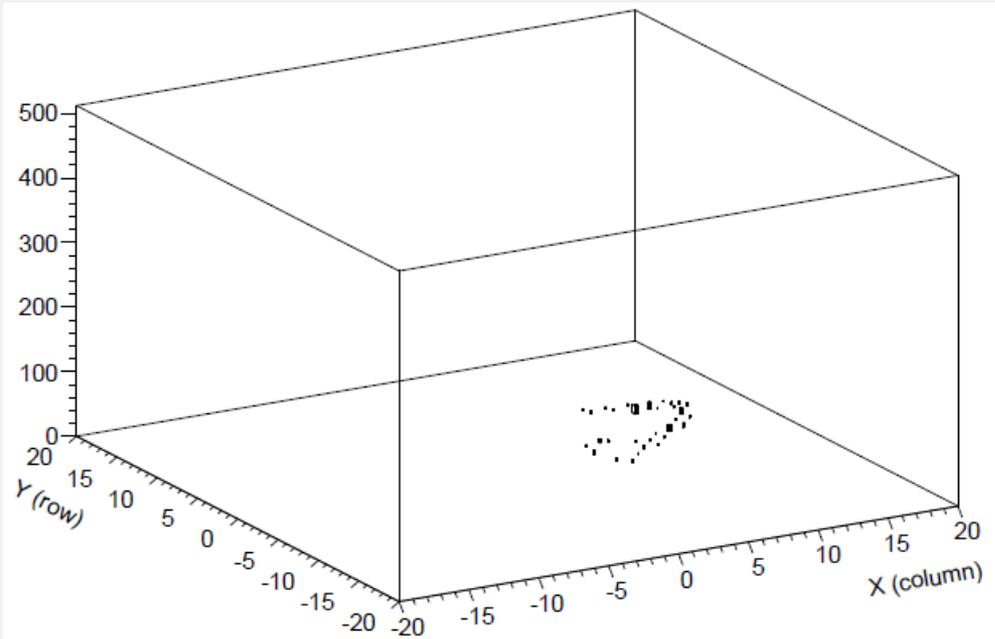
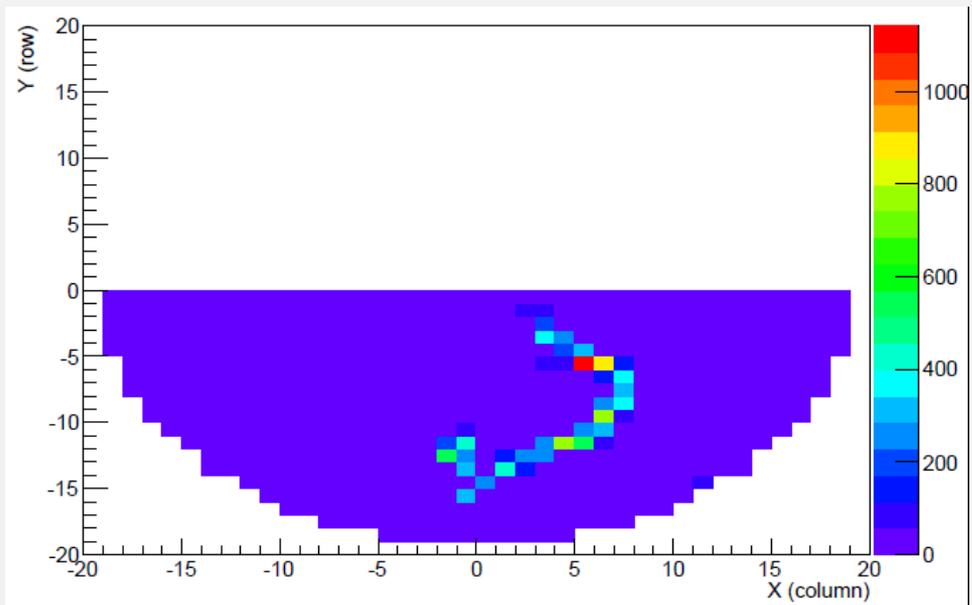


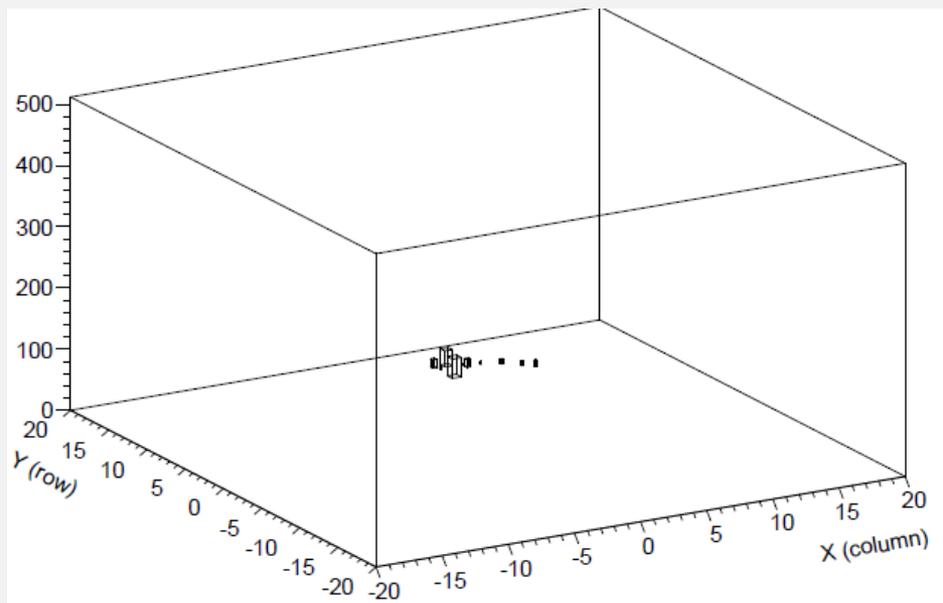
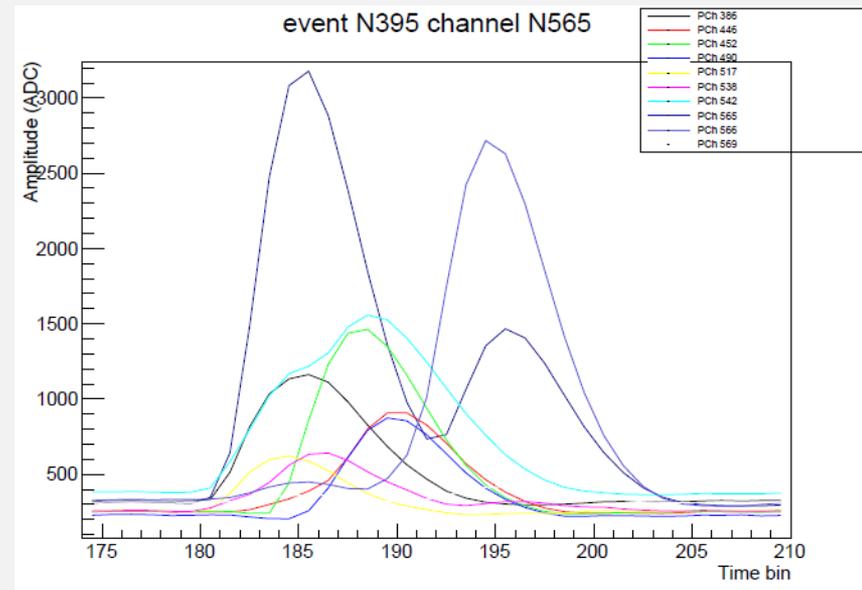
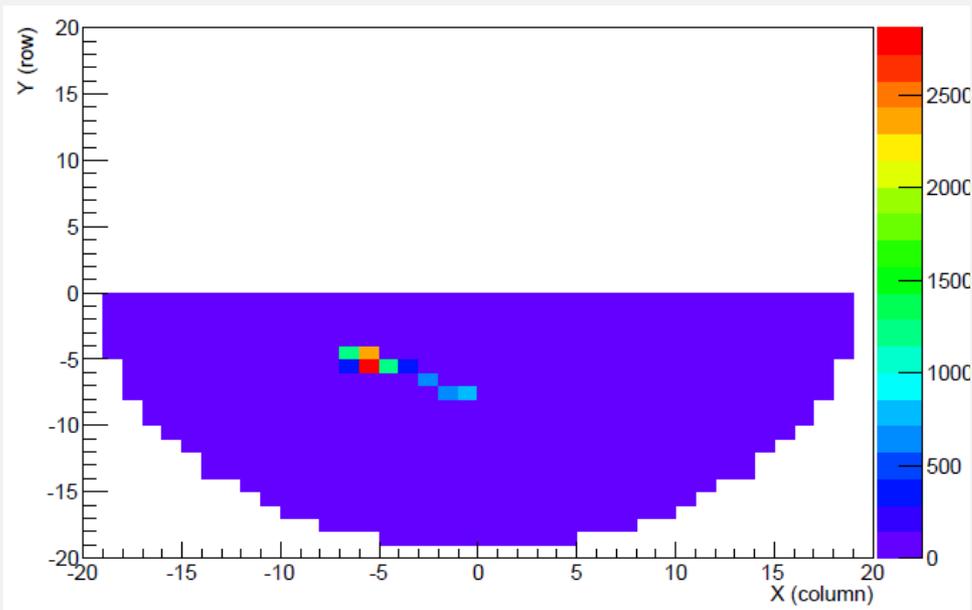
2. Low energy electrons

in random coincidence with trigger

(no analysis, just selection on the
event display)



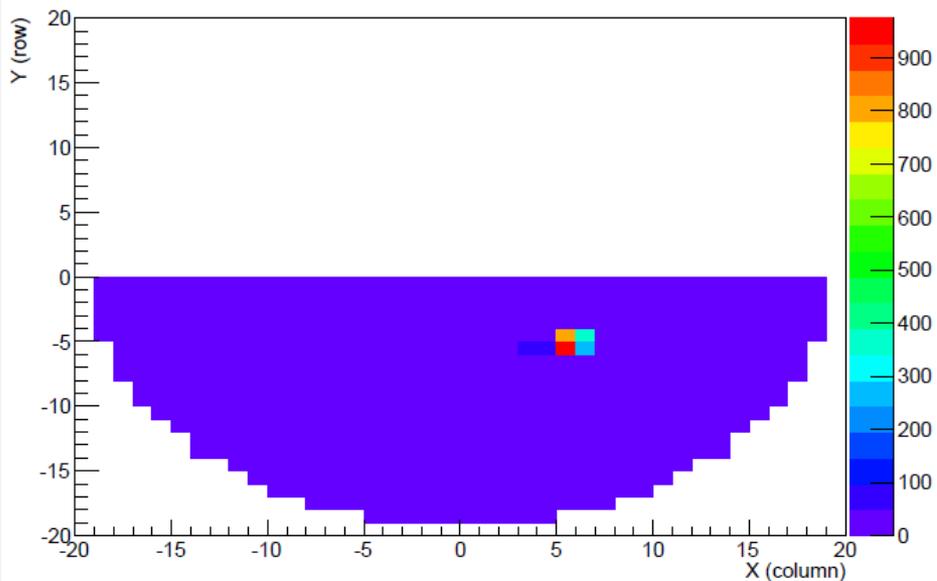




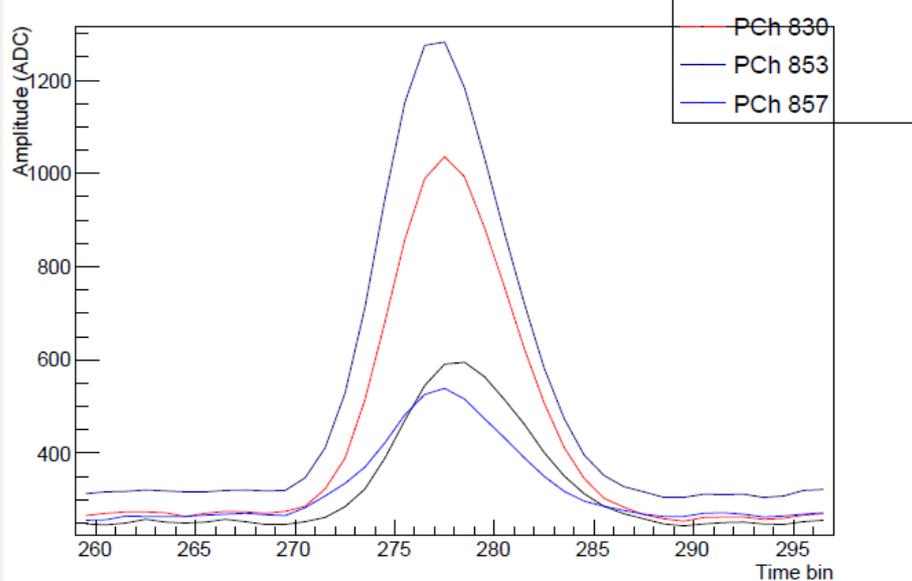
3. ~30keV escape-peak photons
(59.5keV-[29.8-33.6]keV K-shell)

(selection after analysis)

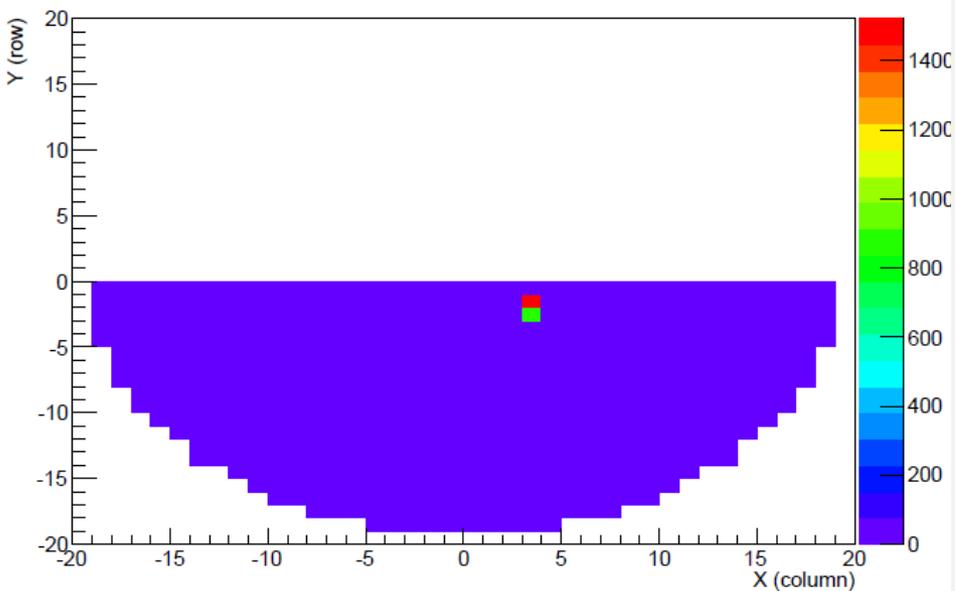
ReadoutMap



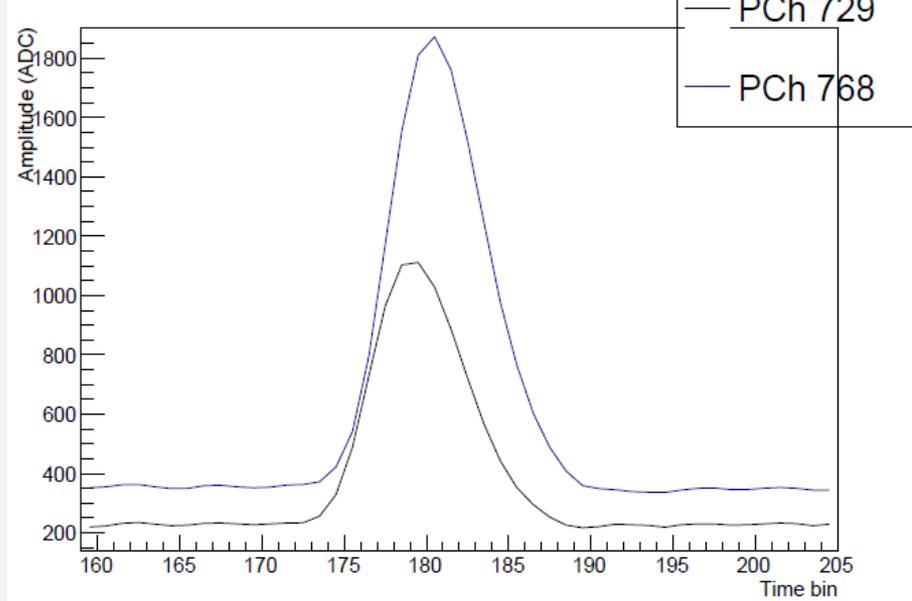
event N36464 channel N853



ReadoutMap



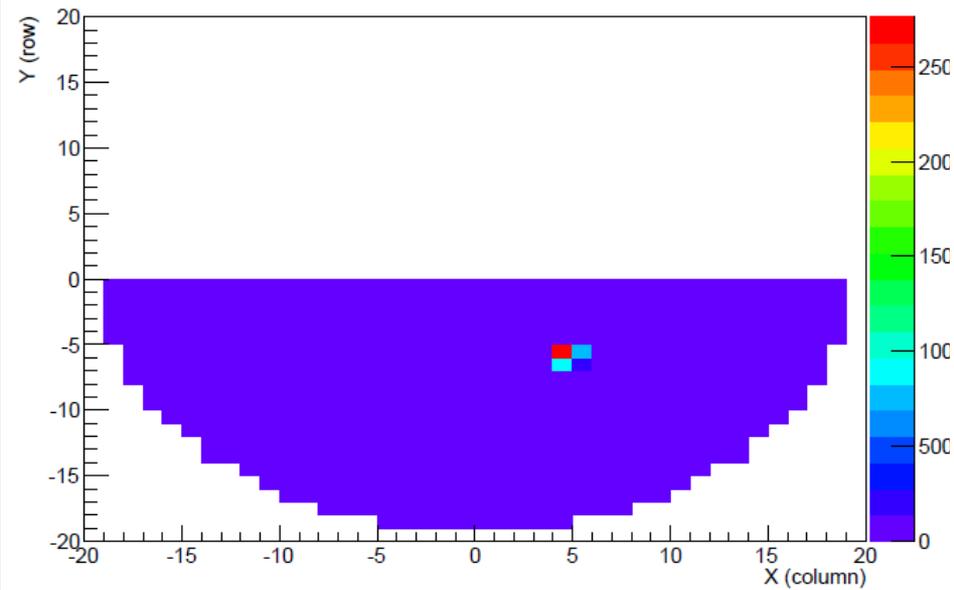
event N36869 channel N768



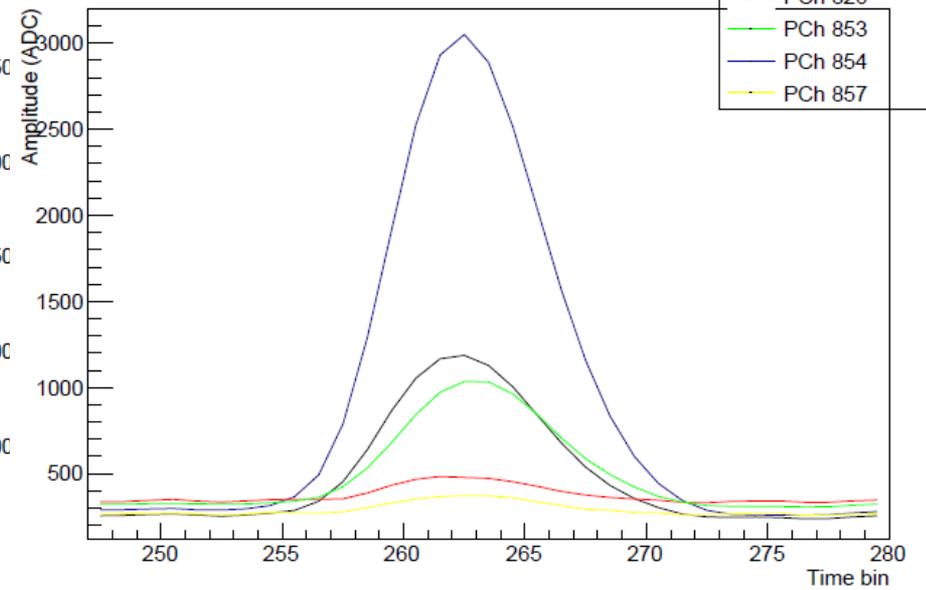
4. Full absorption 59.5keV (1blob)
(after *a*) Auger cascade following
ionization of K-shell or *b*) ionization
from external shells, or *c*) $K_{\alpha,\beta}$ re-
absorbed in the local neighborhood)

(selection after analysis)

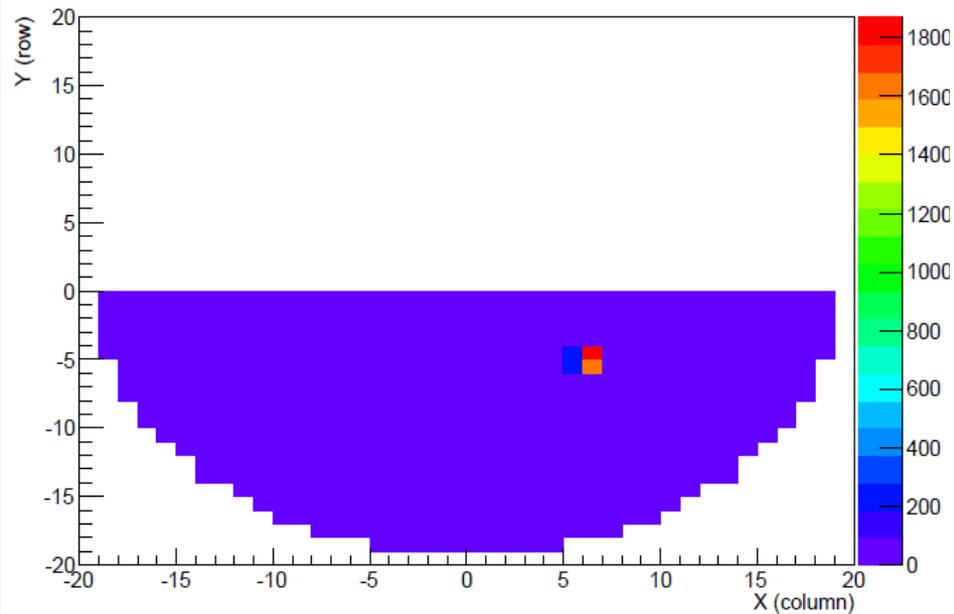
ReadoutMap



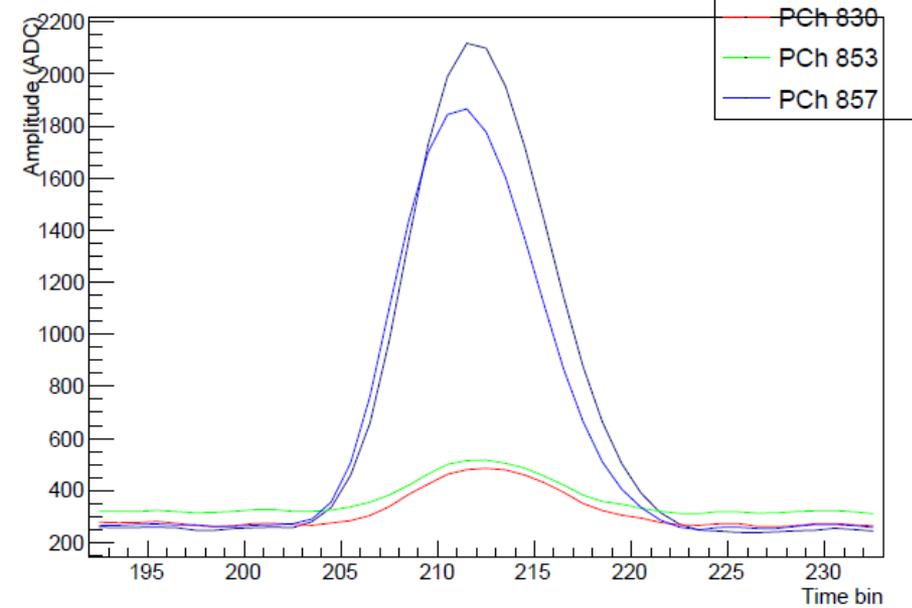
event N20299 channel N854



ReadoutMap

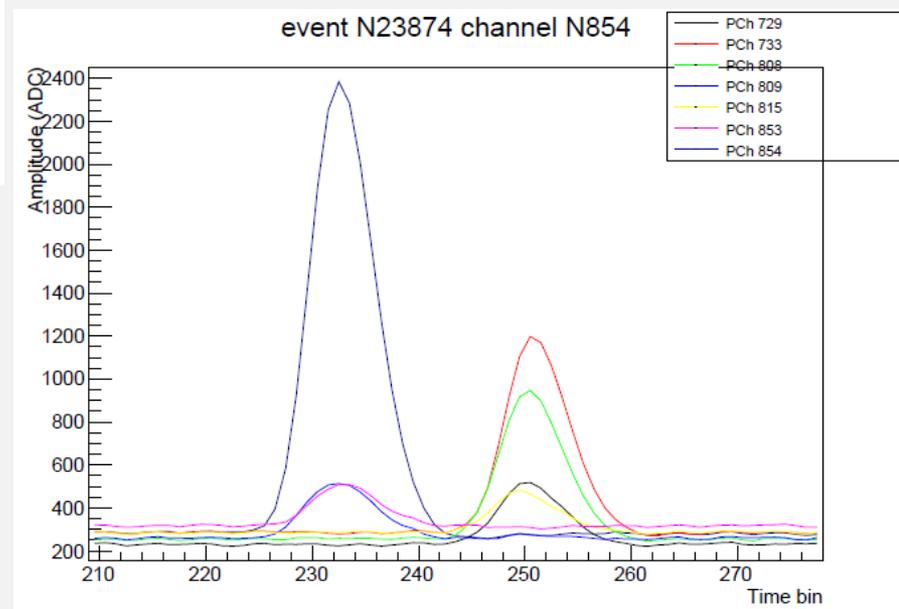
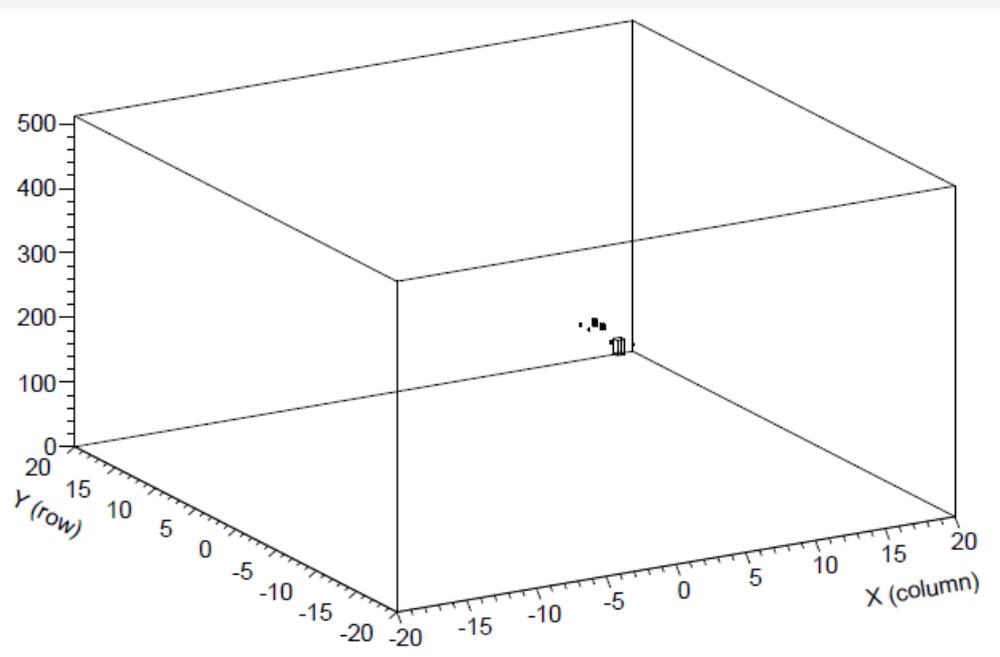
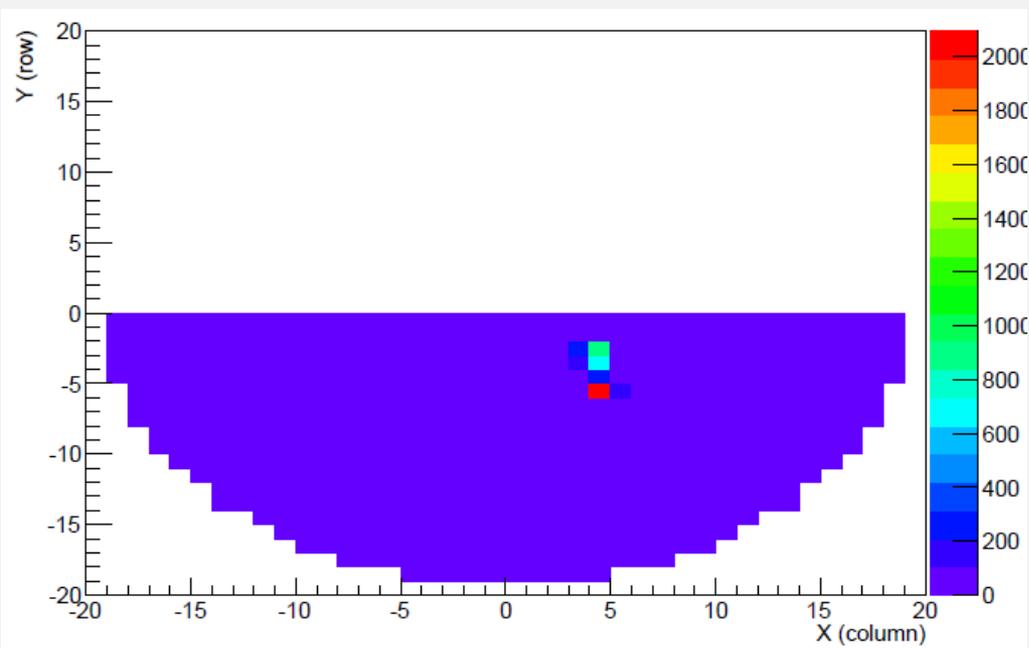


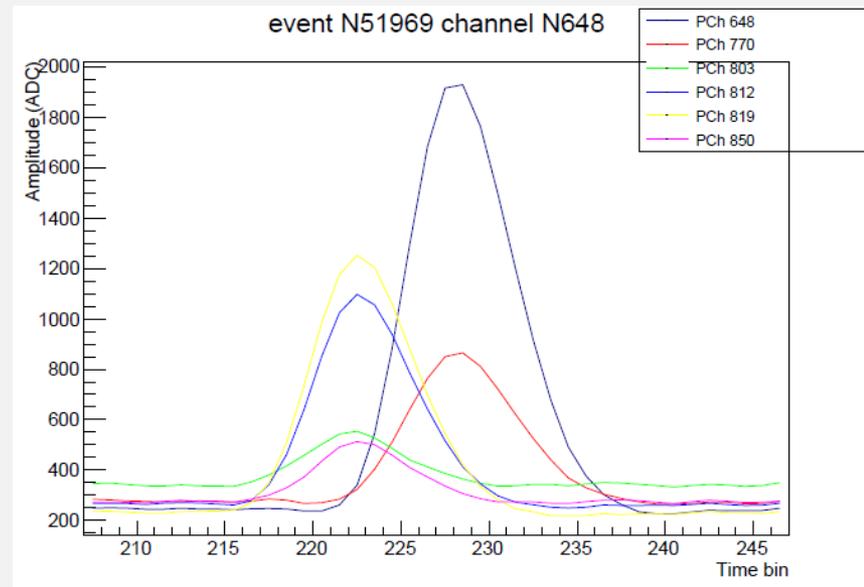
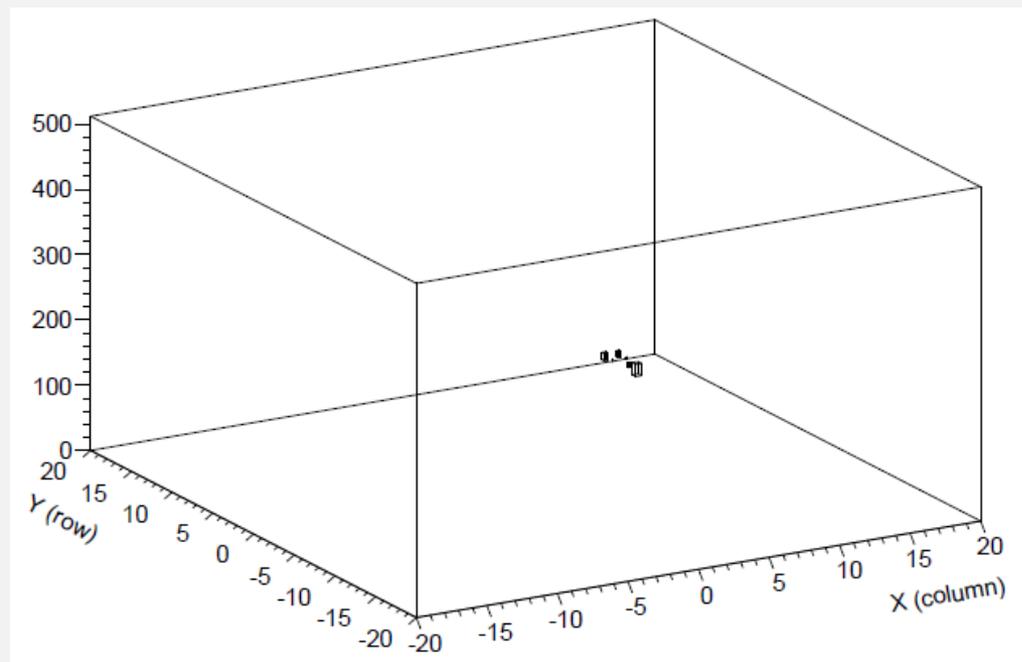
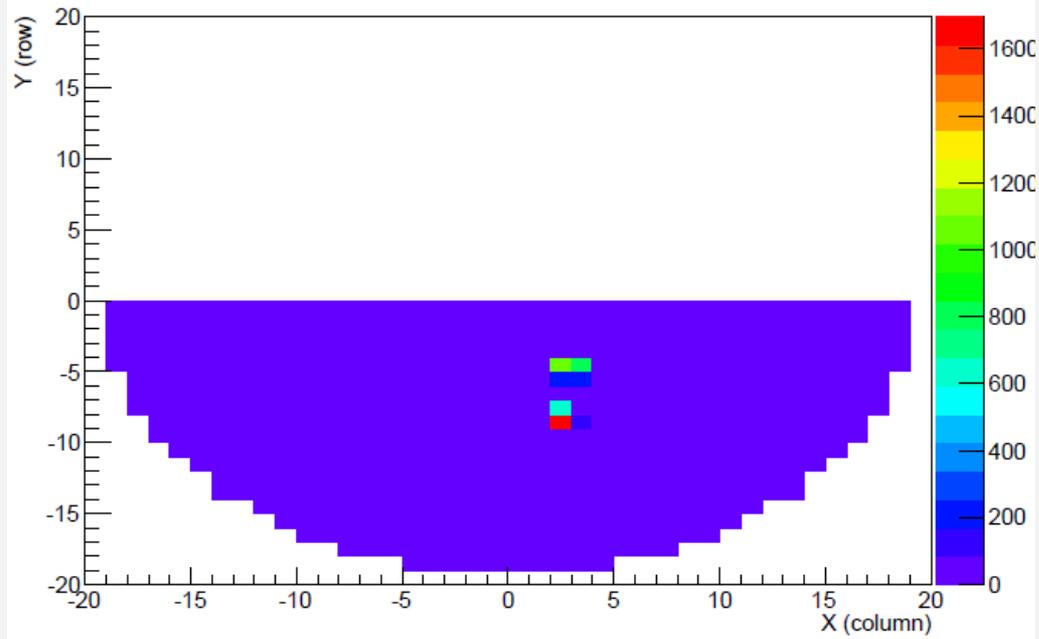
event N29476 channel N822

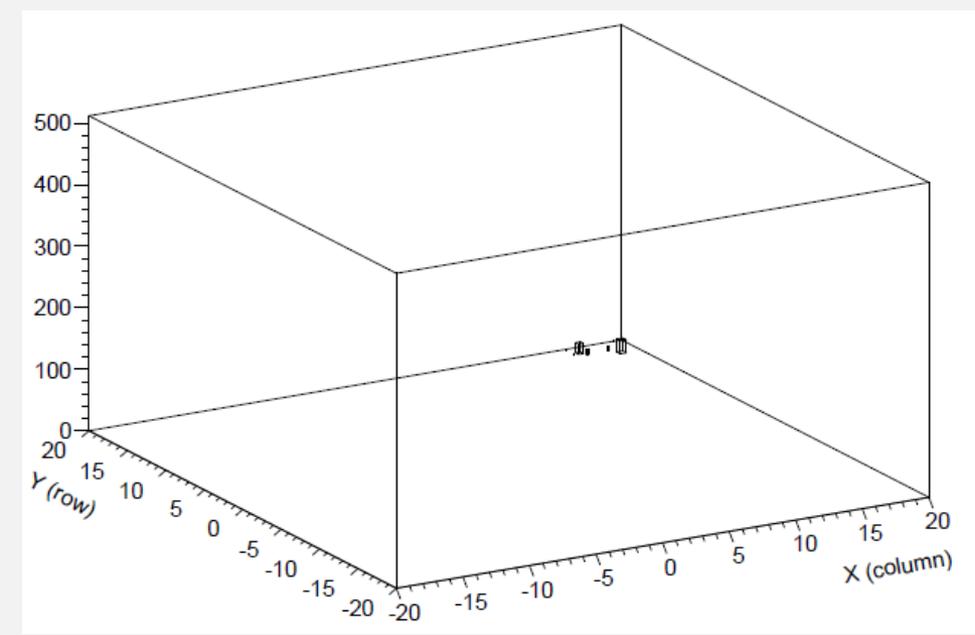
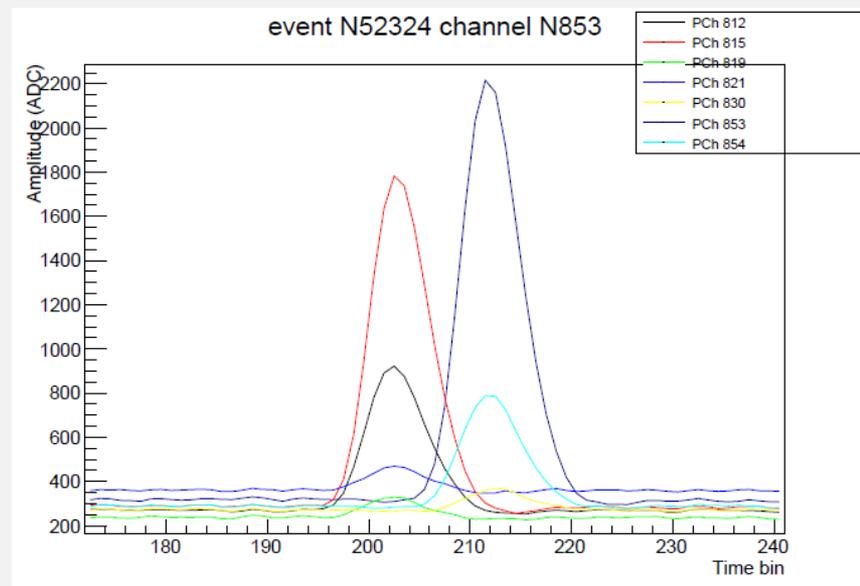
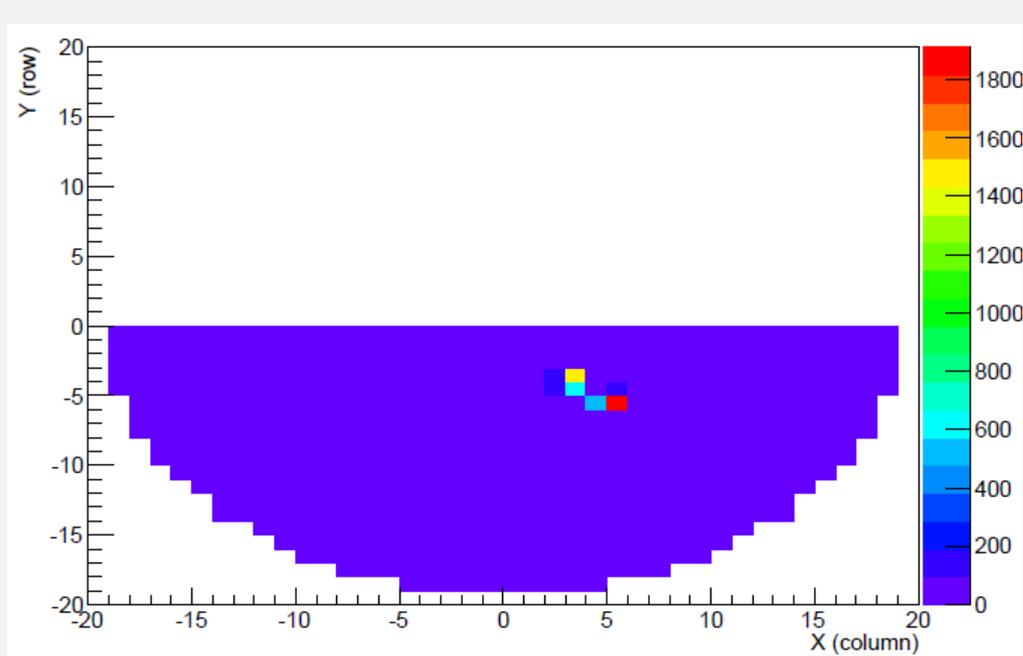


5. Full absorption 59.5 keV (2blobs)
($K_{\alpha,\beta}$ re-absorbed at a distant position)

(selection after analysis)

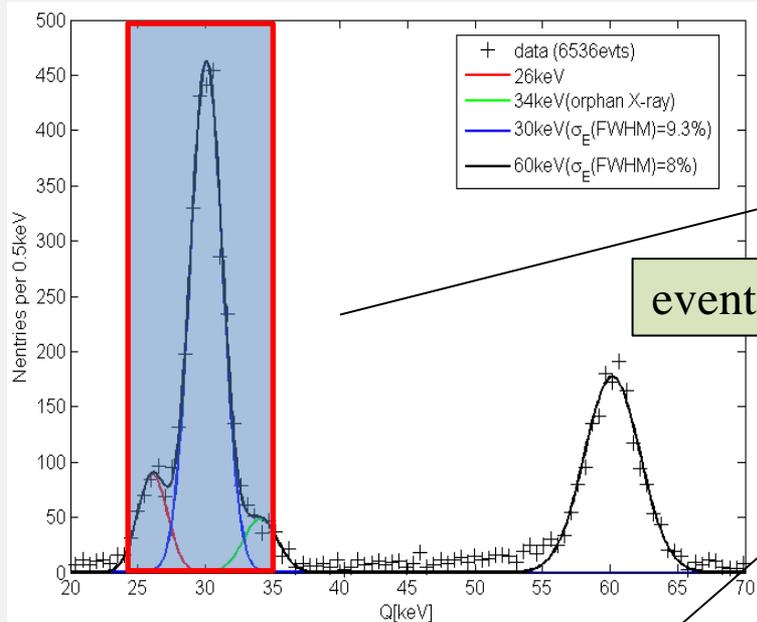




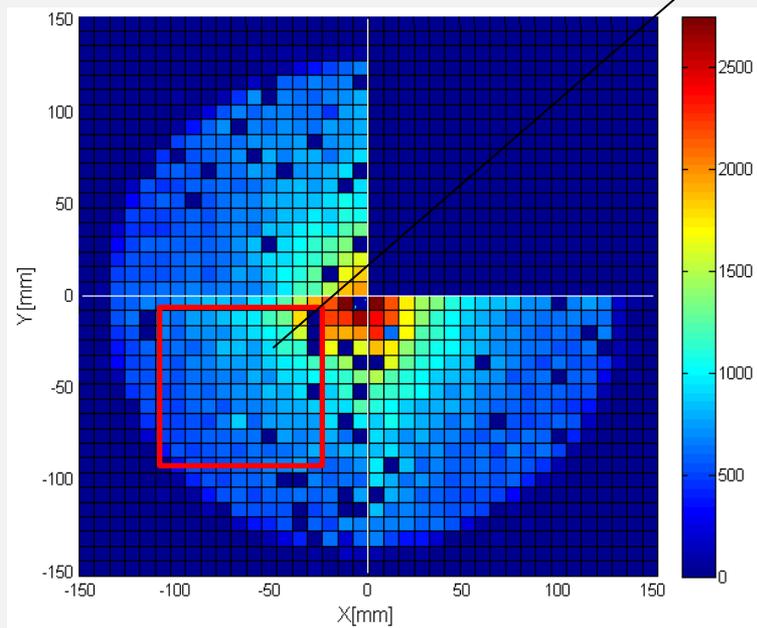
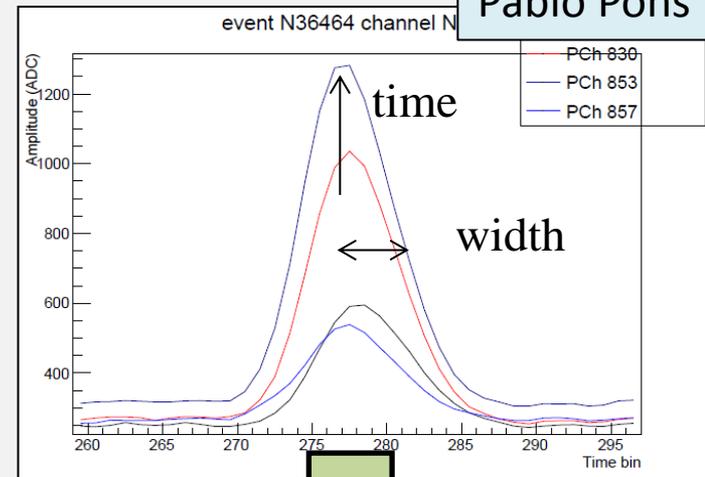


Part 2: identifying the relevant parameters of the electron swarm with the commissioned system.

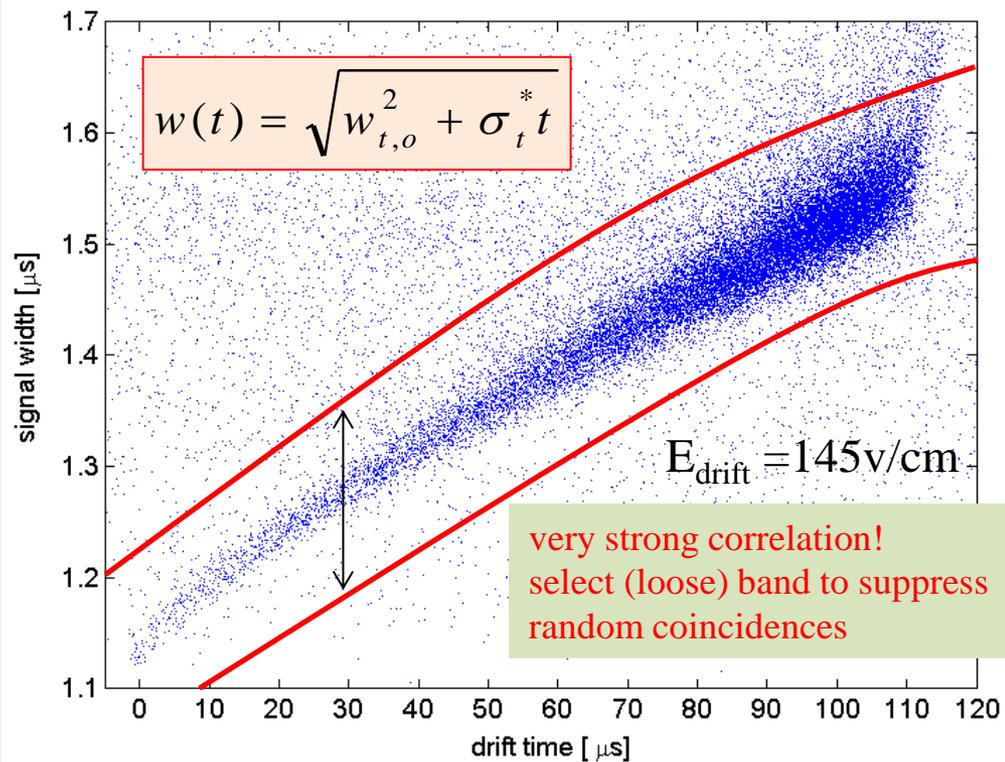
Simple (standard) pulse shape analysis (Gaussian fit)



event selection

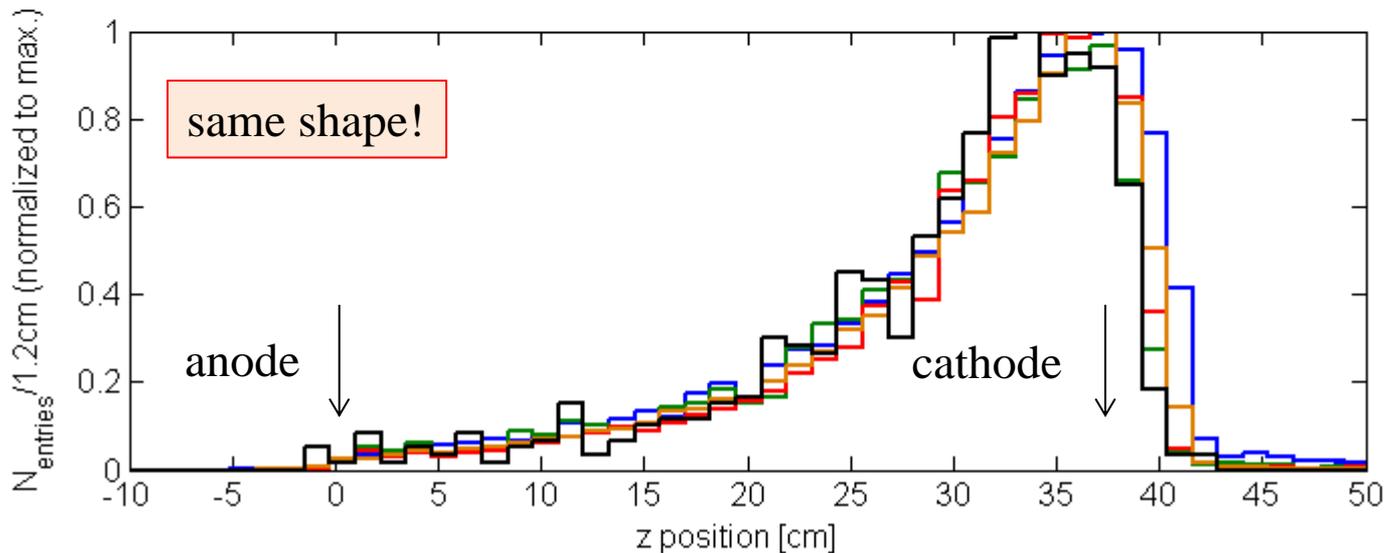
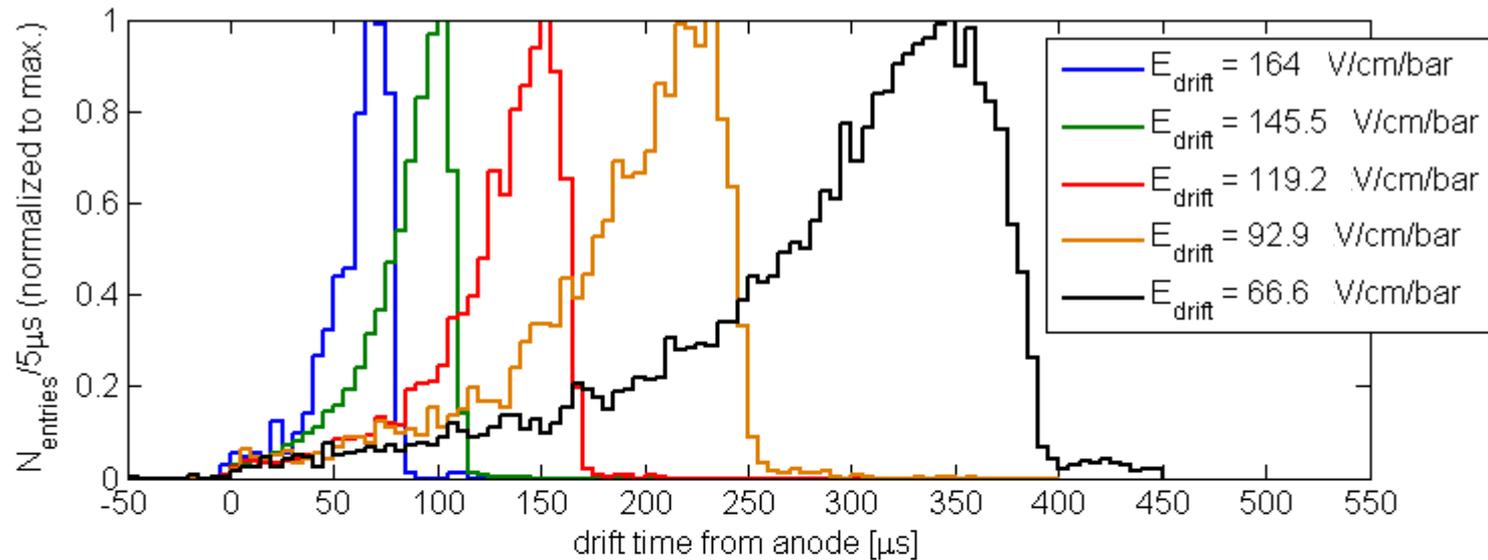


behavior of pulse containing the highest charge

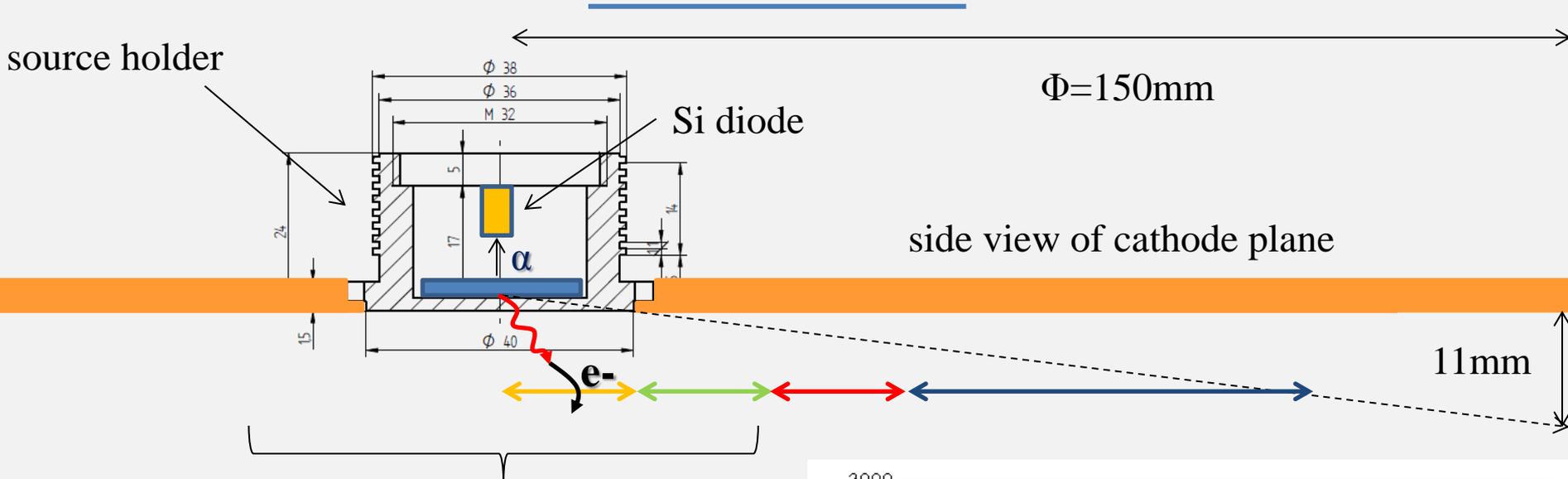


Part 2.1: drift velocity

1. Obtain drift velocity by re-scaling time-distributions to a common z-profile

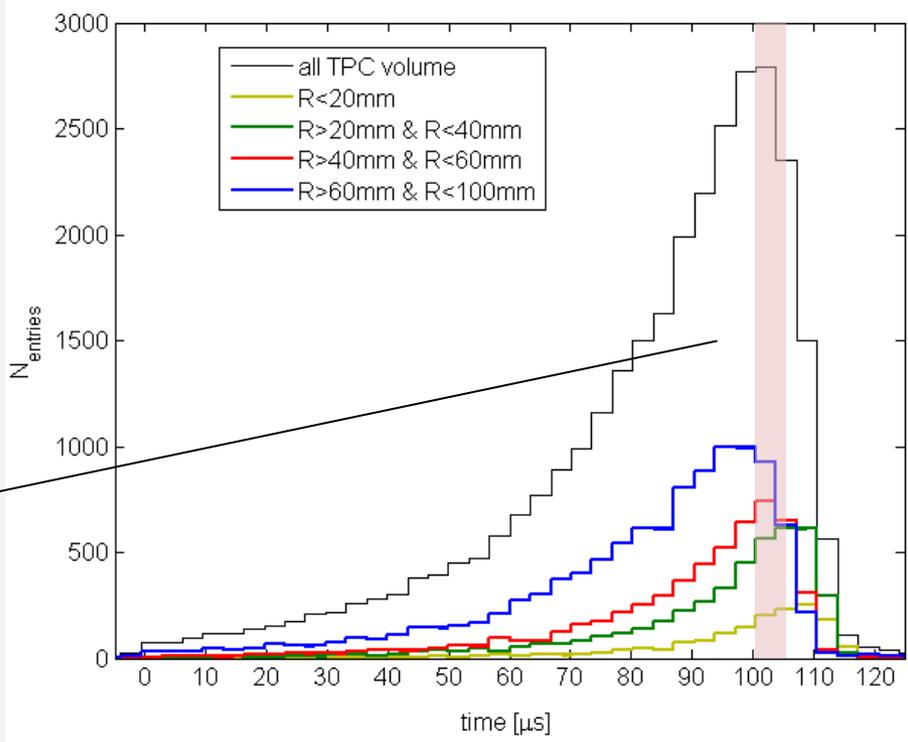


2. Systematic uncertainties involved in drift velocity calculation (dependence with radial position)



Region where fringe fields are important (they create tails towards delayed times)

- We assign a **5% uncertainty** to the definition of the z-position of the cathode due to this geometrical effect.
- $R_{e,csda}=6\text{mm}@1\text{bar}$ (very small residual effect: $6\text{mm}/380\text{mm}=1.5\%$)



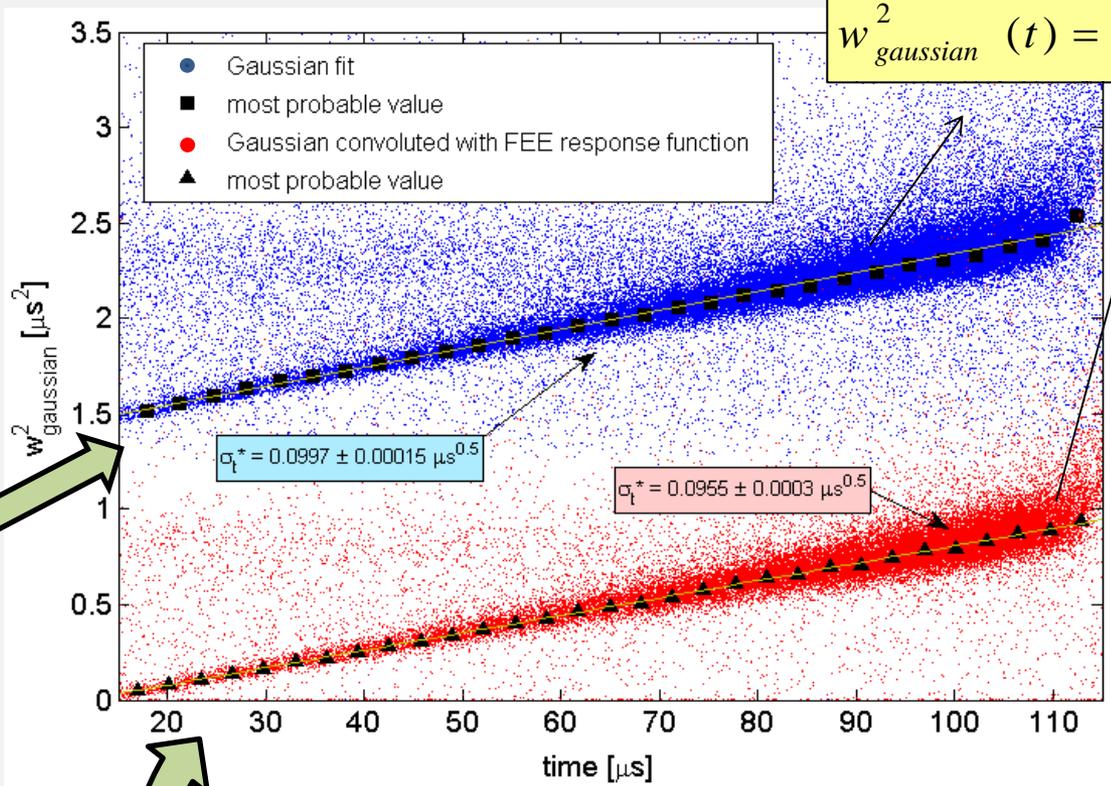
←

Part 2.2: longitudinal diffusion

$\tau_e > 2\text{ms}$ for all measurements

1. Study 2 different analysis procedures

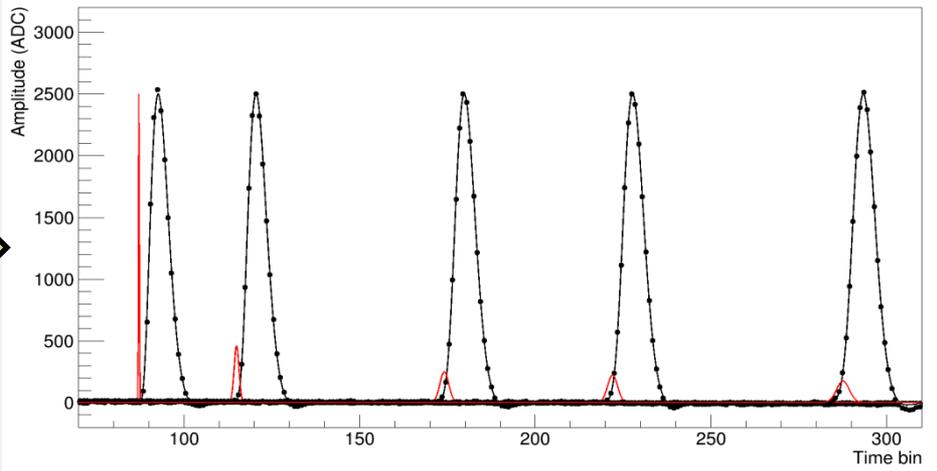
$$w_{\text{gaussian}}^2(t) = w_o^2 + (\sigma_t^*)^2 \cdot t$$



1. width obtained from simple Gaussian fit (default analysis)

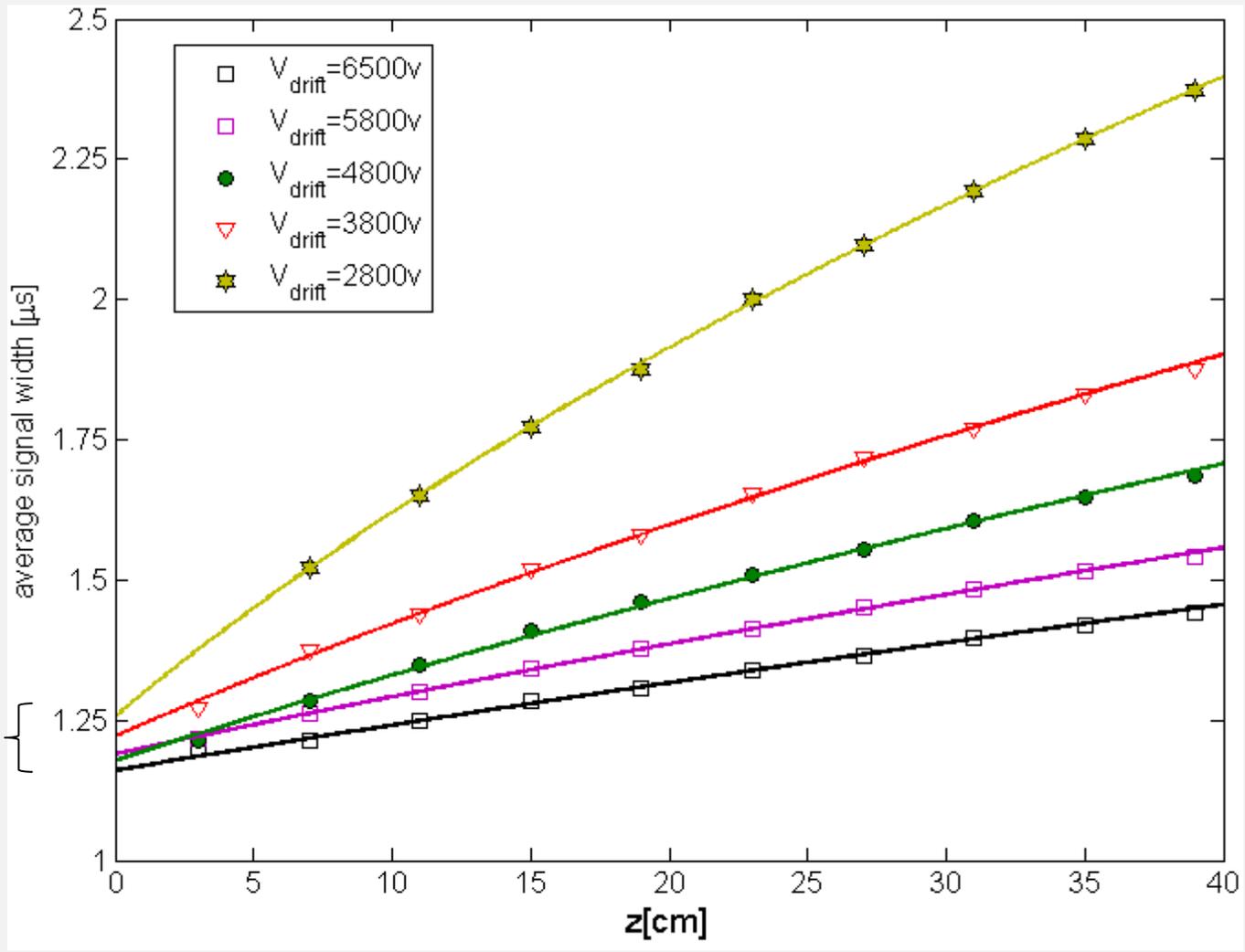
2. width obtained from convolution of Gaussian to FEE response function (numerically costly):

$$f(t) = e^{-3t/\tau} (t/\tau)^3 \sin(t/\tau) \otimes e^{-(t-t_o)^2/2\sigma_t(t)^2}$$



$\tau_e > 2\text{ms}$ for all measurements

2. Fit the most probable values to the expected behavior



Width₀ depending on:
- Ion transit time.
- Track geometry.
- FEE response.



Very little dependent on drift voltage!

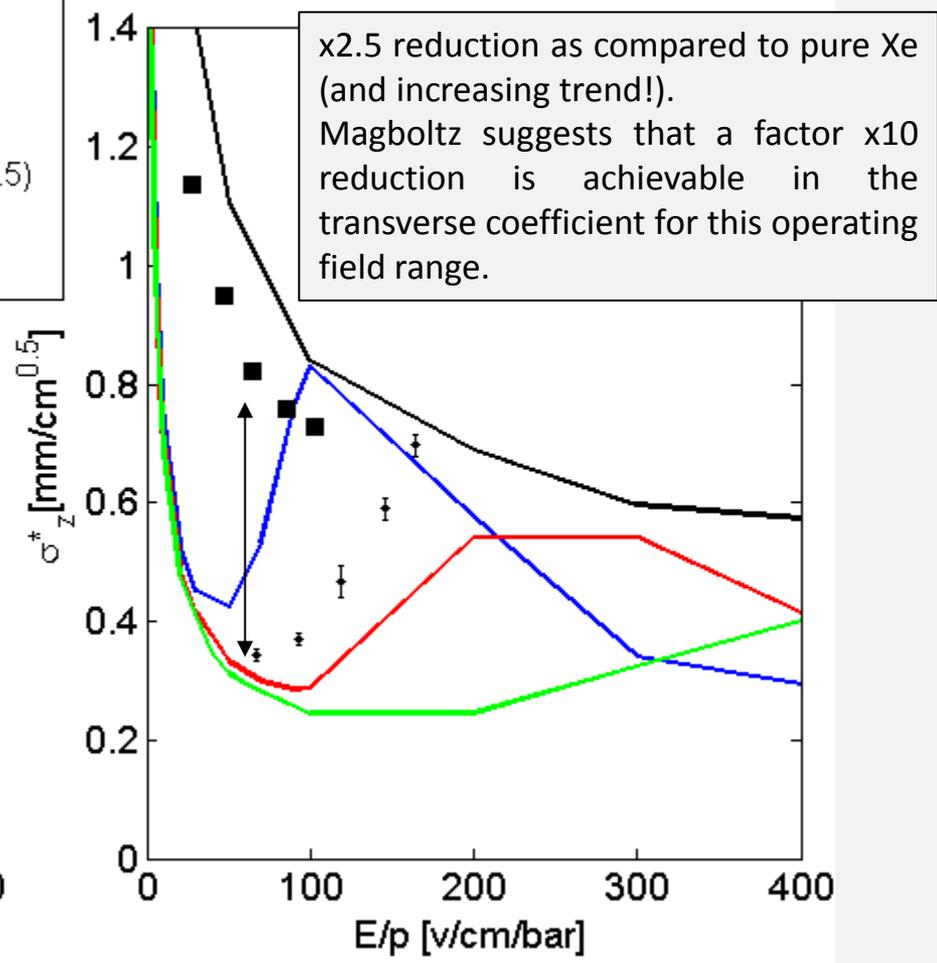
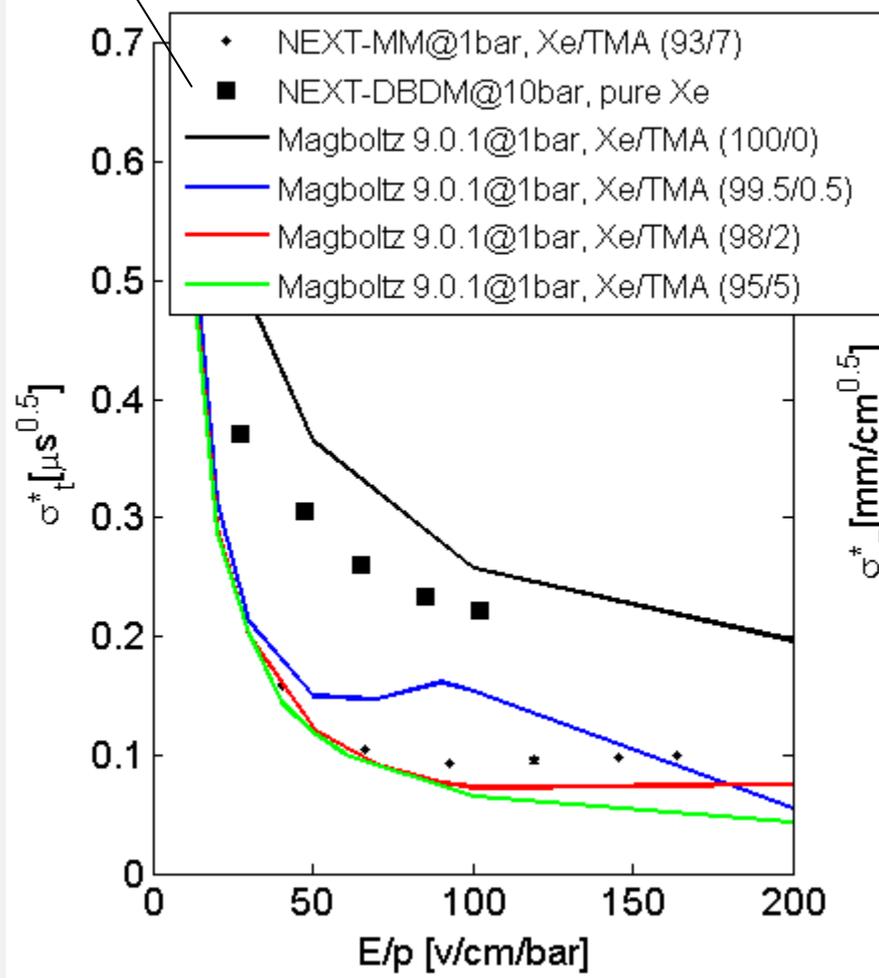
$\tau_e > 2\text{ms}$ for all measurements

longitudinal diffusion compilation

Scaled up by \sqrt{P}
to 1bar

$$\sigma_t = \sigma_t^* \sqrt{t} = \sqrt{\frac{2D_L}{v_d^2}} \sqrt{t}$$

$$\sigma_z = \sigma_z^* \sqrt{z} = \sqrt{\frac{2D_L}{v_d}} \sqrt{z}$$



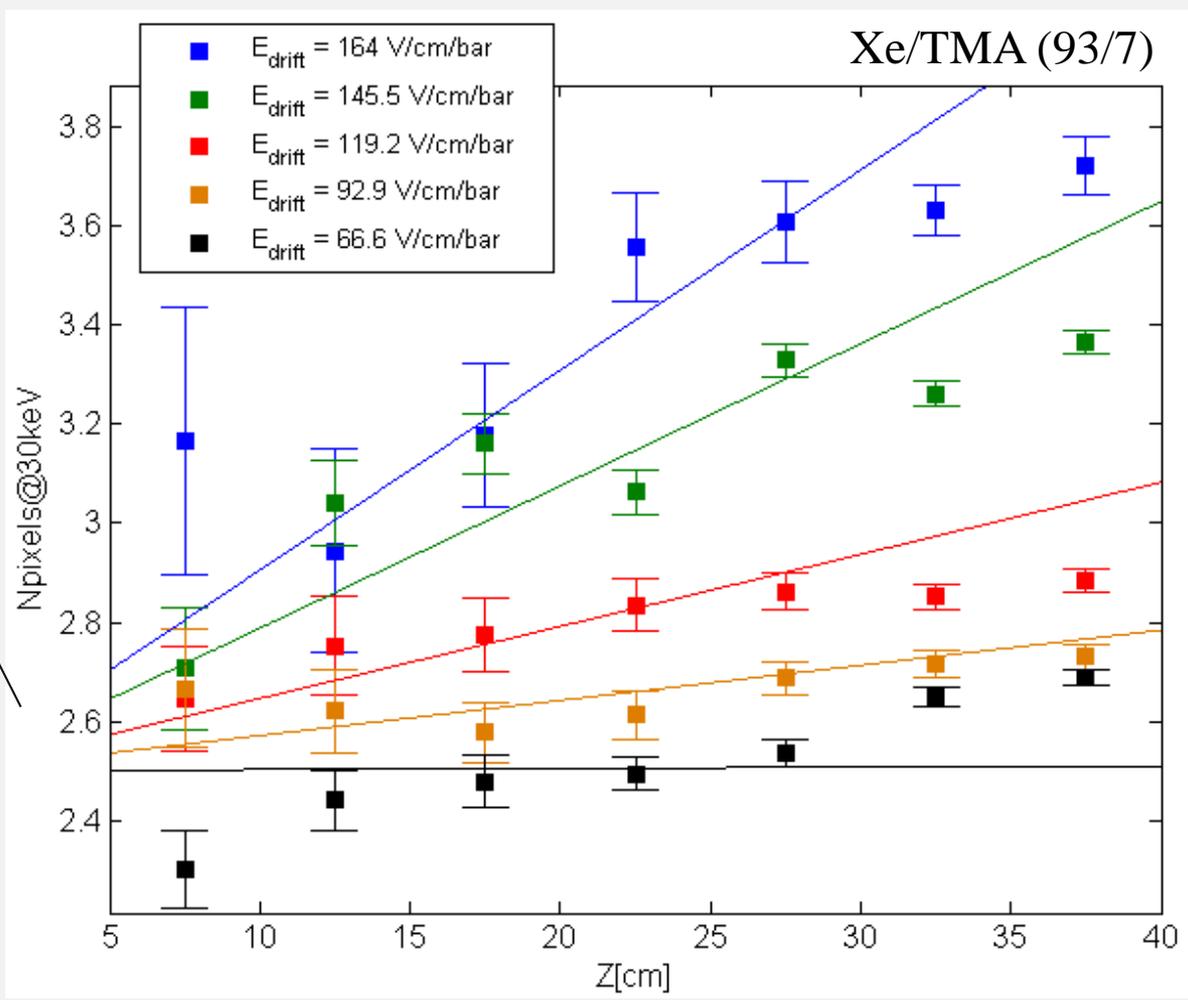
Very strong discrepancy with Magboltz 9.0.1!

Part 2.3: transverse diffusion
(expectedly a strength of this setup)

$\tau_e > 2\text{ms}$ for all measurements

pixel multiplicity

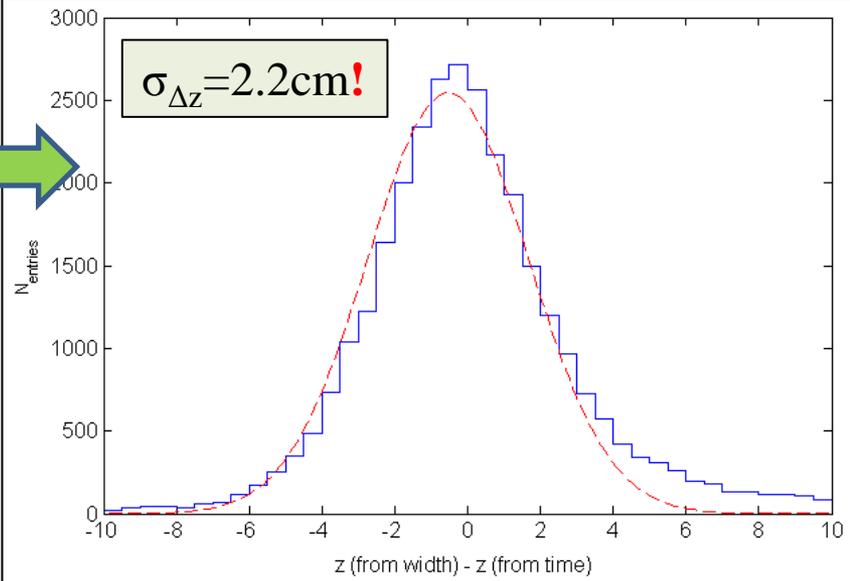
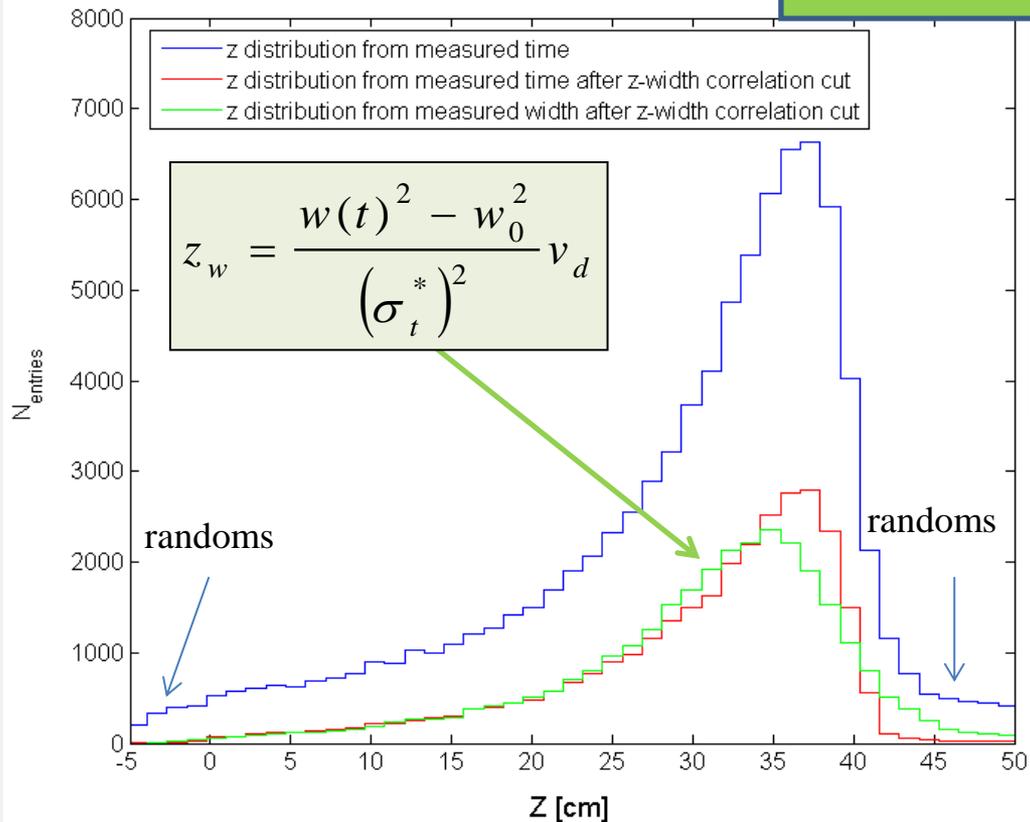
linear fit
(bound to 2.5)



Similar to σ_z^* [mm/ $\sqrt{\text{cm}}$], the transverse diffusion σ_r^* [mm/ $\sqrt{\text{cm}}$], clearly increases with the drift field in this operating range. However, extracting its value seems to require of a full simulation (ongoing), due to the very low hit multiplicity, or some smart idea...

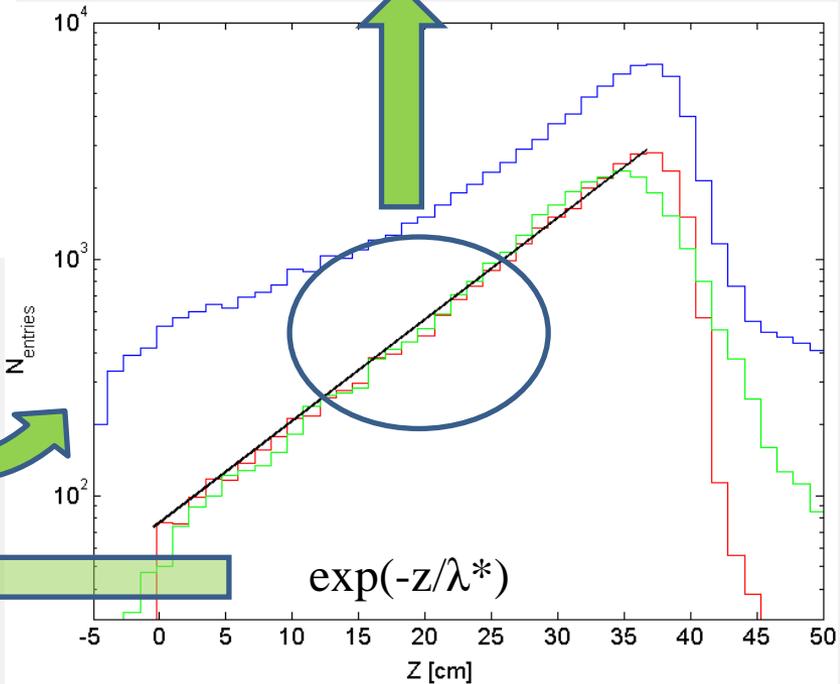
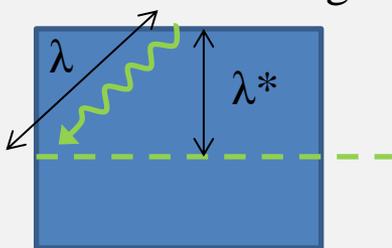
Part 2.4: extras

Position resolution estimated from signal width for a nearly point-like deposit (30keV@1bar)



very small dip due to reduced escape probability at the center of the chamber

$\lambda^* \approx 1/2 \lambda_{59.5\text{keV x-ray @ pure Xe}}$
 effective reduction due to geometry!

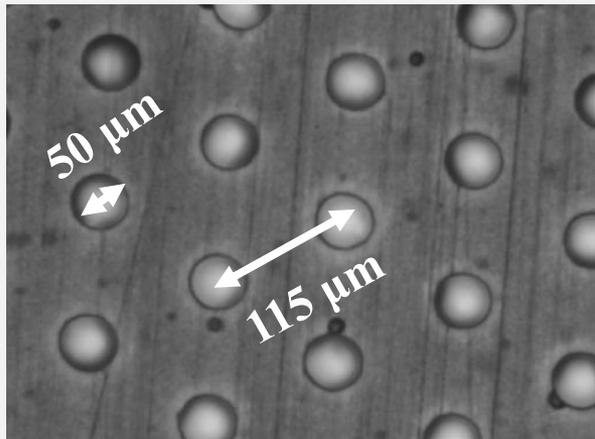


All TMA values from here on must be multiplied roughly by a factor x2 to correct for a calibration problem.

Part 3: Penning effect and energy resolution

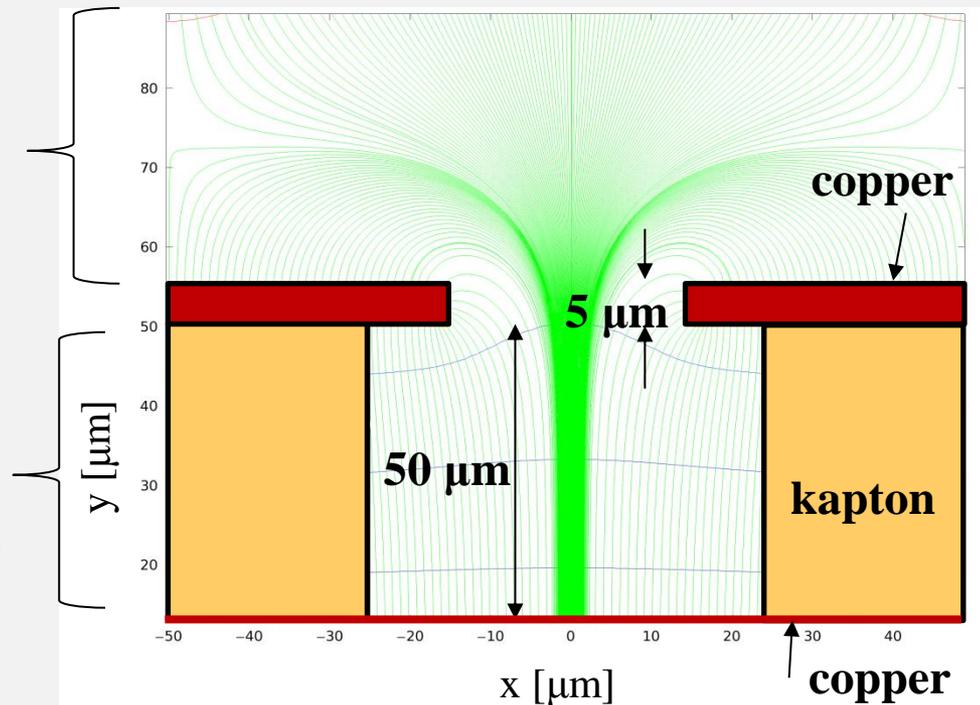
- A proper simulation of the electrons' drift through the field lines precludes a pure hydrodynamic modeling based merely on the parameters of the swarm.
- The short scale at which the electric field varies in the transition region between the drift region and the amplifying gap is comparable to the electrons' mean free path.
- Electrons will not fully achieve (in general) statistical equilibrium before the field orientation and module changes appreciably.
- A microscopic modeling is enforced -> Garfield++.

We have preliminary separated the problem in two parts:



transmission
(Garfield++
& COMSOL)

amplification
(Magboltz,
~uniform field)



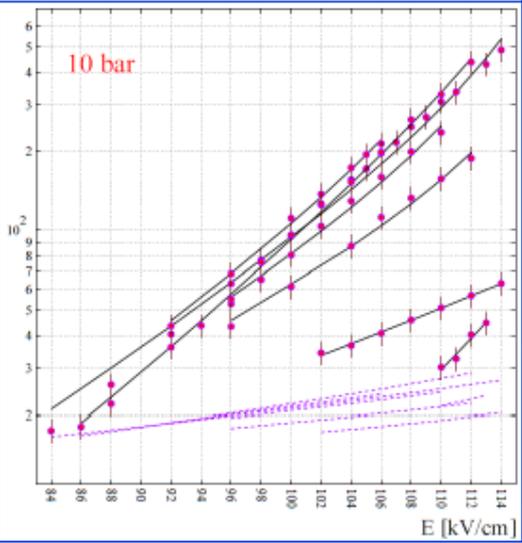
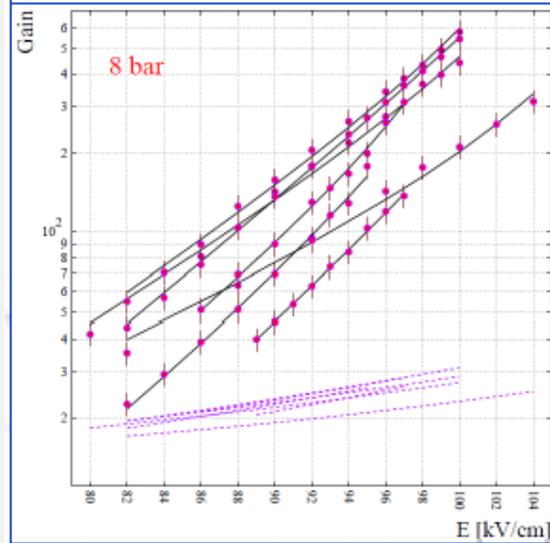
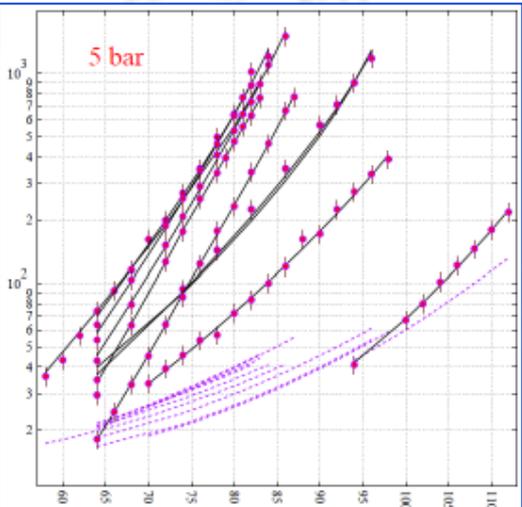
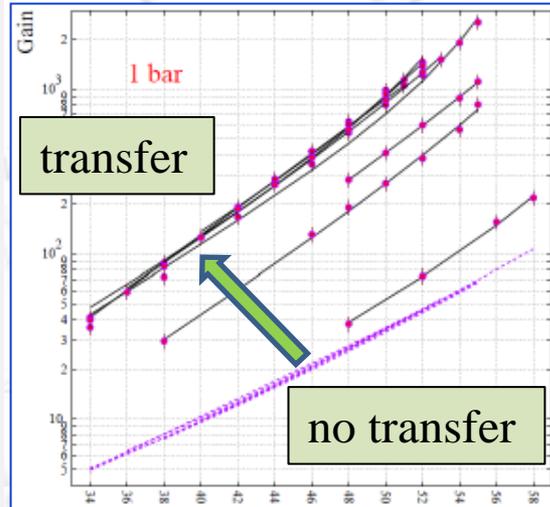
Part 3.1: the amplification region

$$m(E) = \exp(\alpha_{r=0}(E) \left[1 + r \frac{N_{ex,0}}{N_{I,0}} (E) \right] gap)$$

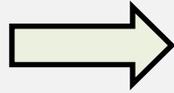


transfer coefficient -r:
 (effective probability that a excited state of the main gas ionizes TMA, field-independent in first order)

lines: simulation
 points: data (at different %TMA)

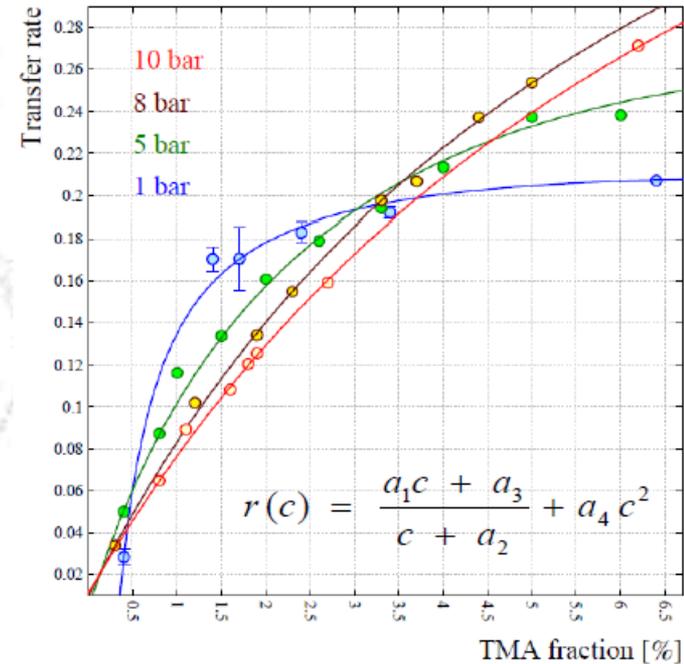


'classic' Magboltz



Status as of April at RD51 mini-week

- ❖ All the fits using the proposed model
- ❖ It describes transfer curves sufficiently well
- ❖ BUT; a_2 and a_3 negative at higher pressures than 5 bar



- ❖ 3 – body interactions only happen for large TMA fractions at low pressures ???
- ❖ Should be checked, with gain measurements at large TMA concentrations at high pressures
- ❖ What is the physical meaning of a_4 parameter, which mechanism(s) leads to drop on transfer curve; in progress.

Problems and next steps:

- **Microscopic modeling needed!** (will mainly mimic a smaller gap, and increase the necessary $-r$).
- **Problem with TMA calibration.** Repeated. Concentration is approximately doubled, as compared to published data (erratum to be submitted soon). Will also likely increase $-r$, due to the stronger e- cooling.
- Interpretation of atomic-molecular parameters $a_{1...n}$ cumbersome in the presence of excimers.... (**work ongoing**)

details in

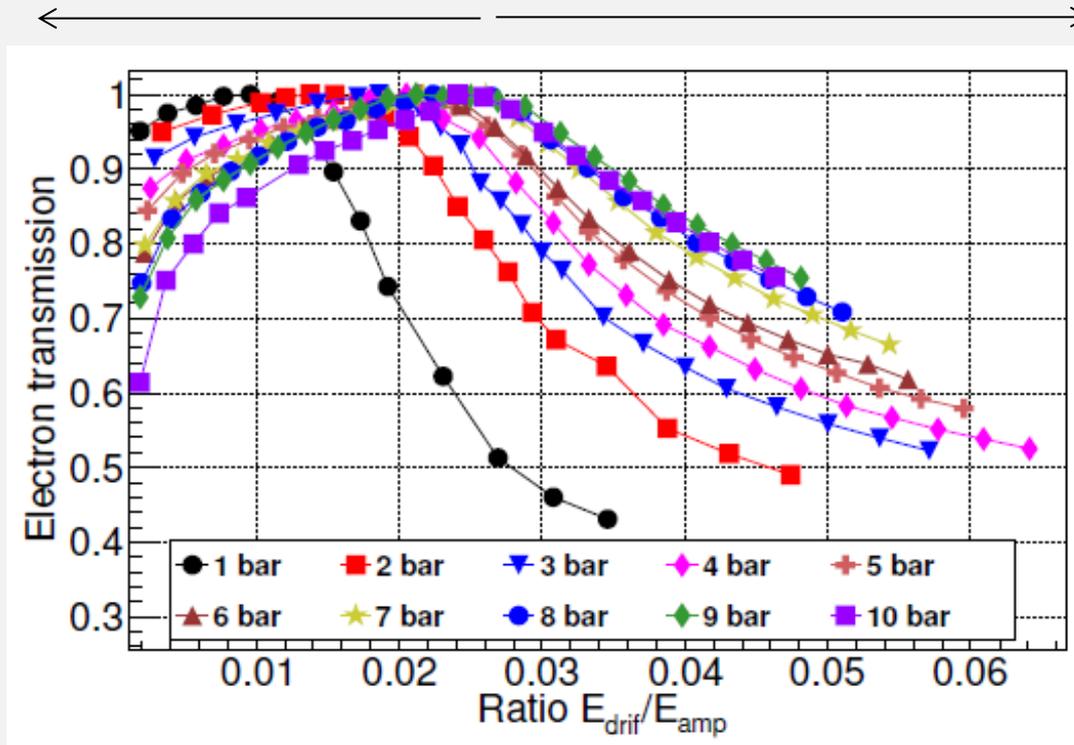
<http://indico.cern.ch/getFile.py/access?contribId=37&sessionId=5&resId=1&materialId=slides&confId=245535>

Part 3.2: the transmission region

The experimental situation

Too low drift field:
losses due to recombination or attachment.

Too high drift field:
loss of transparency. Electrons 'crash'
against the mesh.



(S. Cebrian et al. JINST 8 (2013) P01012)

Is the observed effect compatible with recombination?

- 1) Fit the left-side to the standard ‘Jaffe+Onsager’ model as proposed by Ramsey/Agrawal

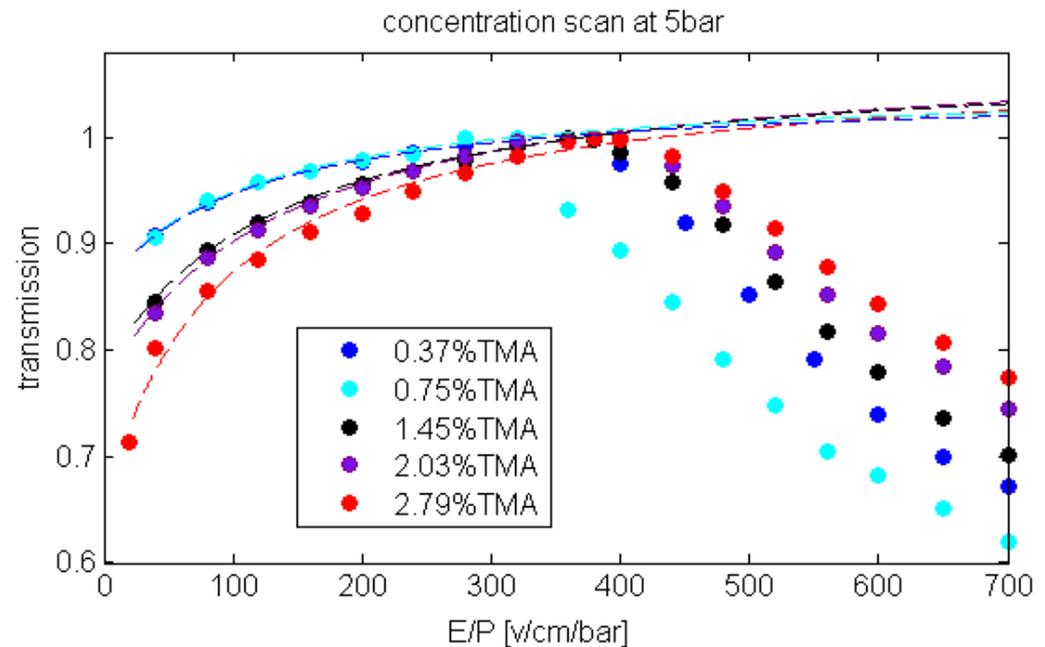
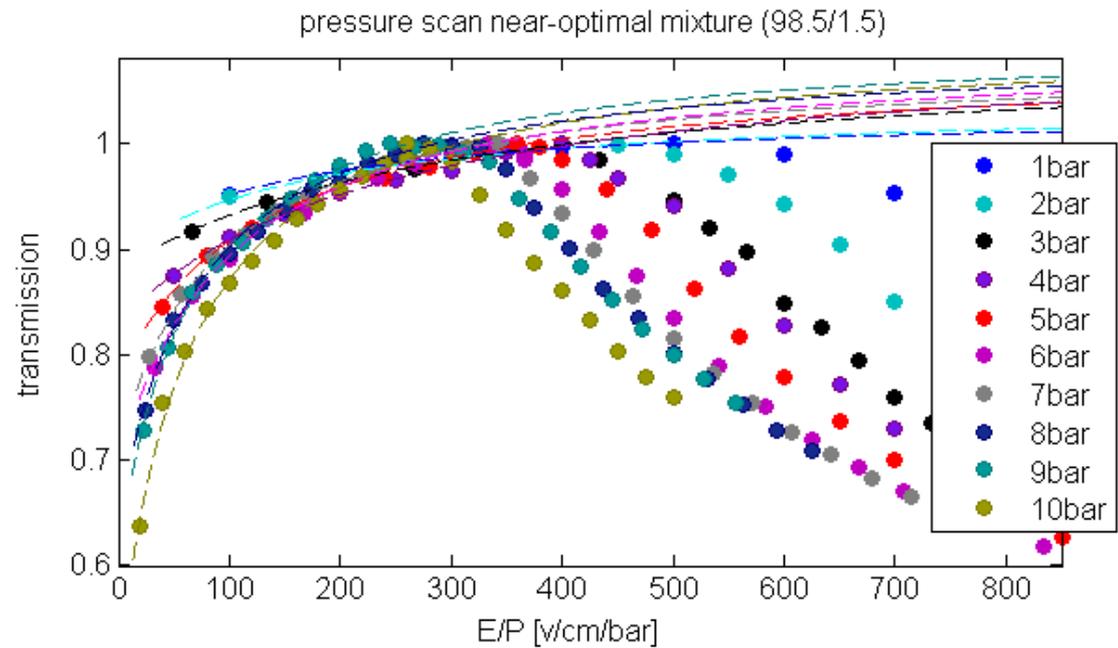
$$Q = Q_0 + \frac{Q_\infty - Q_0}{1 + K/E}$$

- 2) Attachment can be excluded up to 6bar and down to 50V/cm/bar (measured: $\tau_e > 3\text{ms}$ after recirculation! (measurements done on 1cm drift)).

- 3) The observed effect is systematically increasing with increased quencher and increased pressure (intuitive).

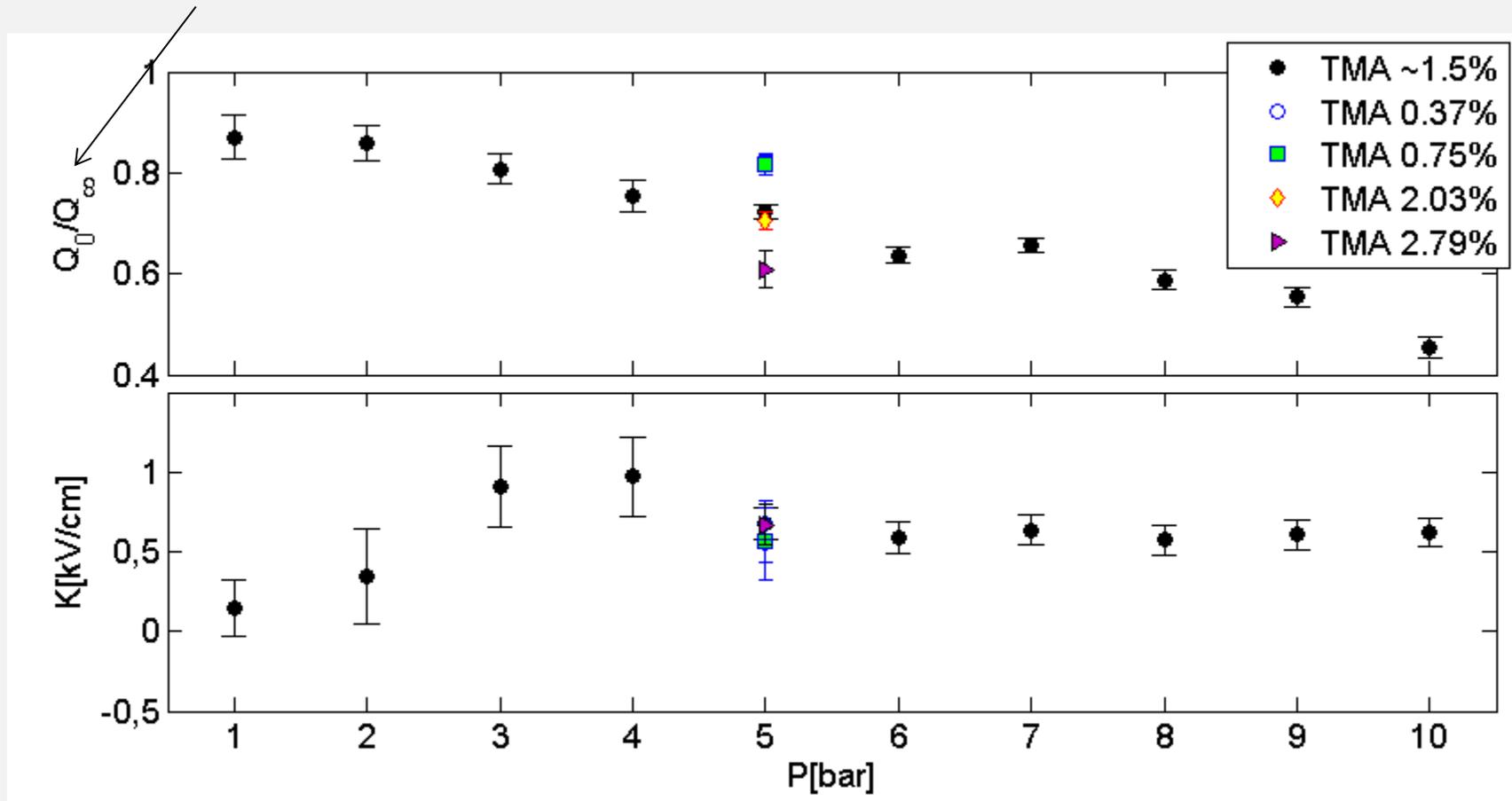
- 4) The behavior to the right of the maximum is a complex interplay between field geometry and diffusion and depends strongly on the behavior of the Micromegas.

- 5) In the absence of recombination or attachment the behavior to the left of the maximum is expected not to depend on the micromegas, equaling one (preliminary studies based on microscopic simulations are given later).



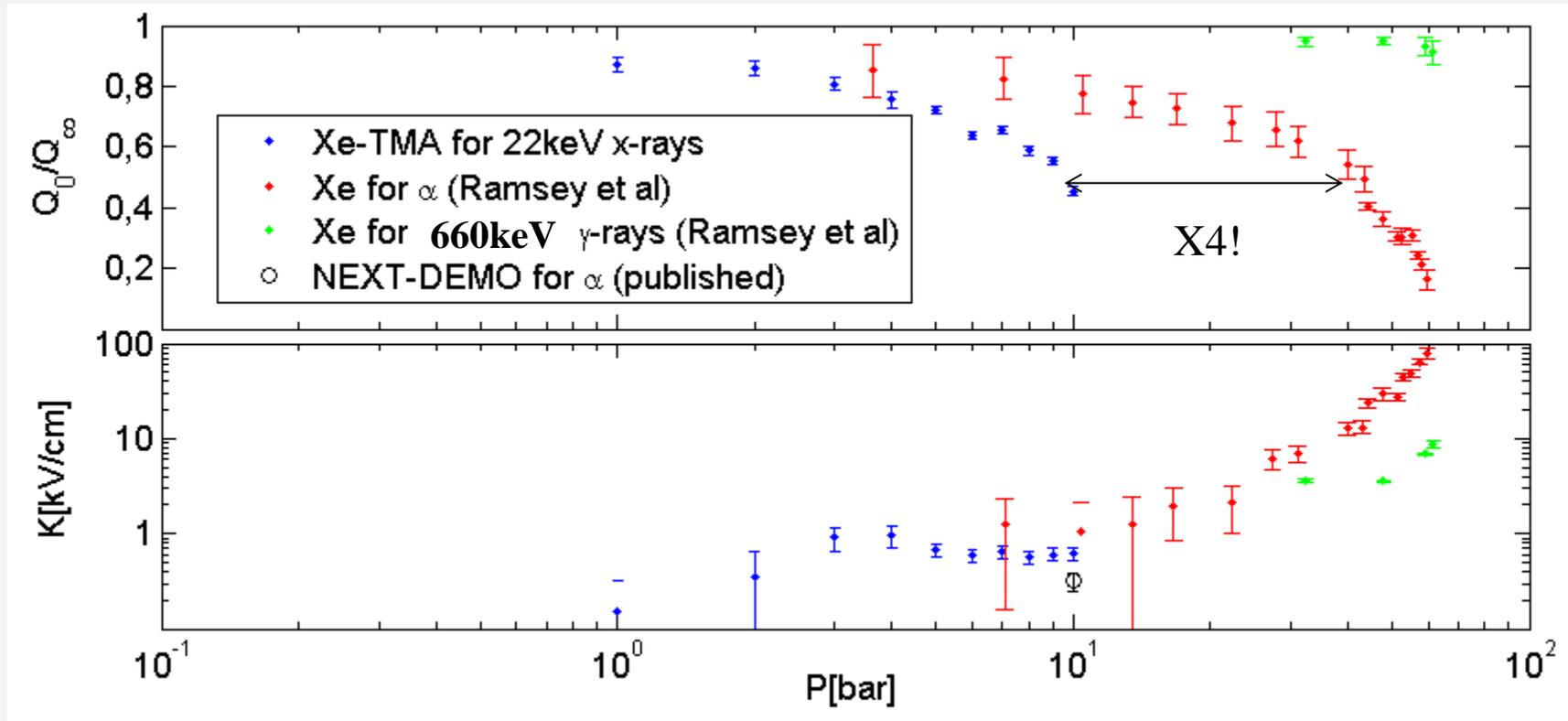
A compilation of the main figures in the Onsager/Jaffe model

fraction of charge that escapes recombination at zero field



Quantitative explanation still missing, but it behaves as intuitively expected. The higher the quencher and the pressure the faster the thermalization, the lower the charge that escapes initial recombination. However...

The observed effect is much more serious than for alphas in pure Xe!



Is this purely an effect of the faster thermalization of the initial electron in the presence of quencher or is Penning also somehow involved??

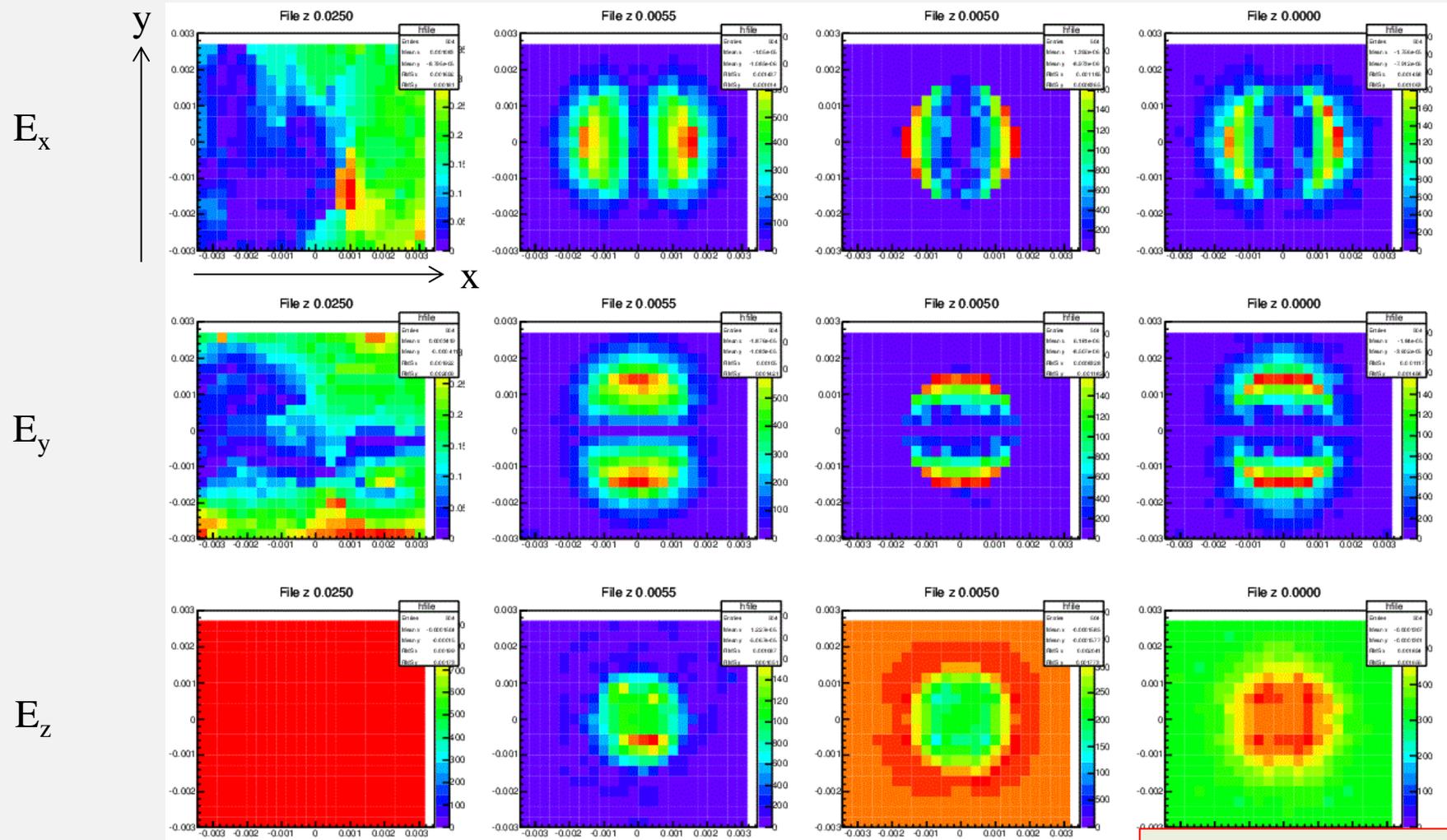
We tried to understand if this loss of transparency at low fields can be caused by the transition to the micromegas amplifying region (Garfield++ and Comsol simulations).

z=0.25mm
(drift)

z=0.55mm
(above mesh)

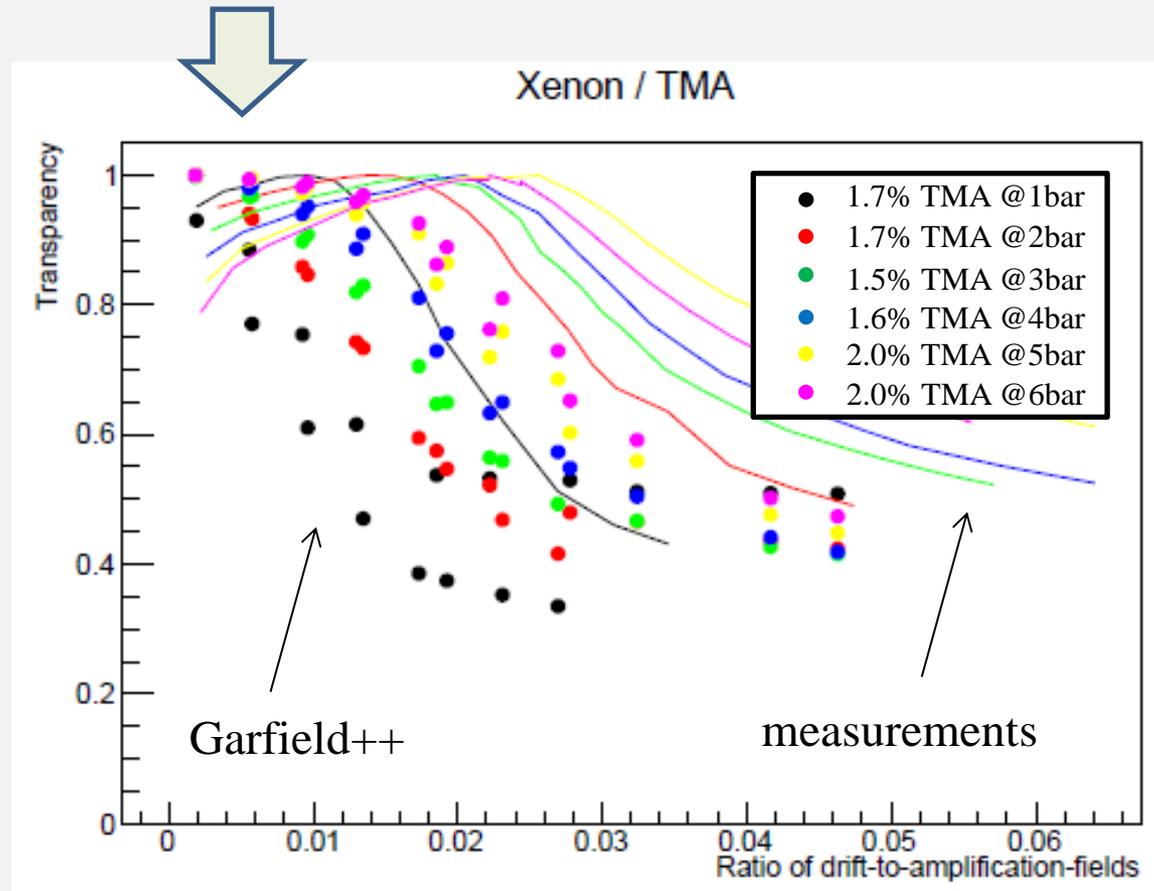
z=0.50mm
(mesh)

z=0mm
(anode)



very preliminary!

No drop at low fields in simulation.
Trend for high drift field correctly captured!



arbitrary normalization!. Curves around the operating plateau differ by to 20% (under investigation)

very preliminary!

Part 3.3: energy resolution

First order formula used in the CDR (valid for large charge collection efficiency)

$$\frac{\sigma_E}{E} \cong 2.35 \sqrt{F^* + f + (1 - T) + (1 - Q / Q_\infty)} \frac{1}{T \times Q / Q_\infty} \frac{1}{\sqrt{n_o}}$$

<0.15

0.3-1 (simulation)
(single-electron variance)

(0-0.2 ->simulation)

(0-0.2->from measurements)

$$F^* \cong F_{xe} (1 - r) + rF_1$$

from simulation



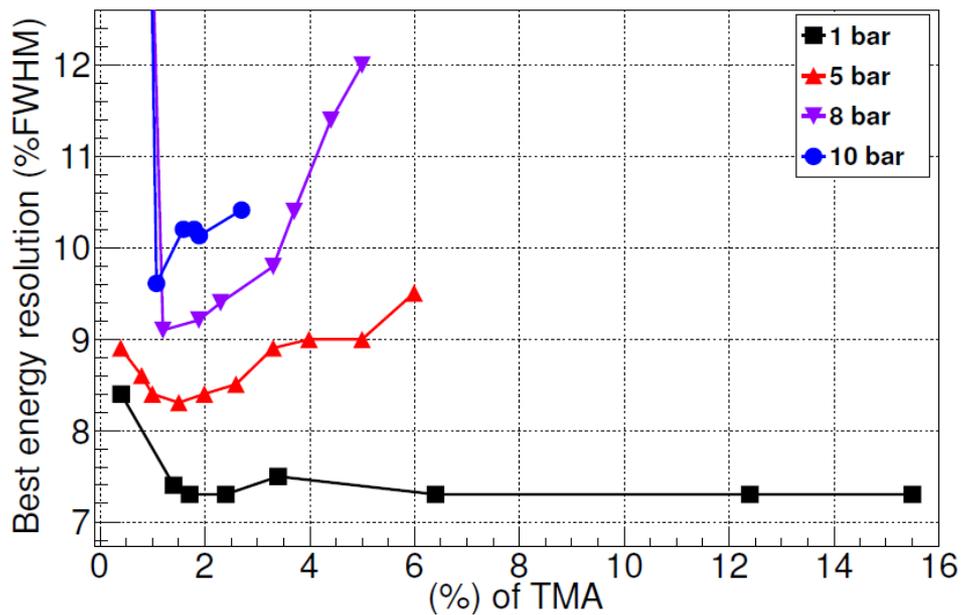
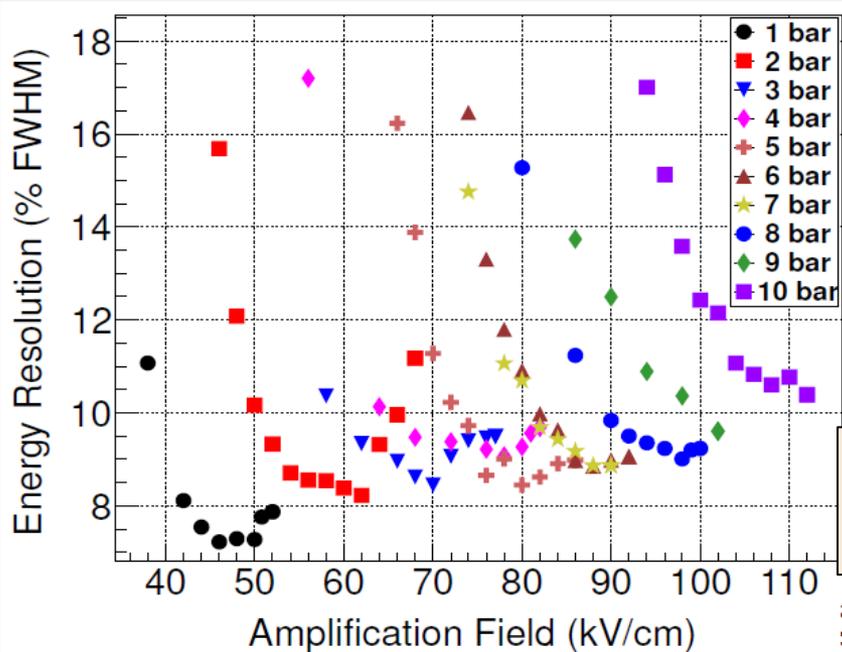
G. D. Alkhozov, A. P. Komar, A. A. Vorobeb, *Ionization fluctuations and resolution of ionization chambers and semiconductor detectors*, NIM A, 1966.
(Eq. 11)

-> F_1 is a complex (**defined-positive**) function.

-> σ is the probability that an excited state causes an ionization by photo-ionization or Penning. ('probability of de-excitation followed by additional ionization', in Alkhozov words—*this old reference is still used by Aprile and Knoll*). Here it has been replaced by r in first order.

Extremely difficult to isolate all contributions..., but we do not give up!

the goal (stay tuned)



Conclusions and outlook

- **System at 1bar well understood and operation stable.**
- *Detailed assessment of unconnected pixels performed and situation understood.*
- *Basic analysis tools developed.*
- *Calibration preliminary implemented. System response very democratic at the moment.*
- *Previously 12%FWHM@30keV energy resolution on 1000evts and small area extended to the whole readout plane for over 100keVts.*
- *Energy resolution asymptotically approaching the NEXT-0 (small TPC) levels (6%), showing regularly 9.5% and hints of 8% for very small regions (~1000evts).*
- **Looking forward to the 3bar-campaing!** (a necessary step before going to 10bar).
- *Analysis of Xe-TMA parameters (diffusion and drift velocity):*
 - **A calibration problem affecting the TMA determination was identified and solved.**
 - **Measurements of the longitudinal coefficient and drift velocity of Xe-TMA mixtures (93/7, 97/3) in strong disagreement with Magboltz 9.0.1.**
 - **Modeling of the Penning effect and microscopic modeling of Micromegas started.**
 - **Simulation results preliminary indicate that the presence of excimers is necessary to describe the transfer probability, as expected.**
 - **Strong hints of loss of transparency (from simulation) and recombination, that may explain the deterioration with pressure and %TMA.**
 - **A common picture emerging... but some work ahead .**

Appendix

Description of the electron cloud in a (standard) hydrodynamic model

avalanche equation

$$-\frac{\partial n}{\partial t} + \alpha v_d n + D \left(\frac{\partial^2}{\partial x^2} n + \frac{\partial^2}{\partial y^2} n \right) + D_L \frac{\partial^2}{\partial z^2} n - W \frac{\partial}{\partial z} n = 0$$

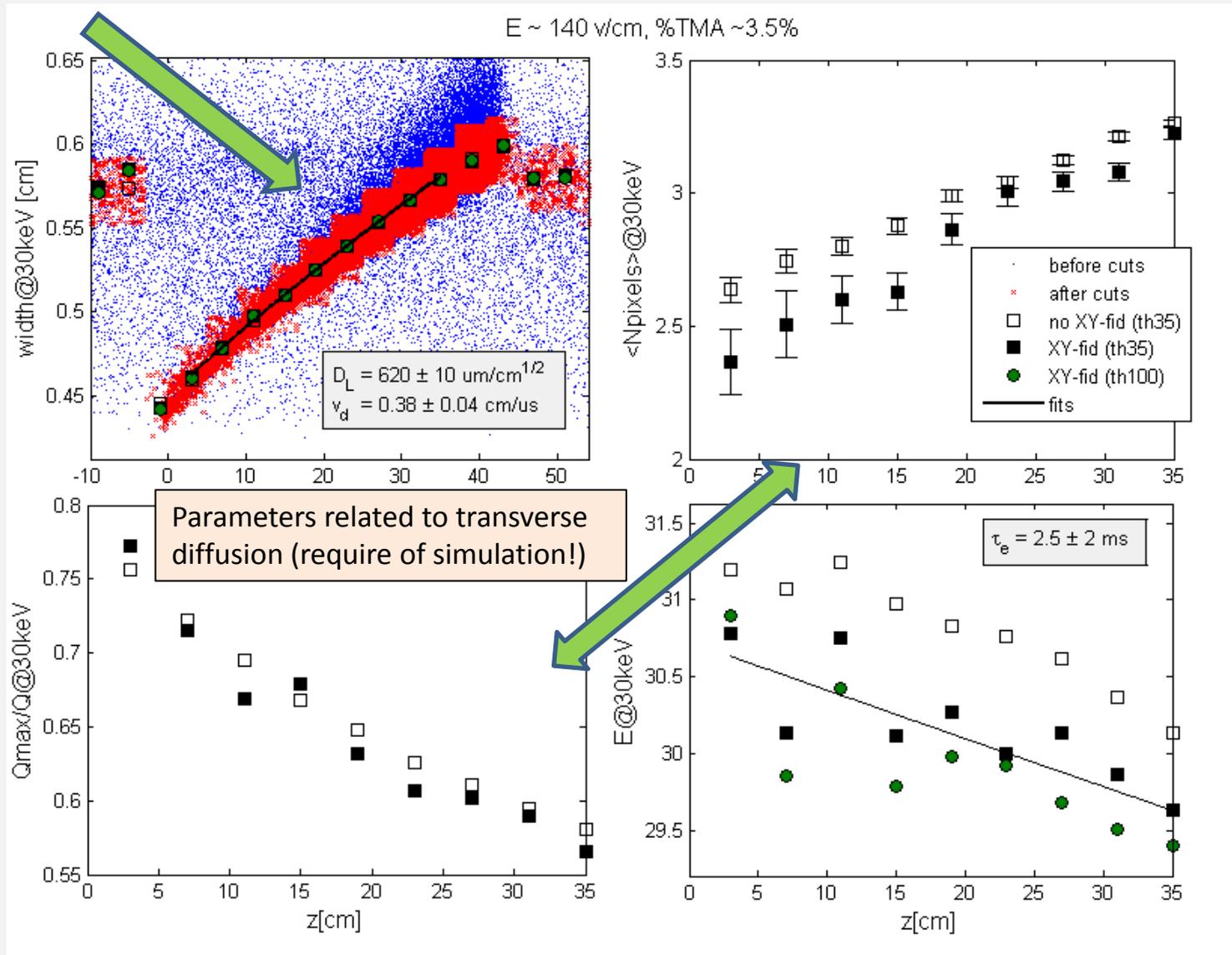
solution for a point-like release of n_0 electrons

$$n(r, z, t) = \frac{n_0 \exp(-r^2 / 4Dt)}{v_d t (4\pi Dt) (4\pi D_L t)^{1/2}} \times \exp\left(-\frac{r^2}{4D_T t}\right) \times \exp\left(-\frac{(z - v_d t)^2}{4D_L t}\right) \times \exp[\alpha v_d t]$$

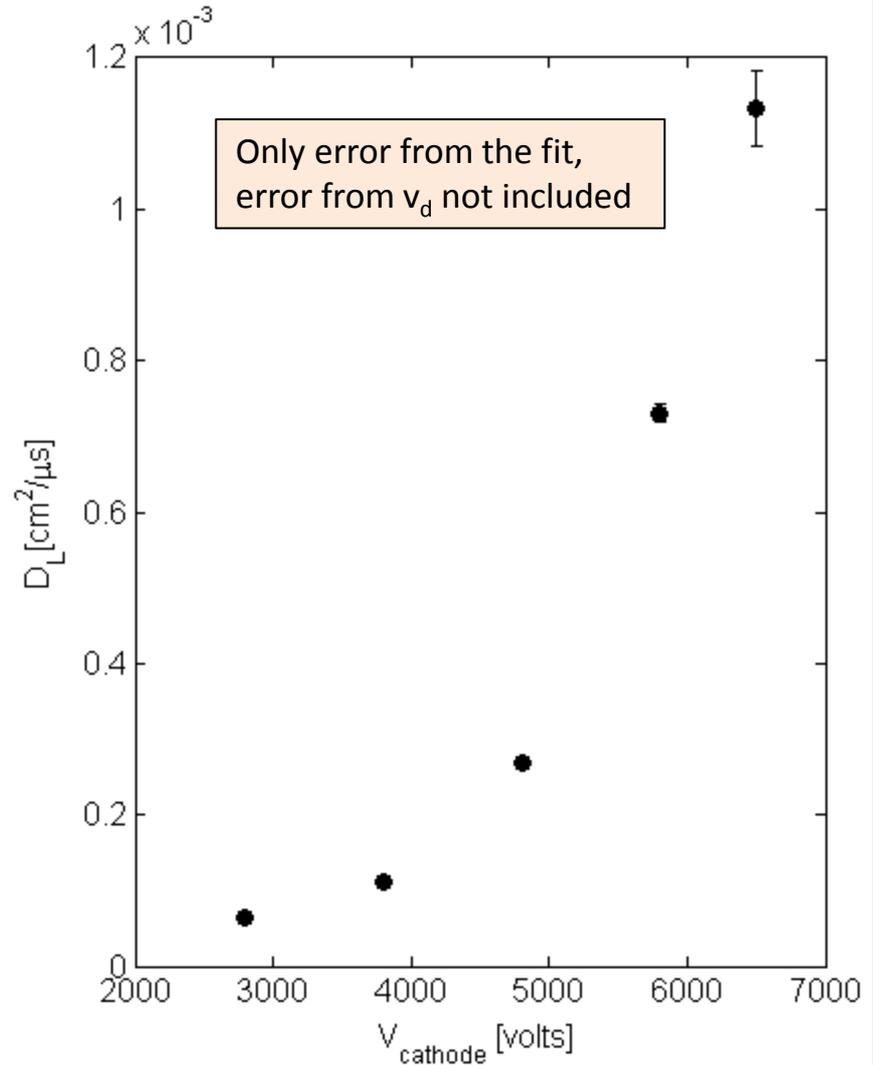
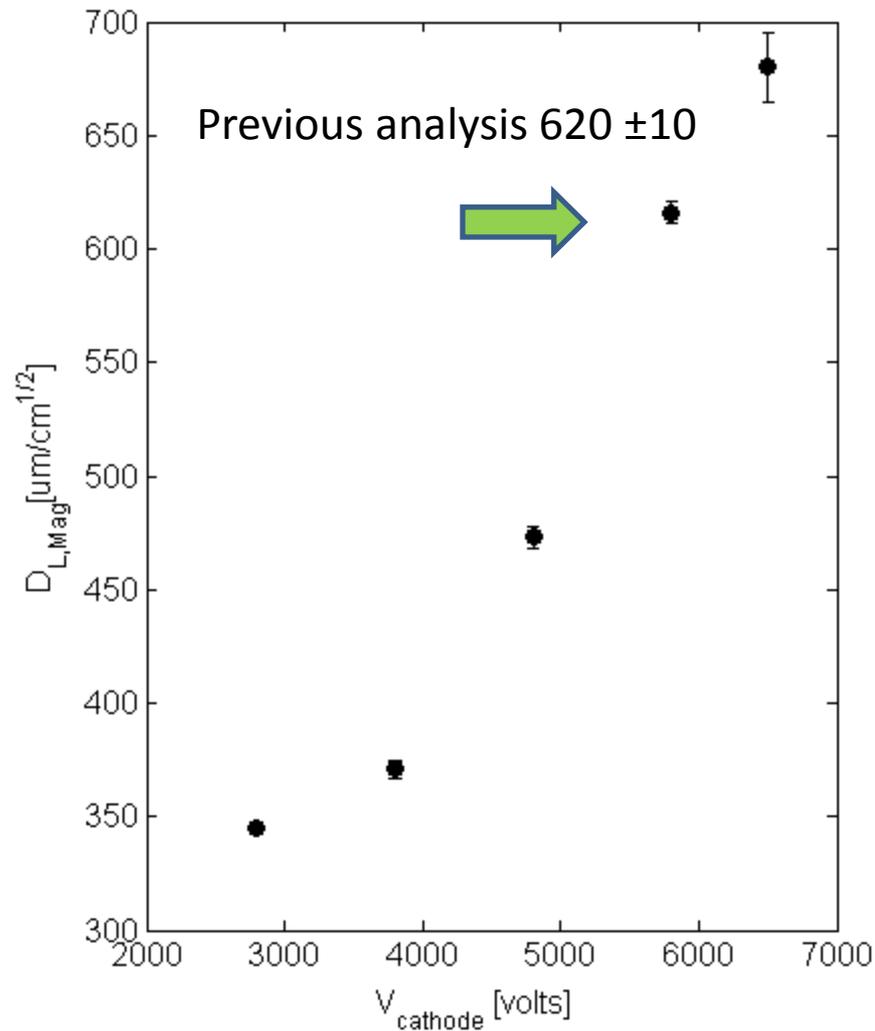
standard Magboltz re-definition

$$4D_{L,T} t = 2\sigma_z^2 = 2\left(D_{L,T(Mag)} \sqrt{z}\right)^2$$
$$D_{L,T(Mag)} = \left(\frac{2D_{L,T}}{v_d}\right)^{0.5}$$

parameters of drift region (old analysis (very high statistics))

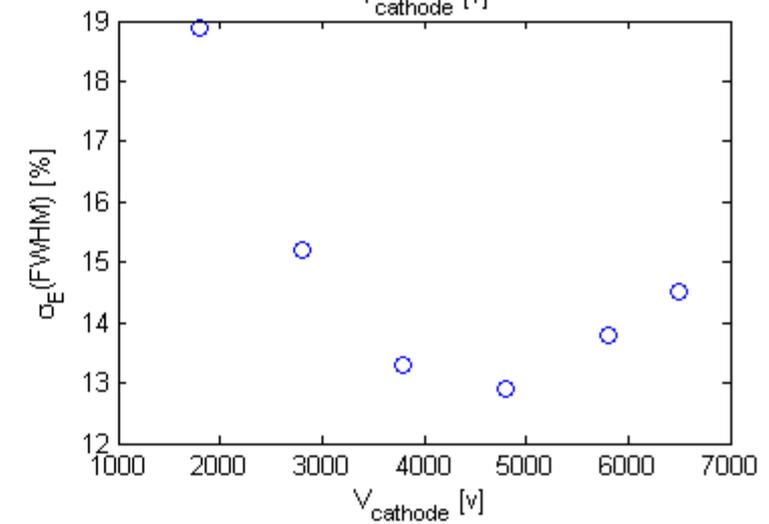
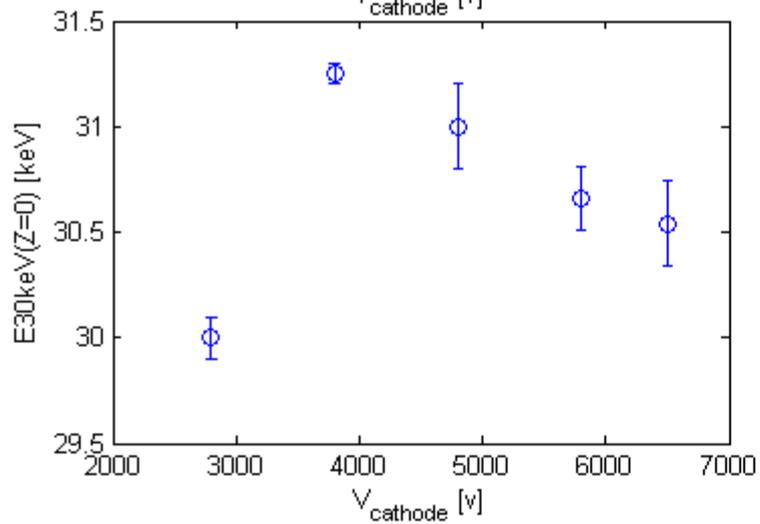
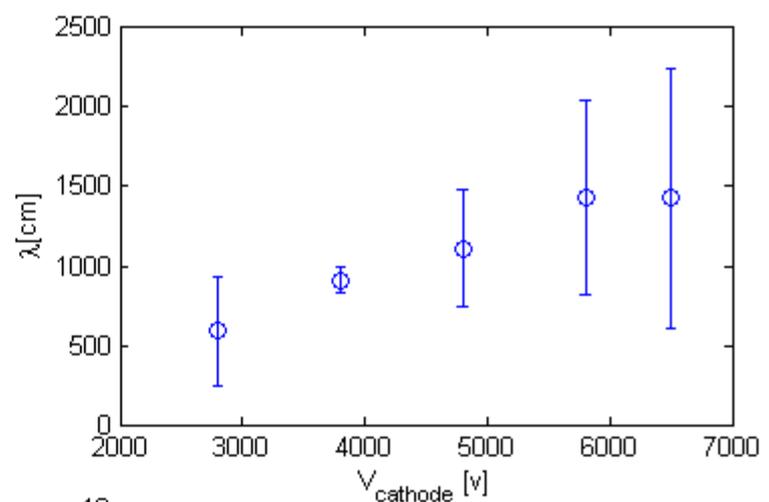
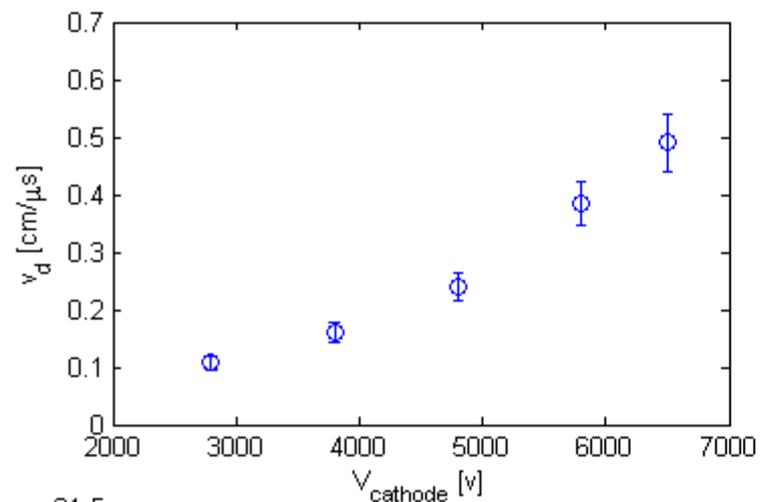


Results for the diffusion coefficient

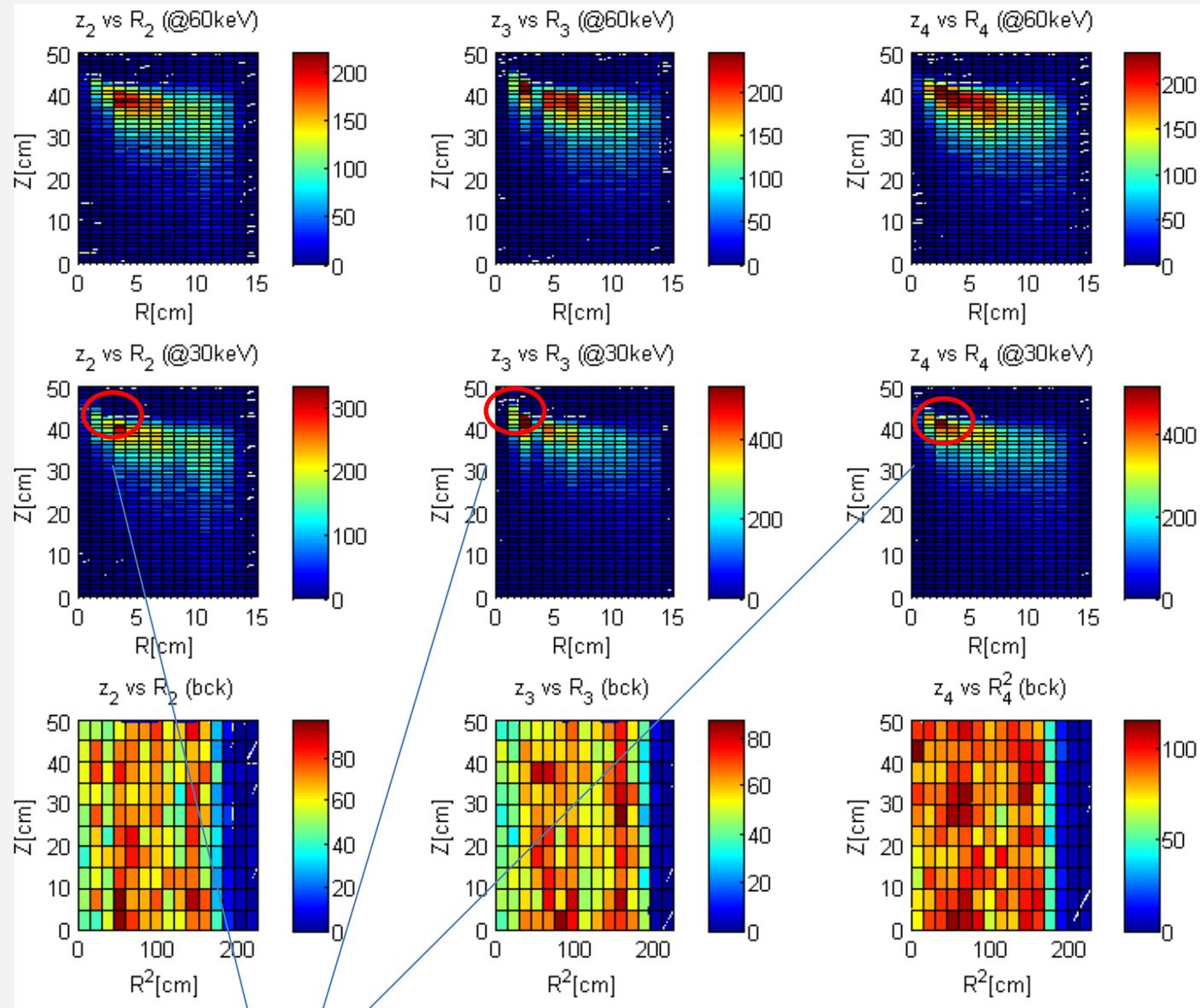


This experimental parameter depends very weakly on the chosen XY-region and threshold used for the analysis, very robust!!

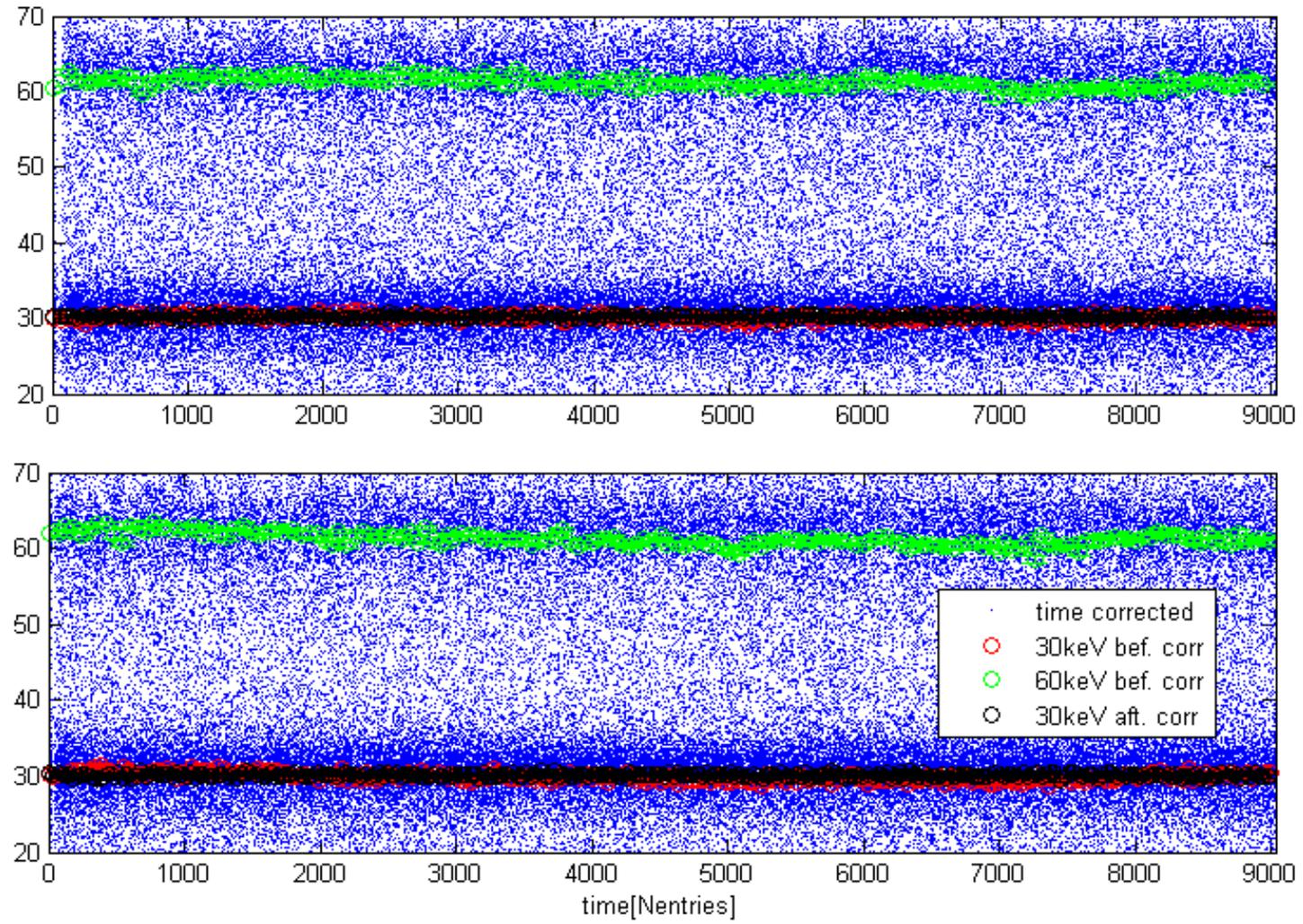
Other relevant parameters as a function of voltage



Small effects to correct for

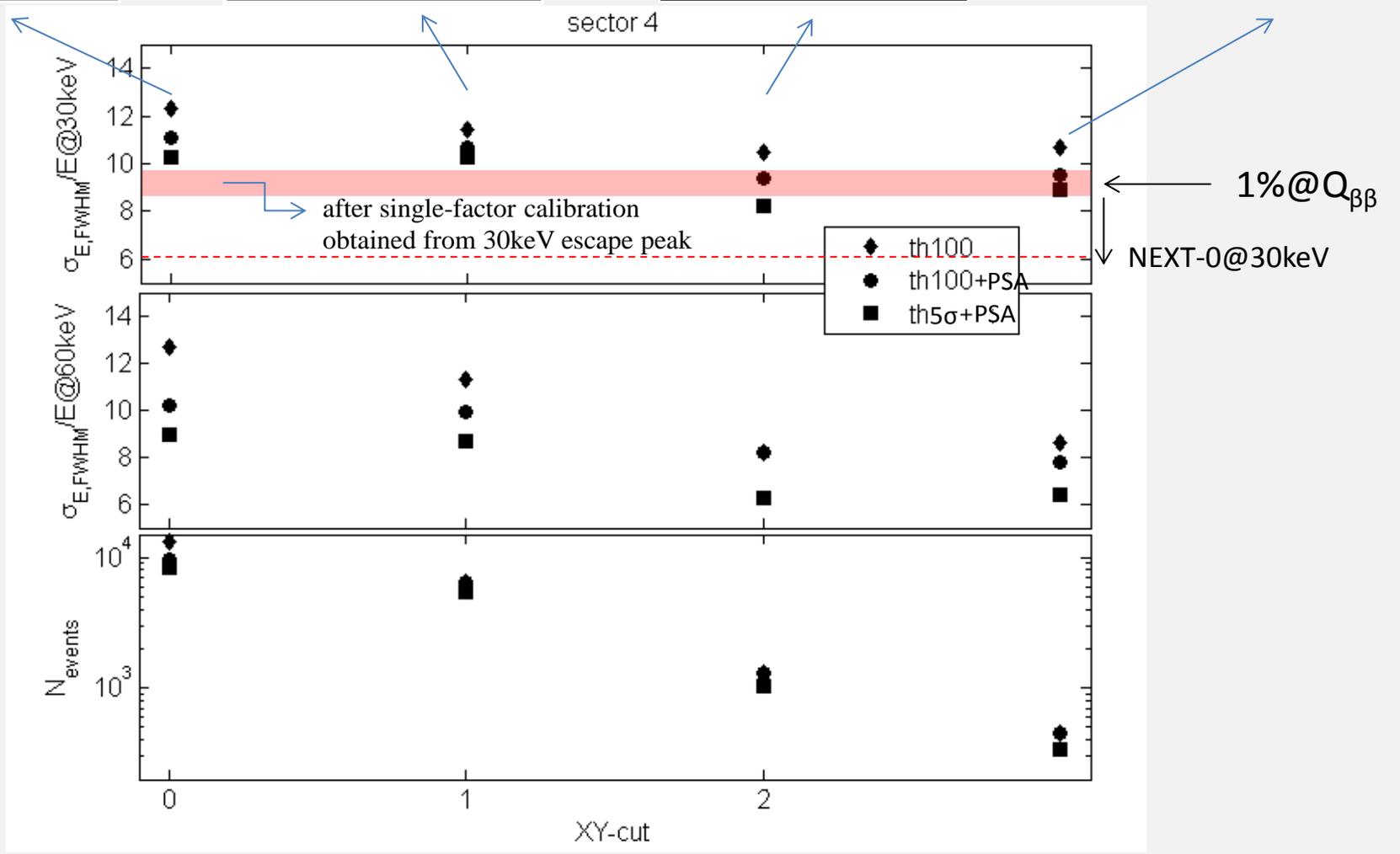
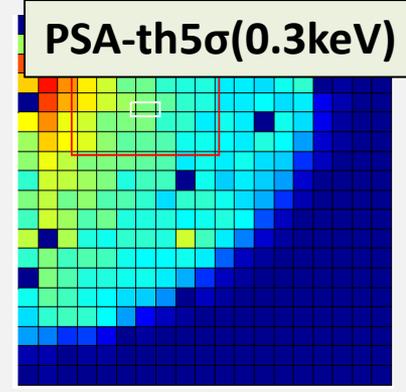
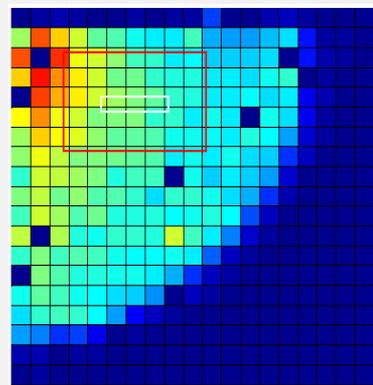
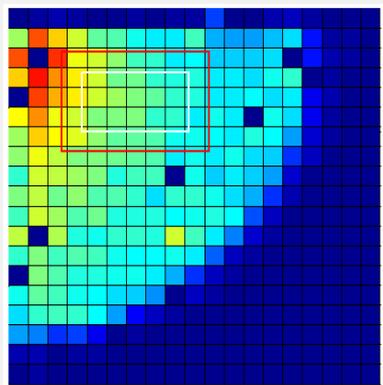
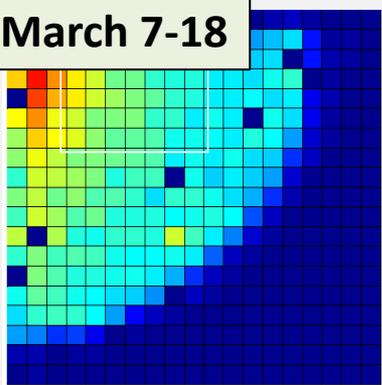


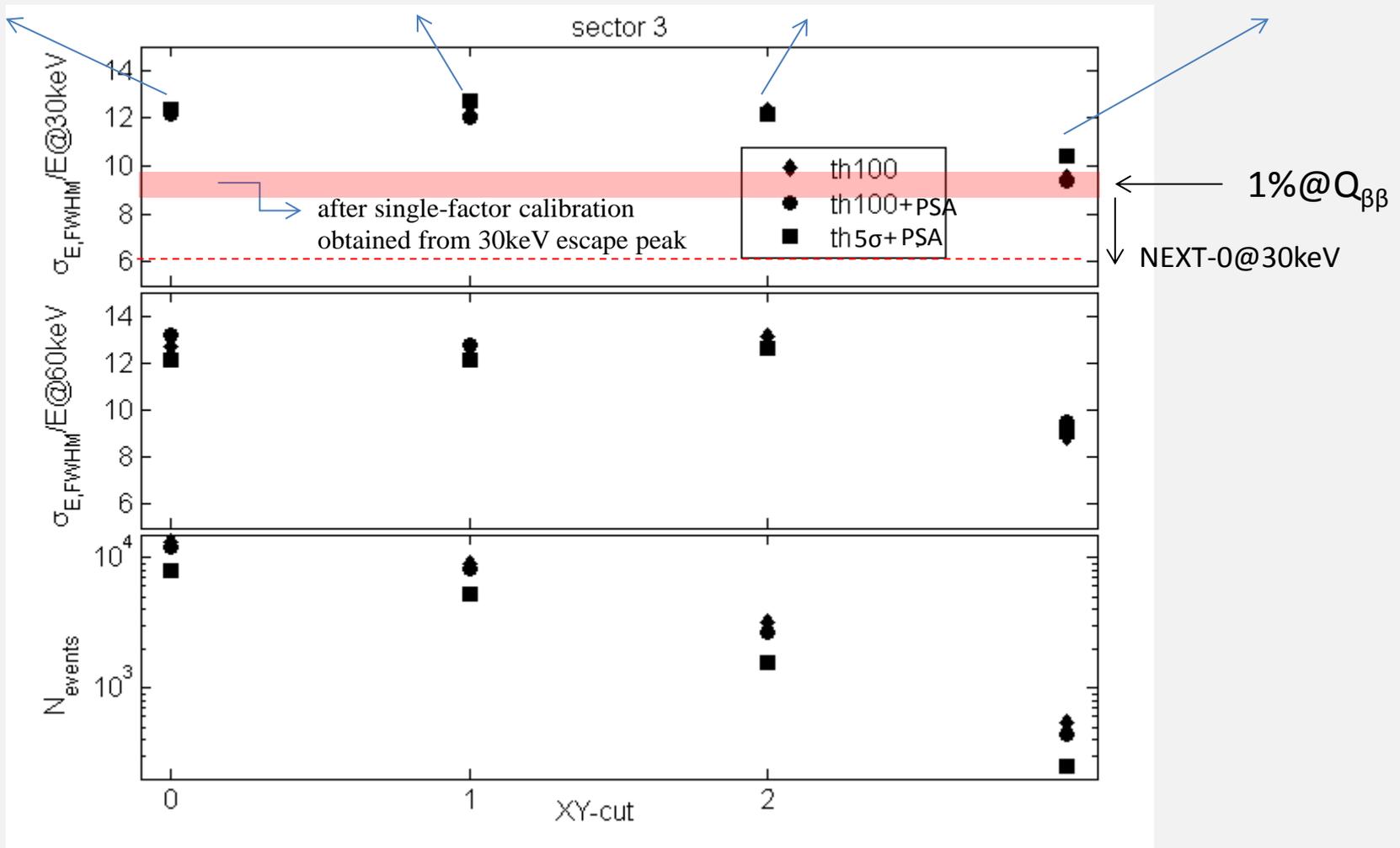
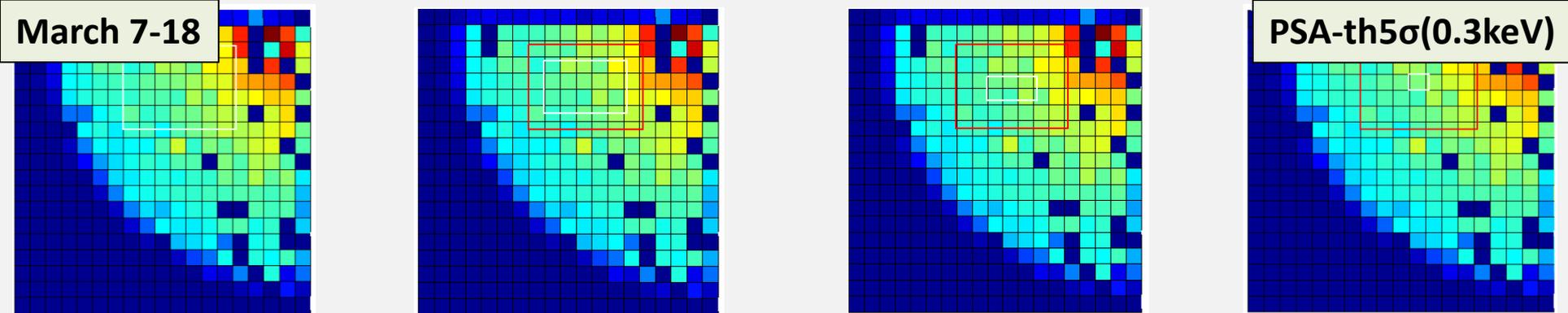
gain excursions (before and after correction)

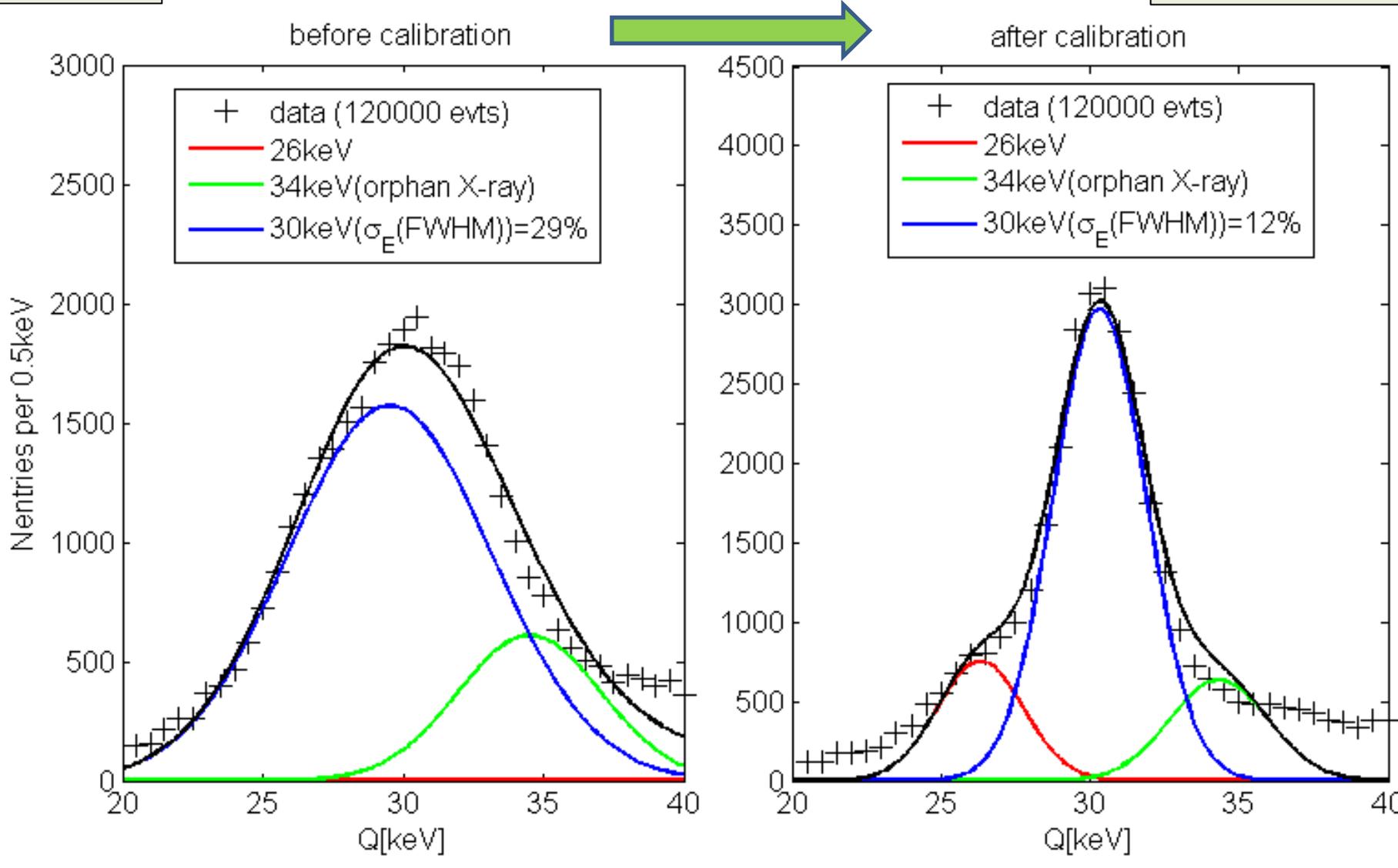


Excursions much smaller with the new power supplies!

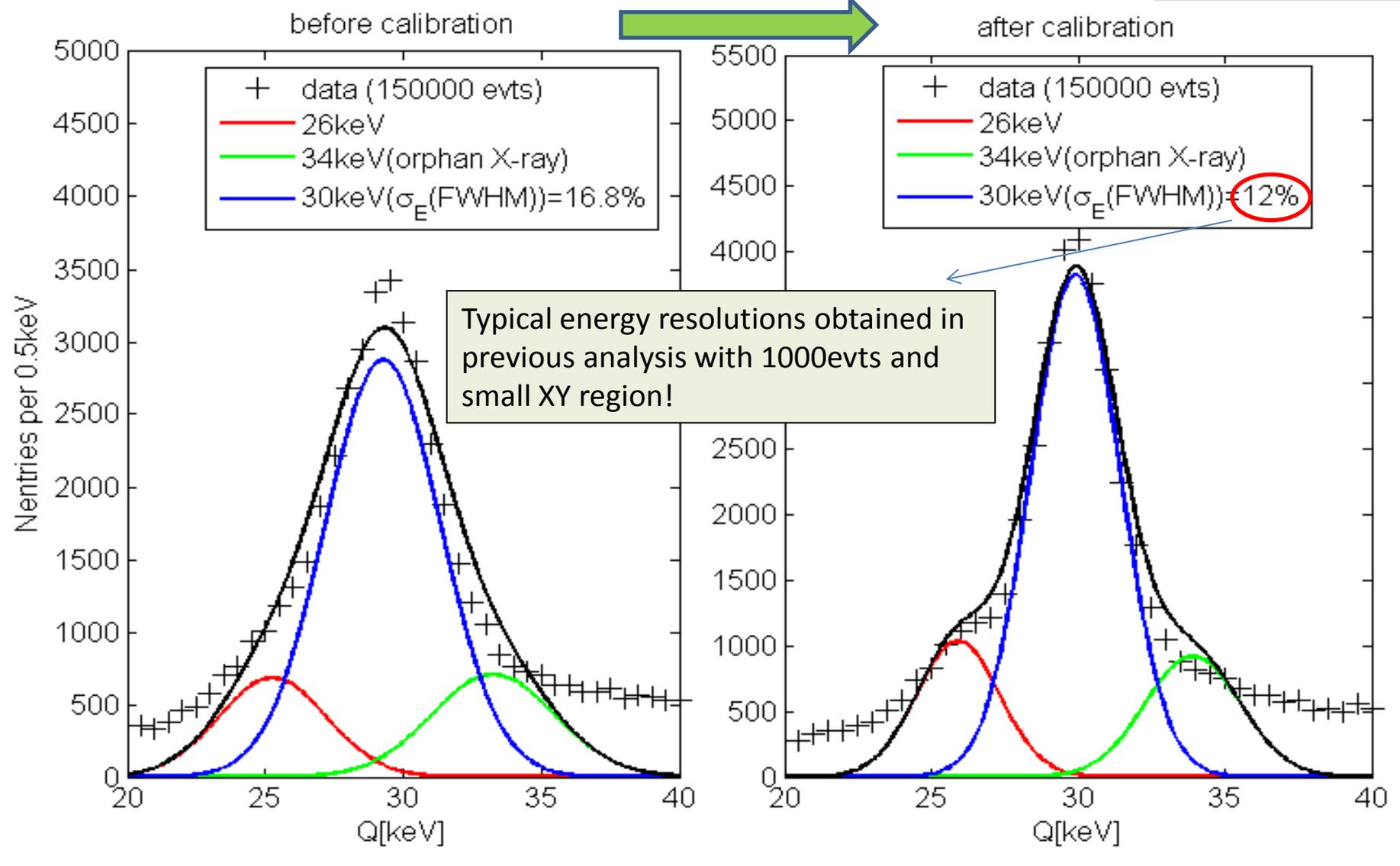
March 7-18



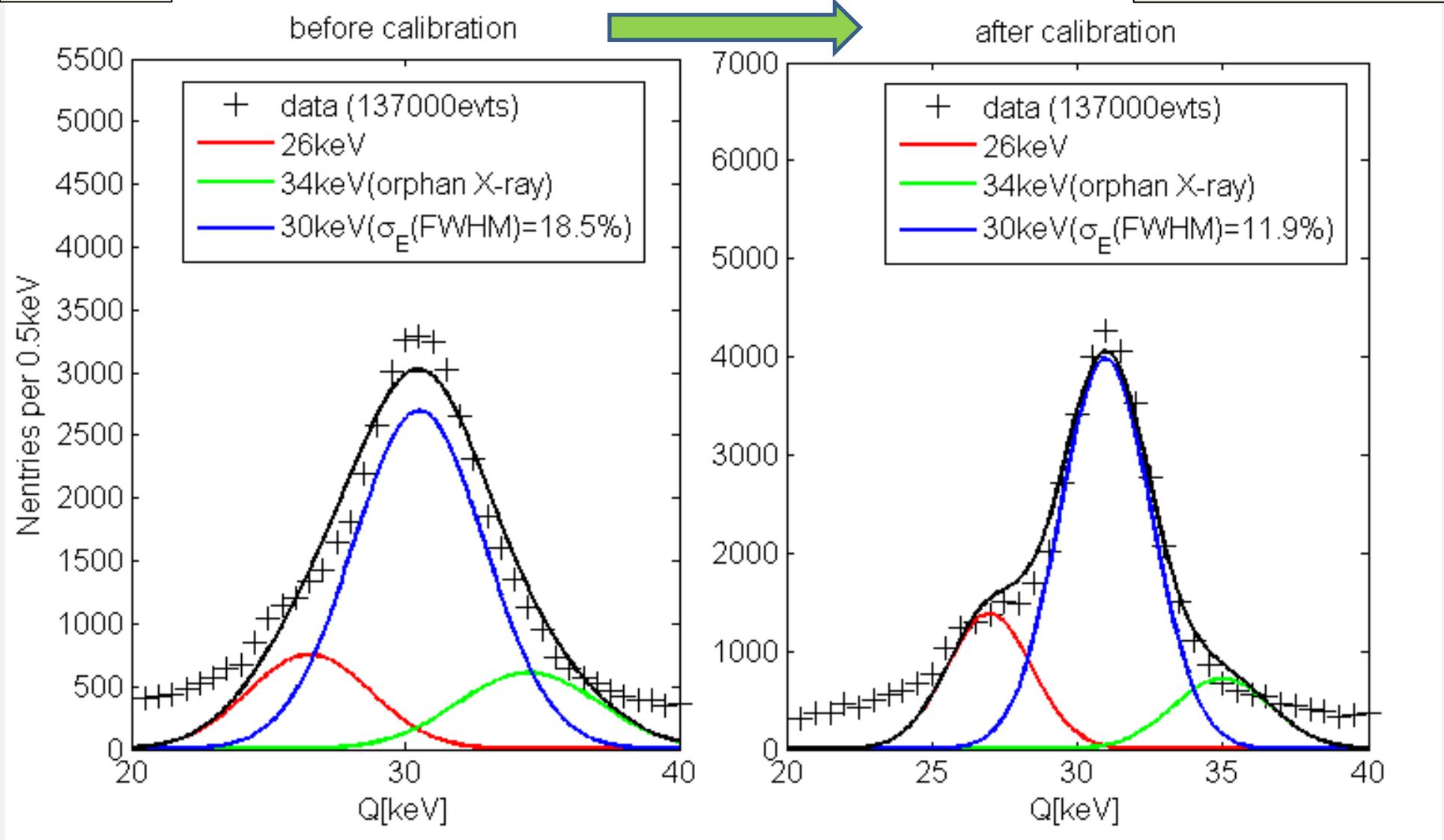




NOTE: cut in signal width should suppress backgrounds.
calibration works better for 30keV, since ~70% of the energy goes to one pixel



NOTE: cut in signal width should suppress backgrounds and improve resolution. calibration works better for 30keV, since ~70% of the energy goes to one pixel

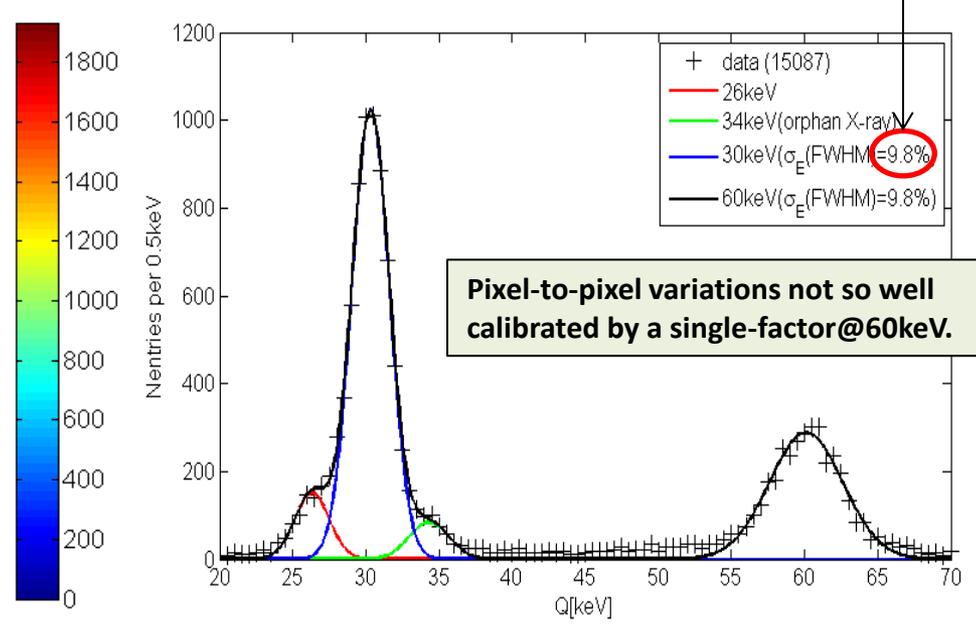
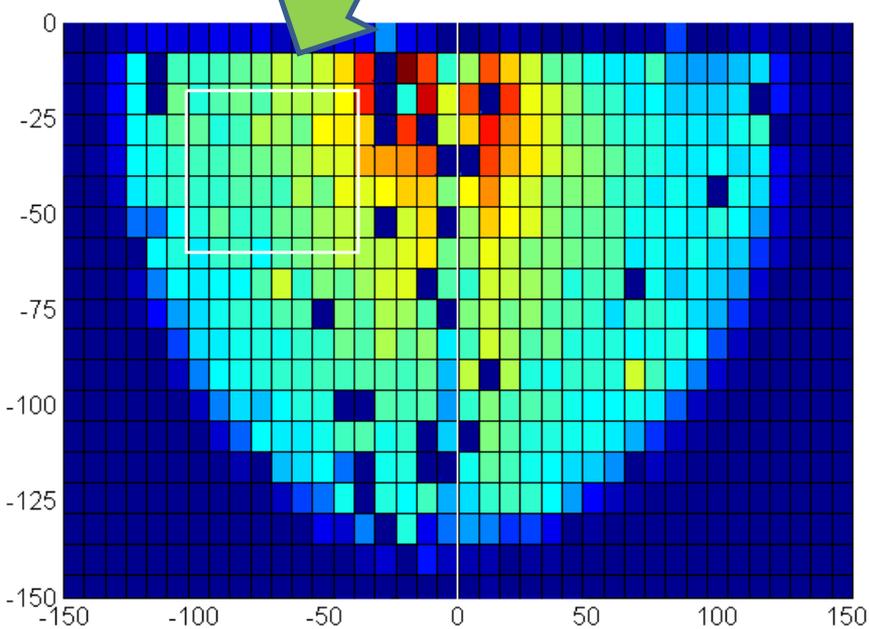
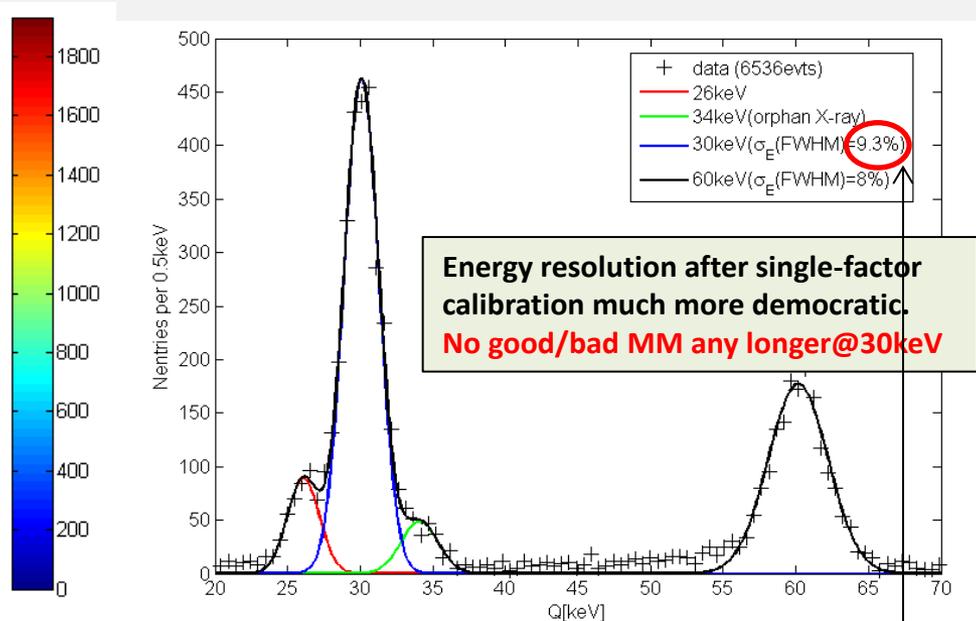
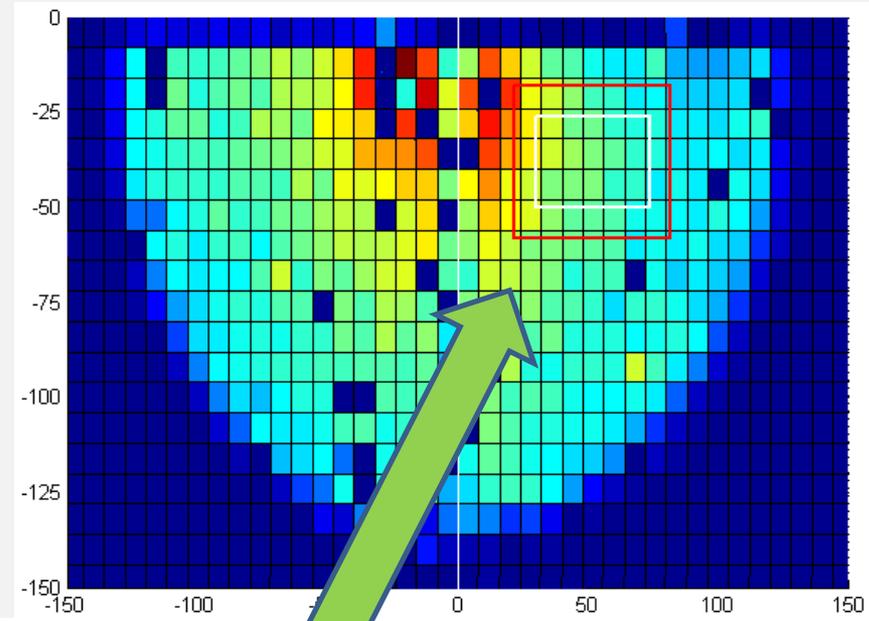


NOTE: cut in signal width should suppress backgrounds and improve resolution.
calibration works better for 30keV, since ~70% of the energy goes to one pixel

March 7-18

resolution's best (after preliminary single-factor calibration)

PSA-th5 σ (0.3keV)



Summary of NEXT-MM analysis@1bar

	PSA th1.2keV + phys(old soft) + Matlab	PSA th1.2keV + phys(old soft) + Matlab	PSA th1.2keV + phys(old soft) + Matlab	PSA th1.2keV + phys(old soft) + Matlab	???
Before calibration (30keV)	17%(S3) -30%(S2)	13-15%	11-13%	8-9%	NEXT0 6%
After calibration (30keV)	12% tails visible	10.3-10.5% small tails	9.3-9.9% ~no tails	8-9% ~no tails	With further analysis we can certainly approach 7%
Typical Number of events	120000- 150000evts	50000evts	5000-10000evts	500-1000evts	?
Typical size	1 sector	9cm x 8cm	5cm x 5cm	1cm x 1cm	5cm x 5cm
Typical problems	unconnected pixels, fringe fields, bad containment	unconnected pixels (some ~ 5% -typical)	1.03-1.1% @ $Q_{\beta\beta}$	~single-pixel limit. Little statistics PSA th 0.3keV analysis makes a difference	
Notes			Standard analysis (fast)		